

# Electron Beam Instrumentation for SwissFEL

Rasmus Ischebeck, for the SwissFEL Team



# Electron Beam Instrumentation for SwissFEL

- > Beam Position Monitors
- > Charge Monitors
- > Time-Resolved Measurements
  - > Arrival Time Monitor
  - > Compression Monitor
  - > Electro-Optical Monitor
  - > Transverse Deflecting Cavity
- > Optical Spectrum of Transition Radiation
- > Profile Monitors
  - > Wire Scanner
  - > Synchrotron Radiation Imager
  - > Screen Monitor

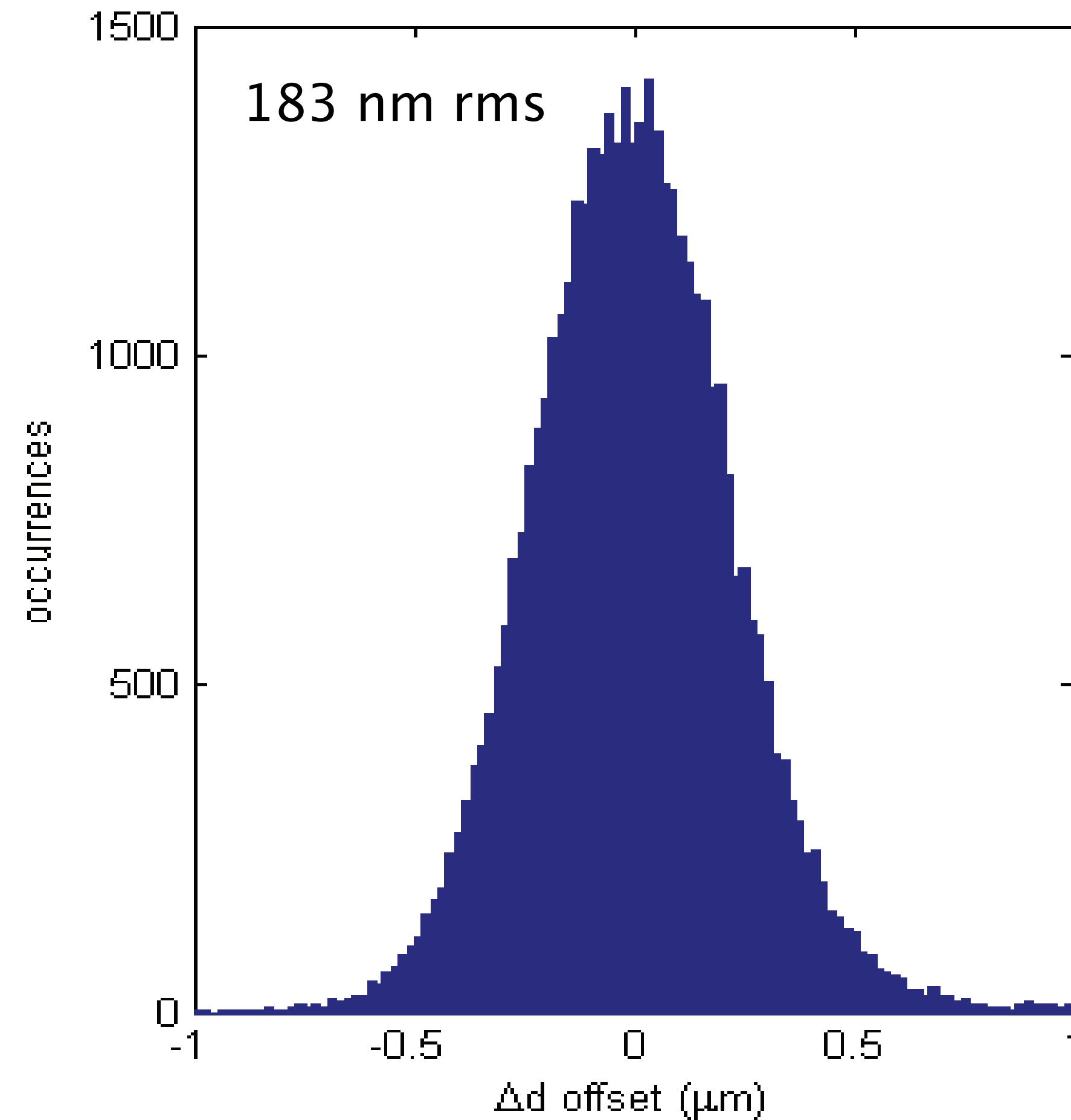
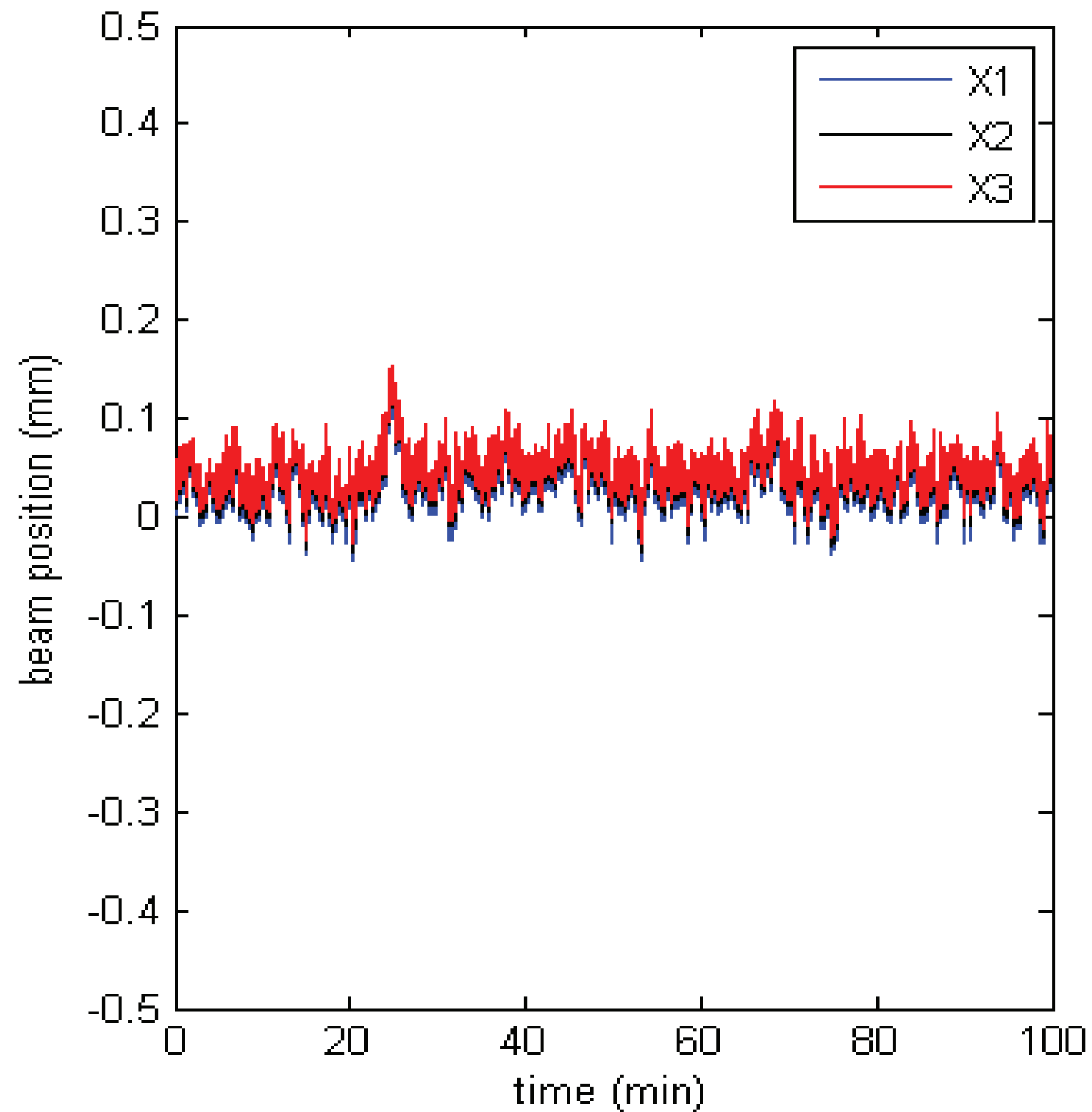


# Beam Position Monitors



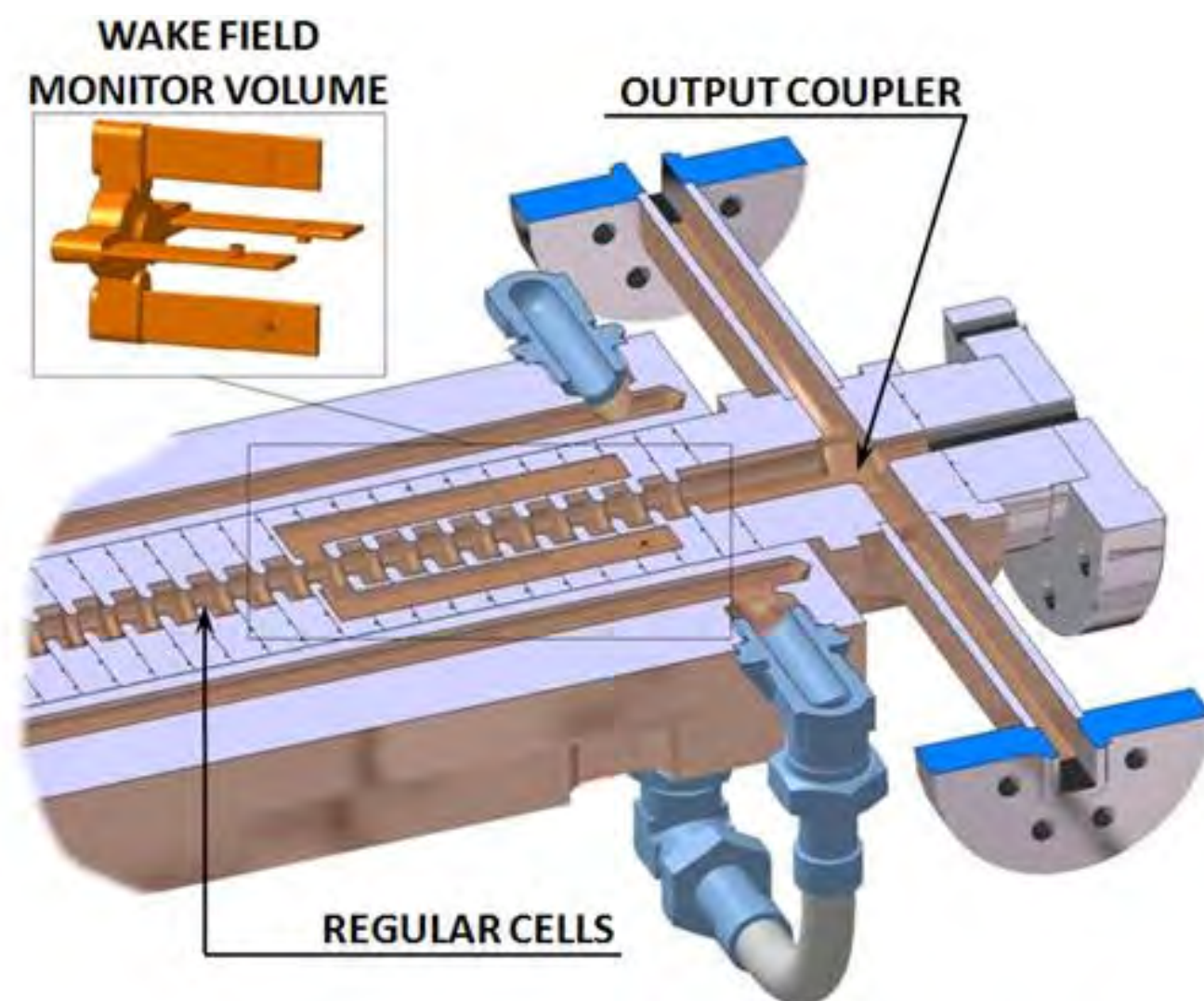
# Cavity Beam Position Monitors

- > SwissFEL will use only cavity beam position monitors
- > The same electronics as for the European XFEL will be used
- > Sub-micrometer resolution has been demonstrated

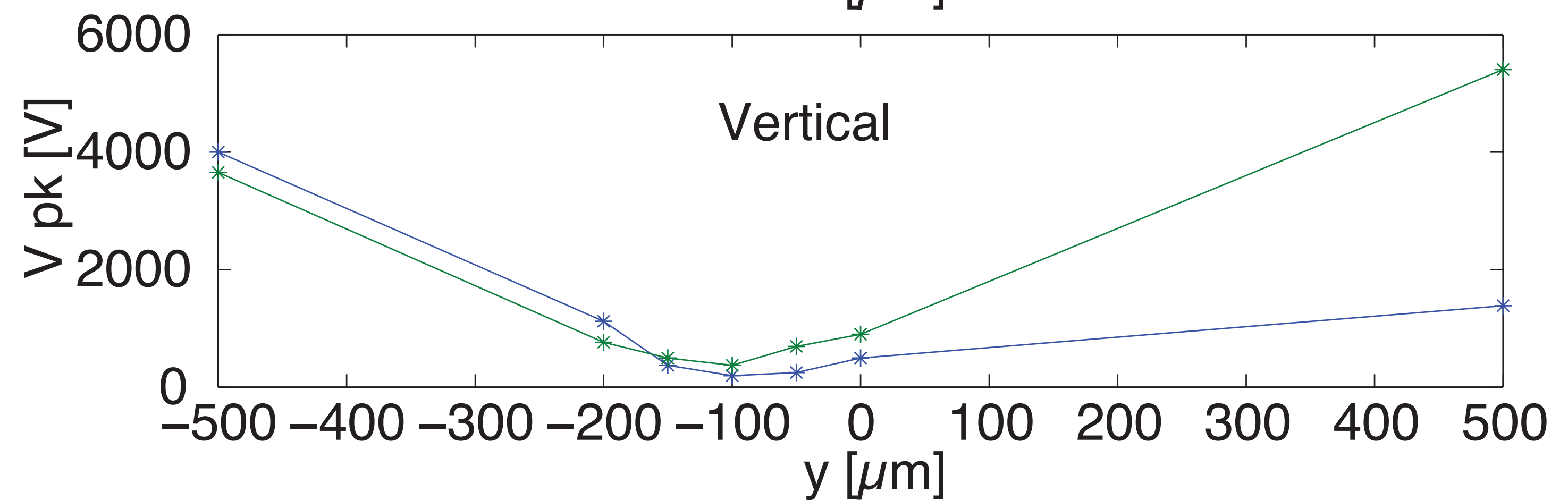
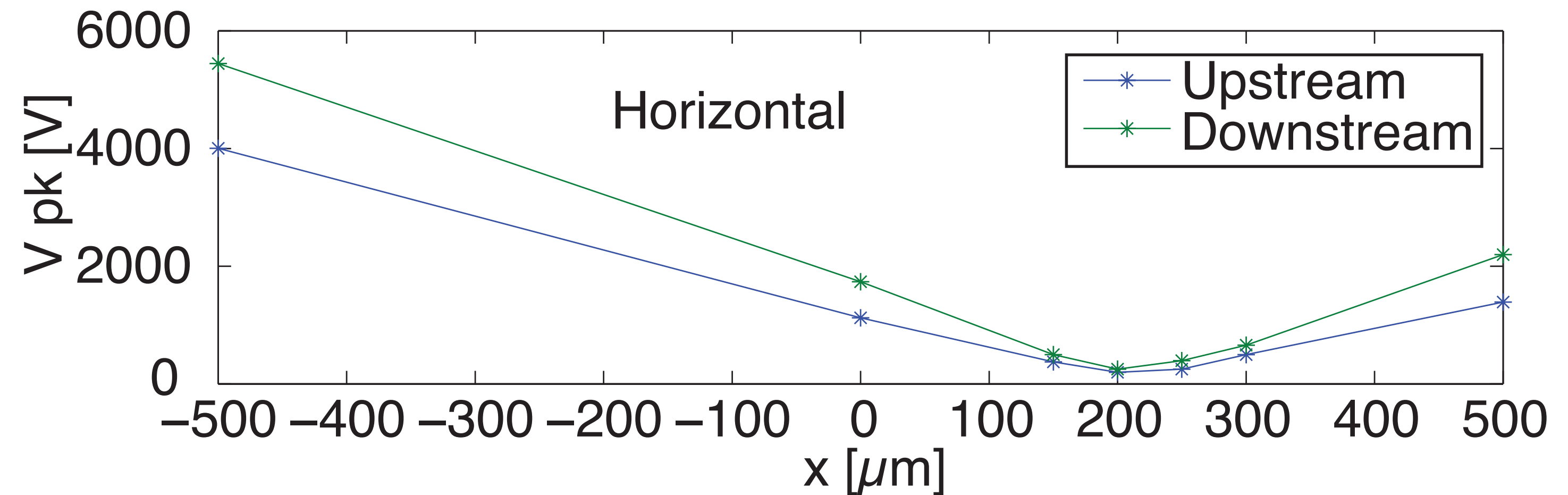


# Position Measurement: Wakefield Monitor

- > Position in X band linearizing cavity is important to reduce effects of wake fields
- > Wake fields can be measured directly

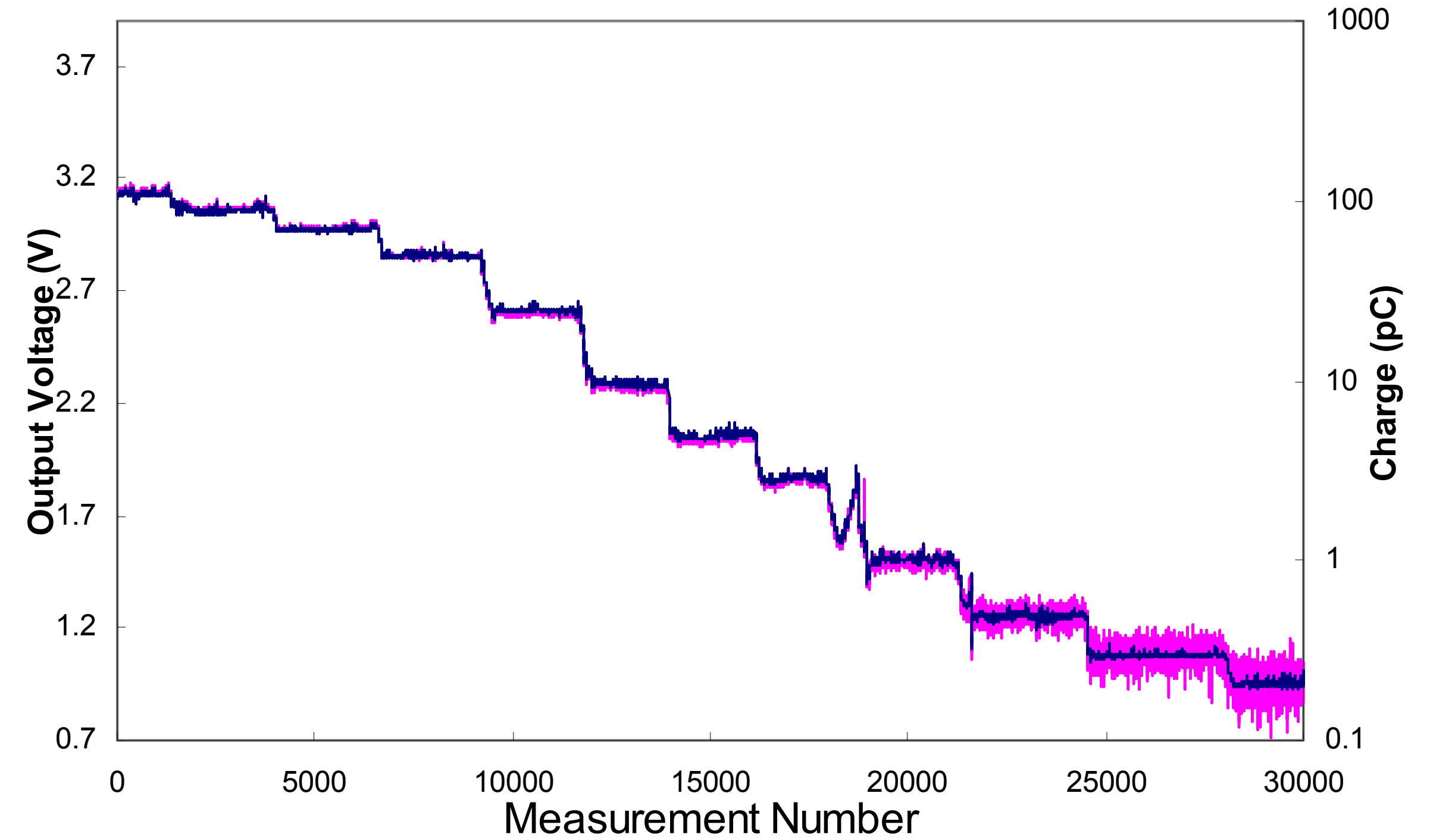
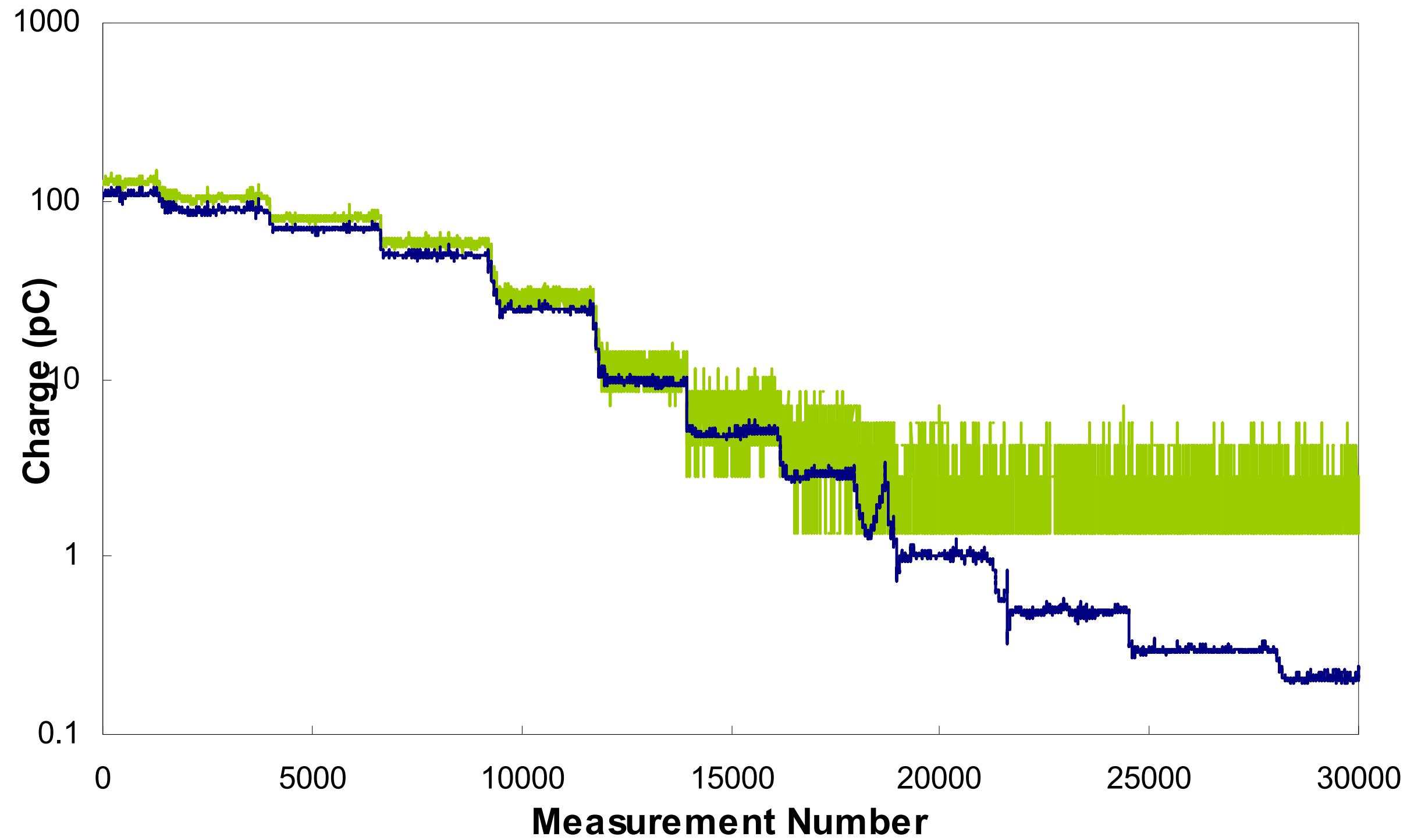


- > Outcoupling of wakefields at frequencies above 10 GHz requires special care in
  - > couplers
  - > cables
  - > data acquisition



# Charge Monitors

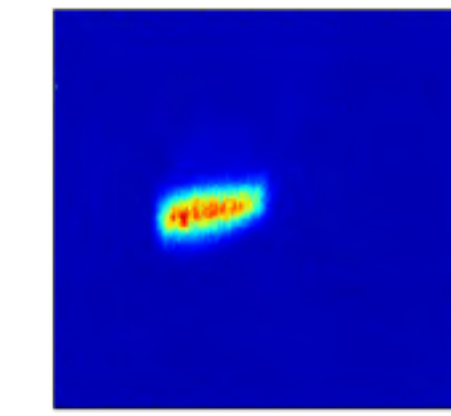
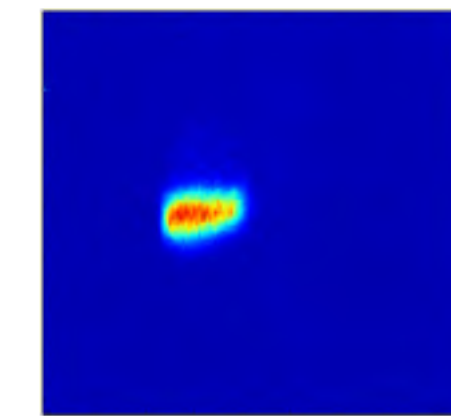
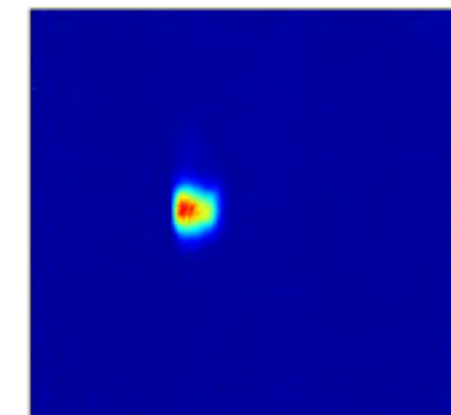
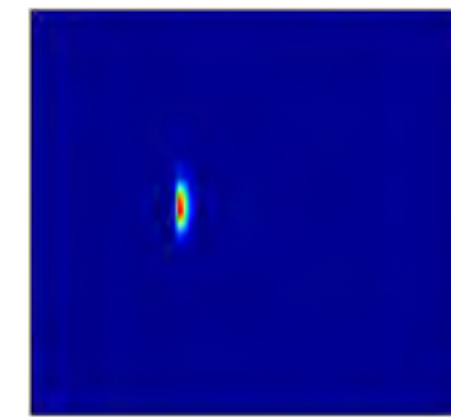
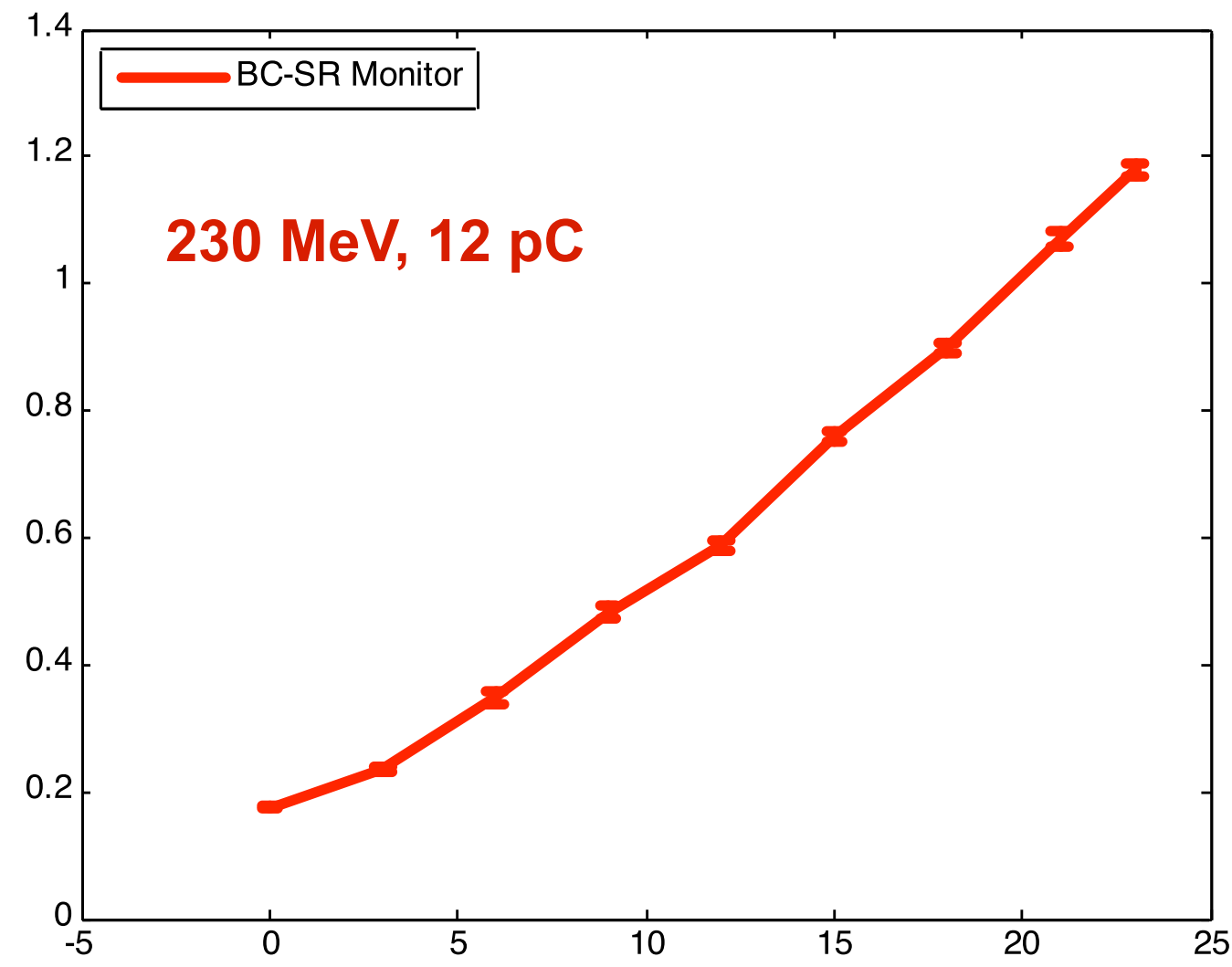
- > Absolutely calibrated integrating current transformers
- > New and improved model shows superior noise at low charge
- > Resolution: 1% at 120 pC



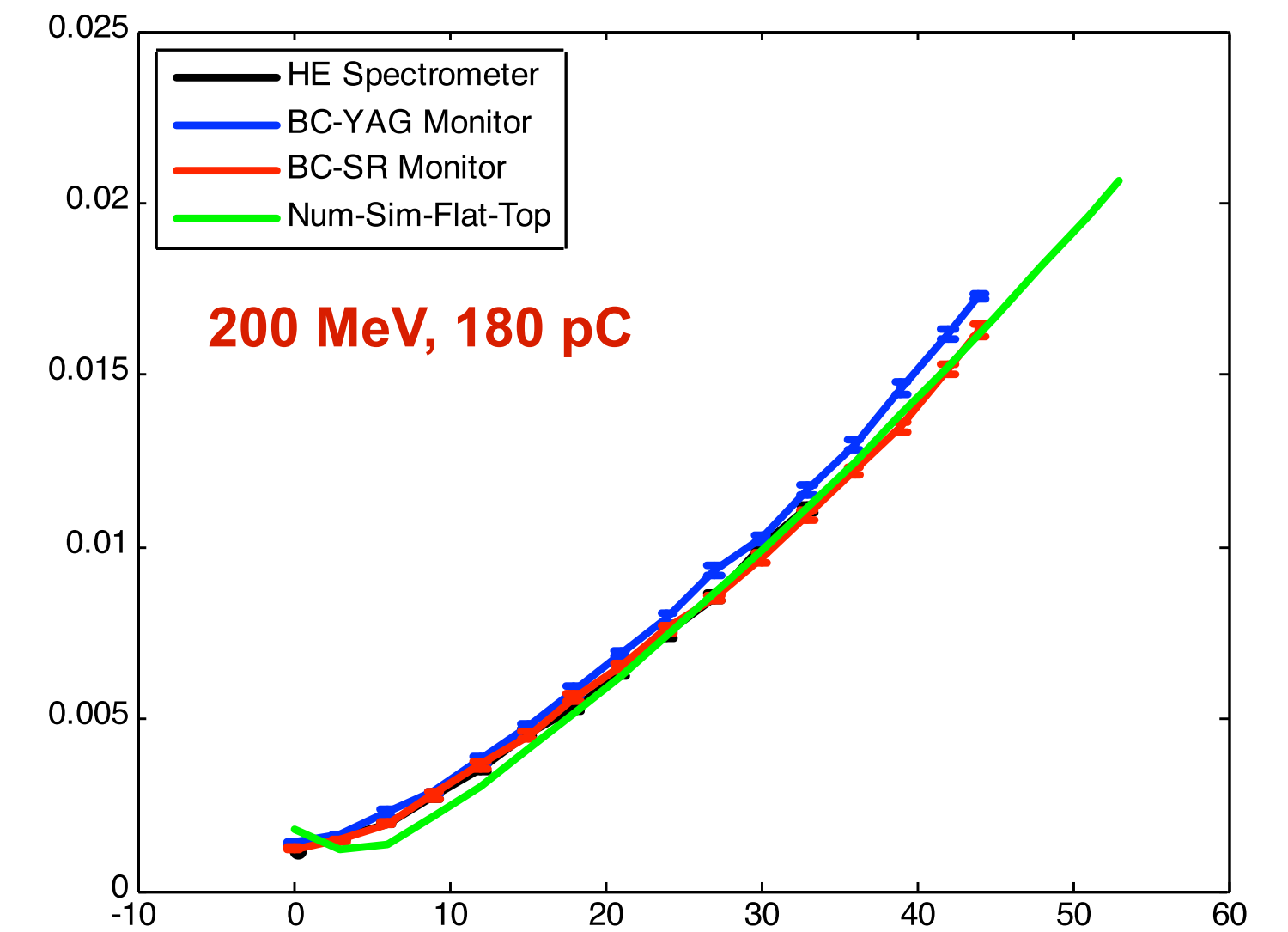
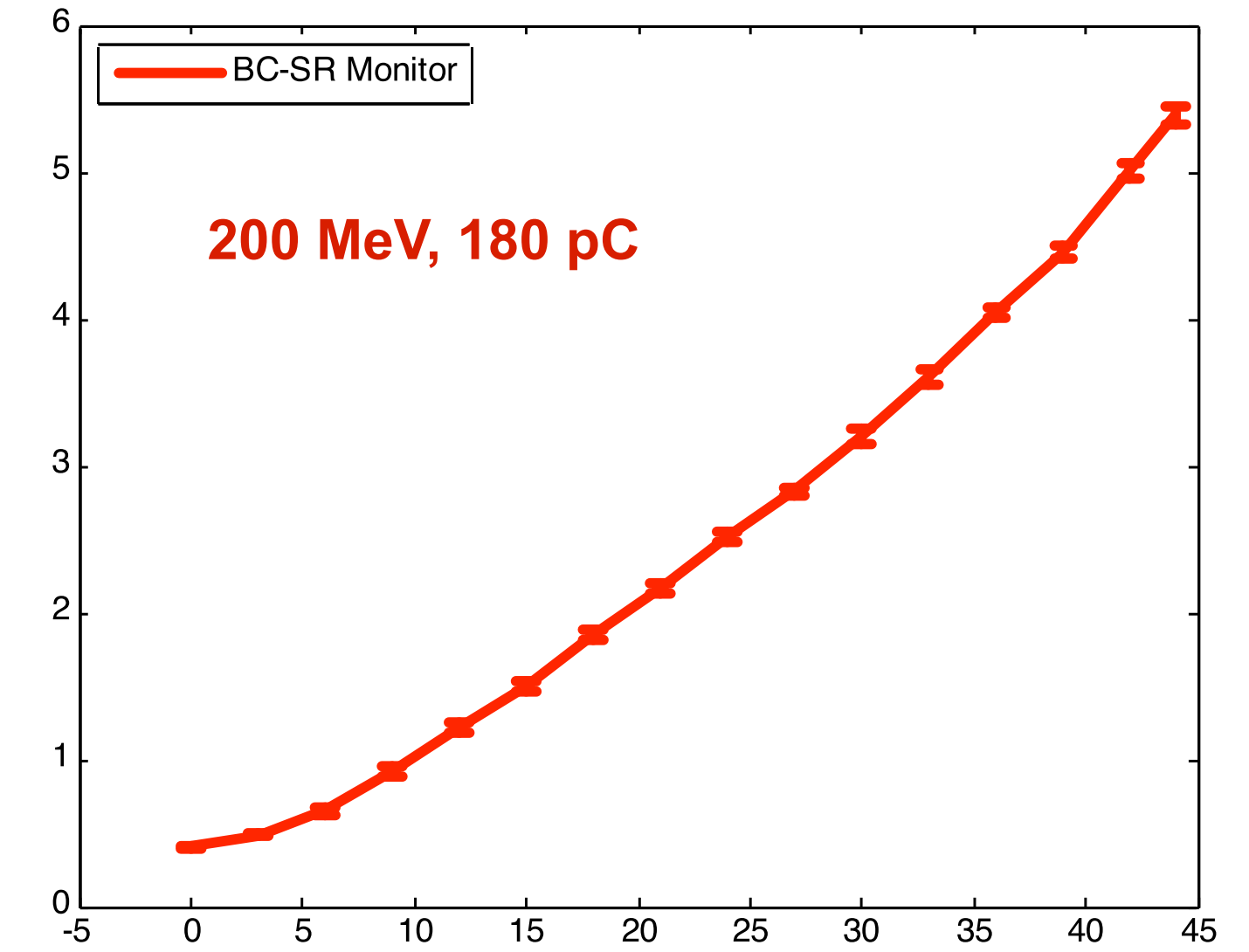
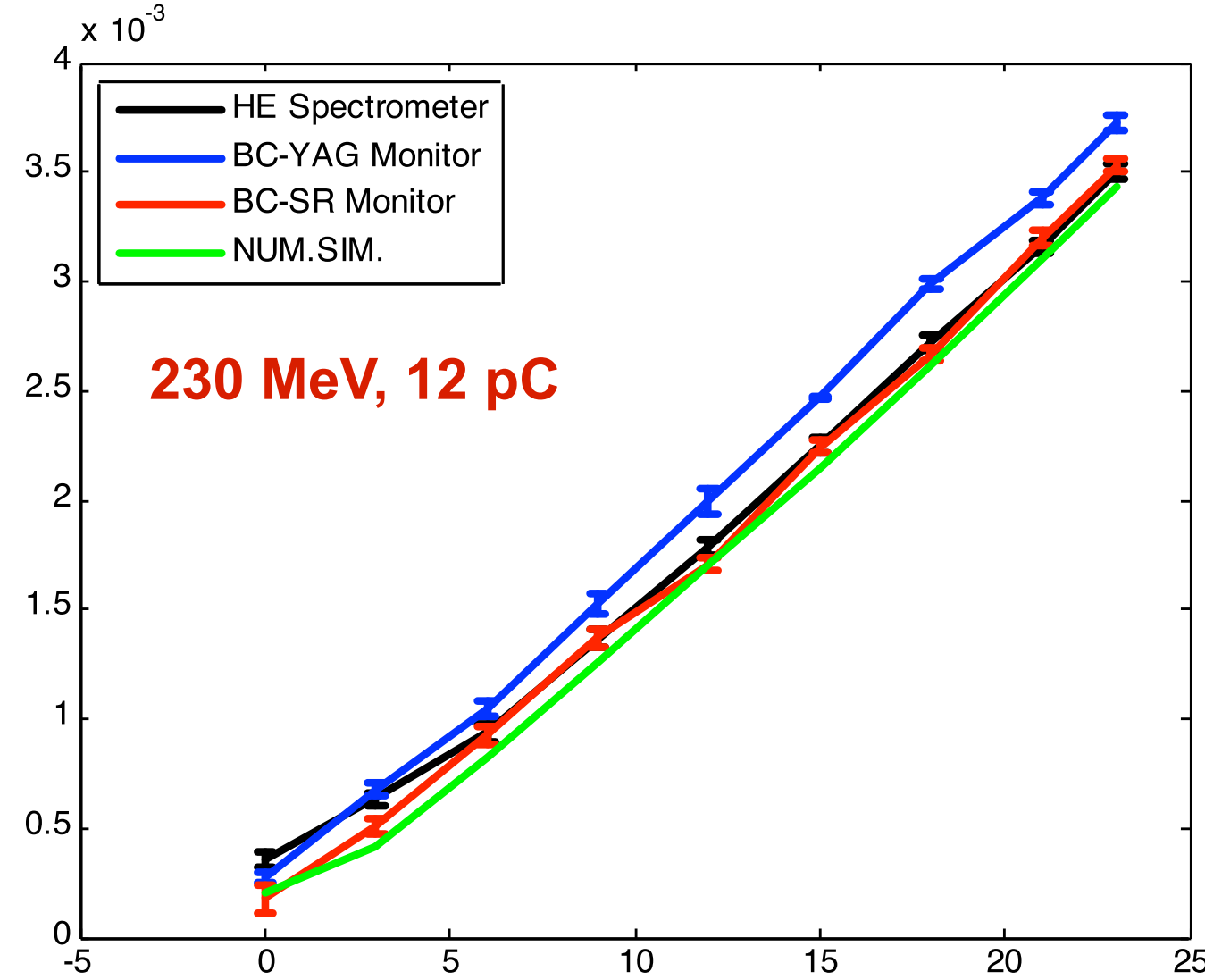
# Synchrotron Radiation Imager



# Synchrotron Radiation Imager

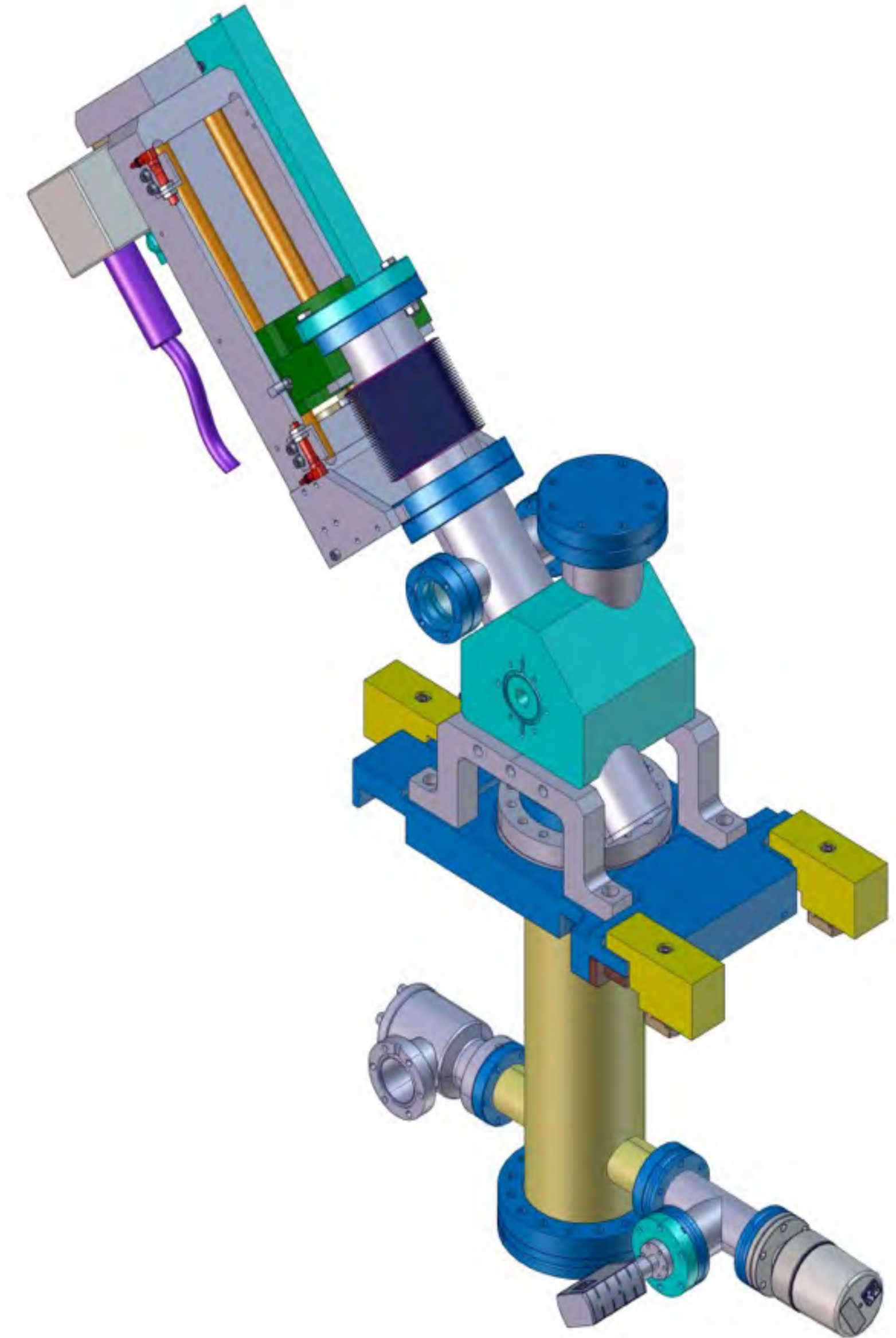
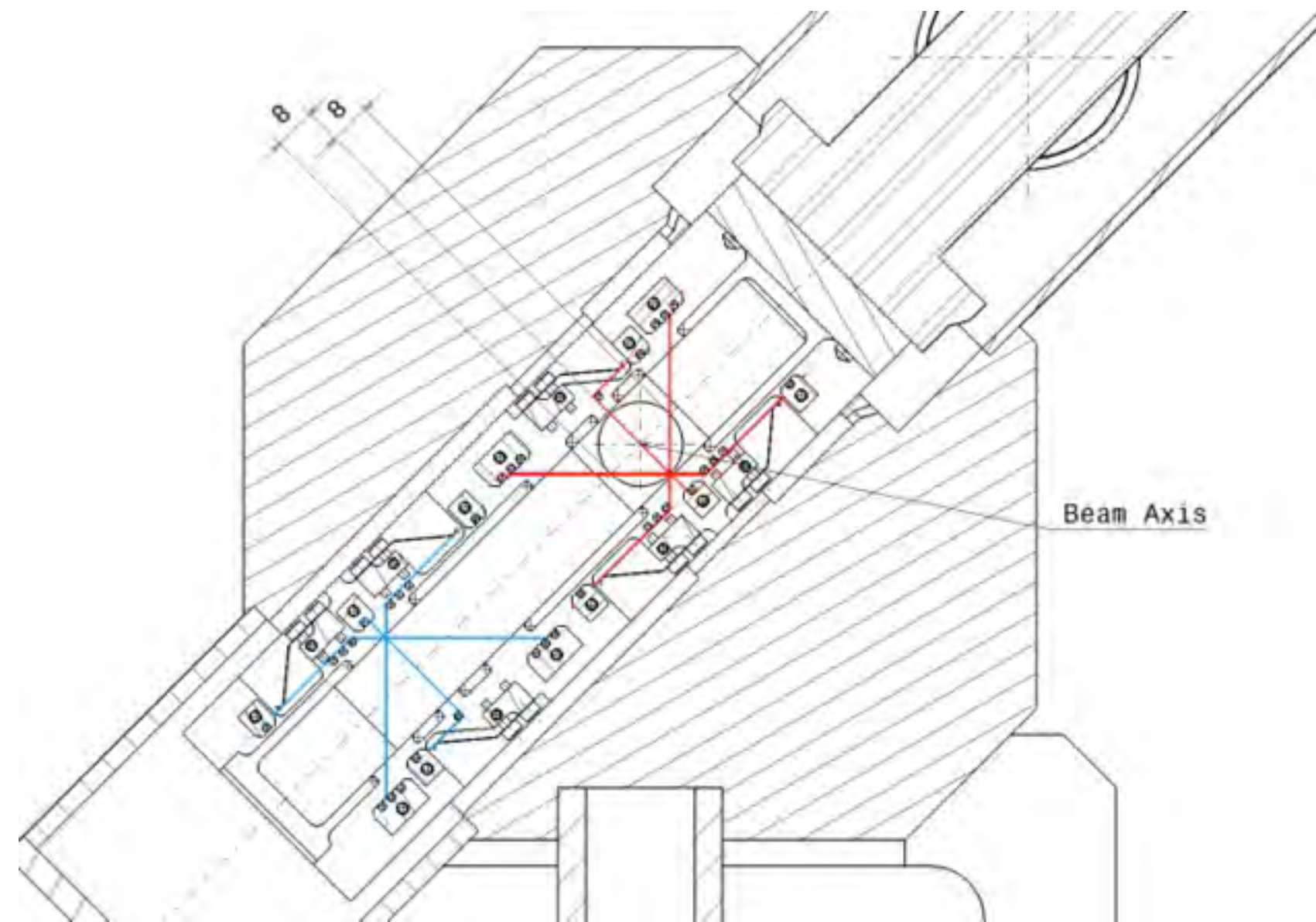


12 pC, SR Monitor images,  
0- 23 deg OFF RF Crest



# Wire Scanners

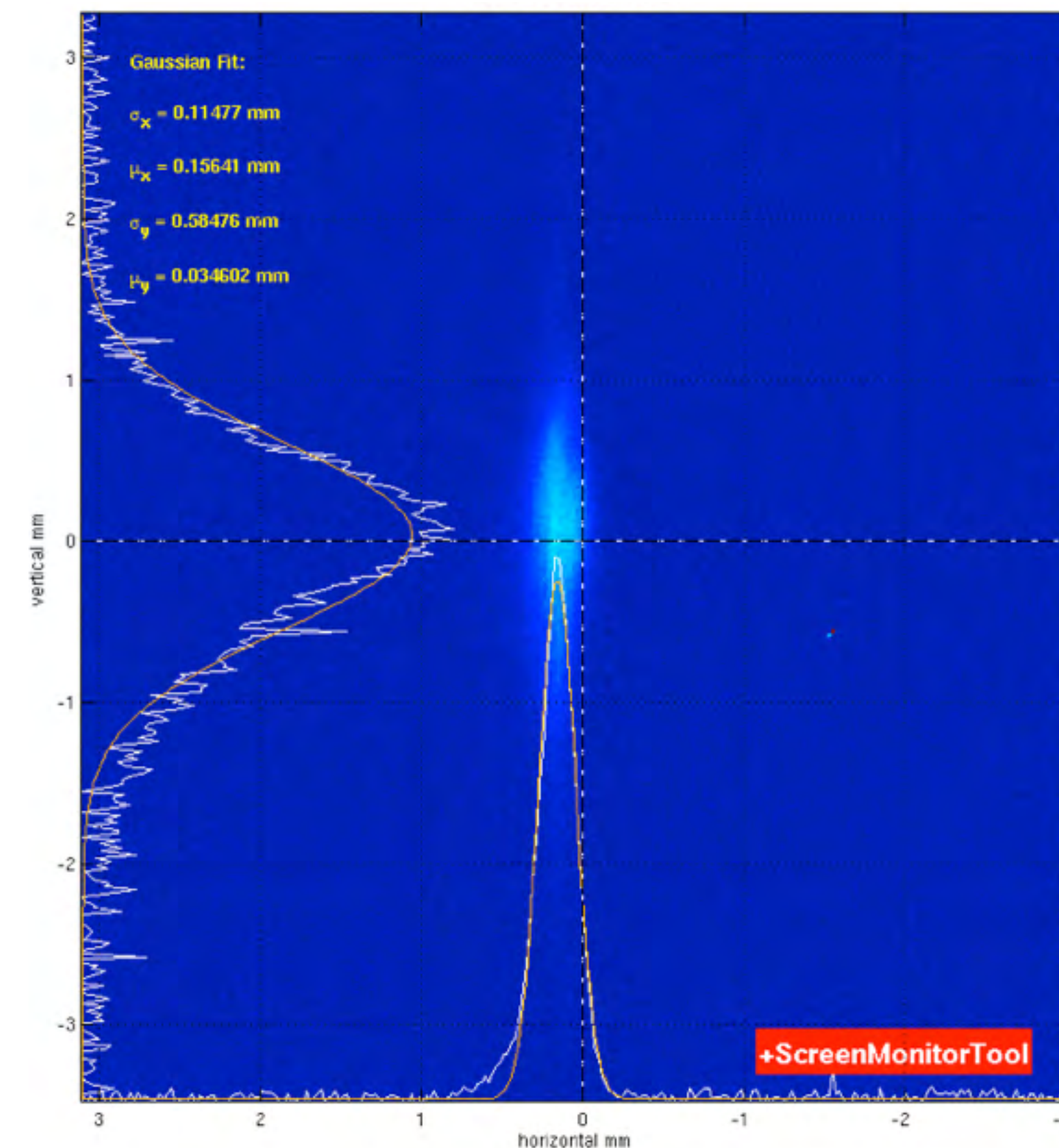
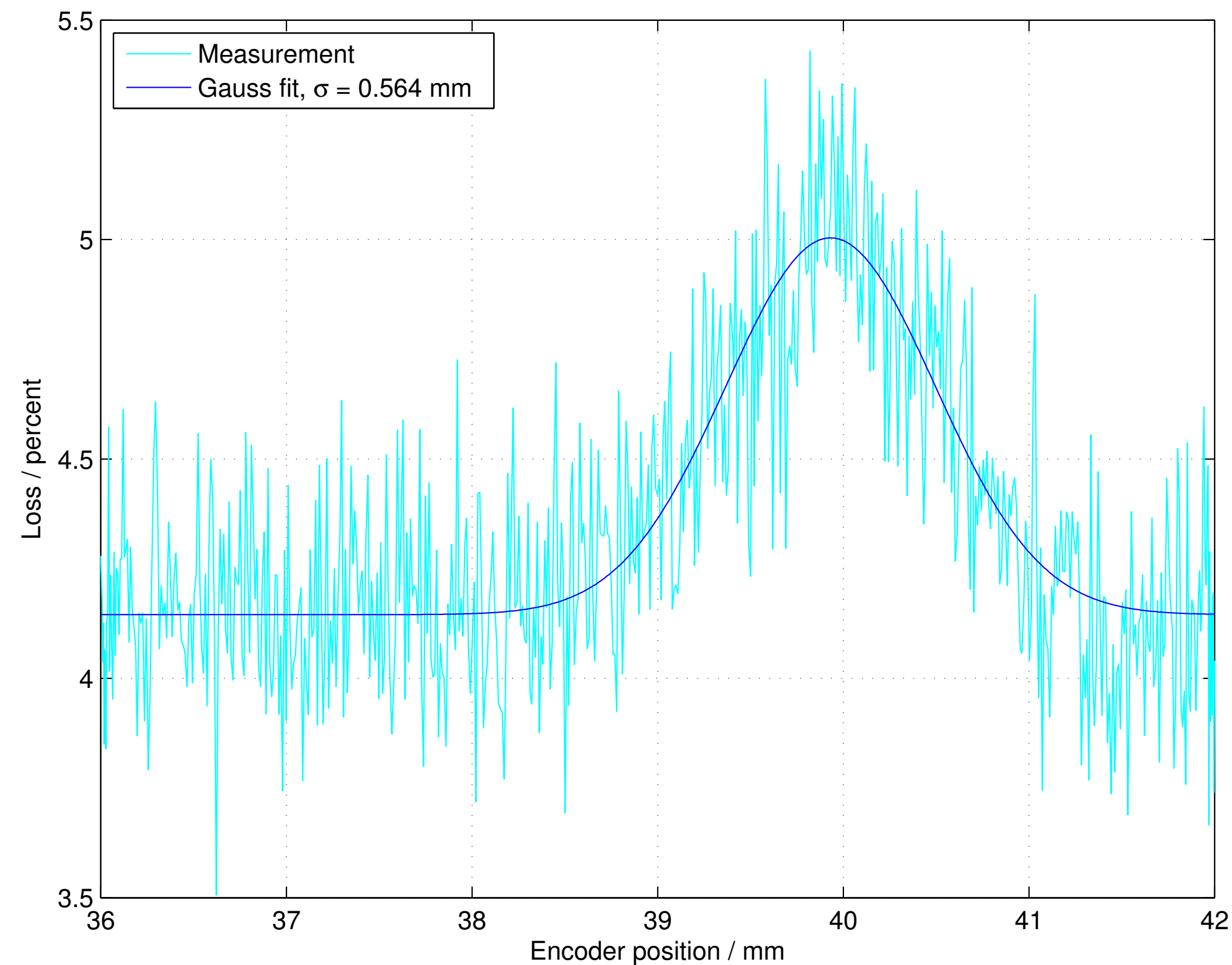
- > SwissFEL version:
  - > Inserted at  $45^\circ$  → measurement of horizontal beam size possible
  - > Can be used in a quasi-parasitic mode



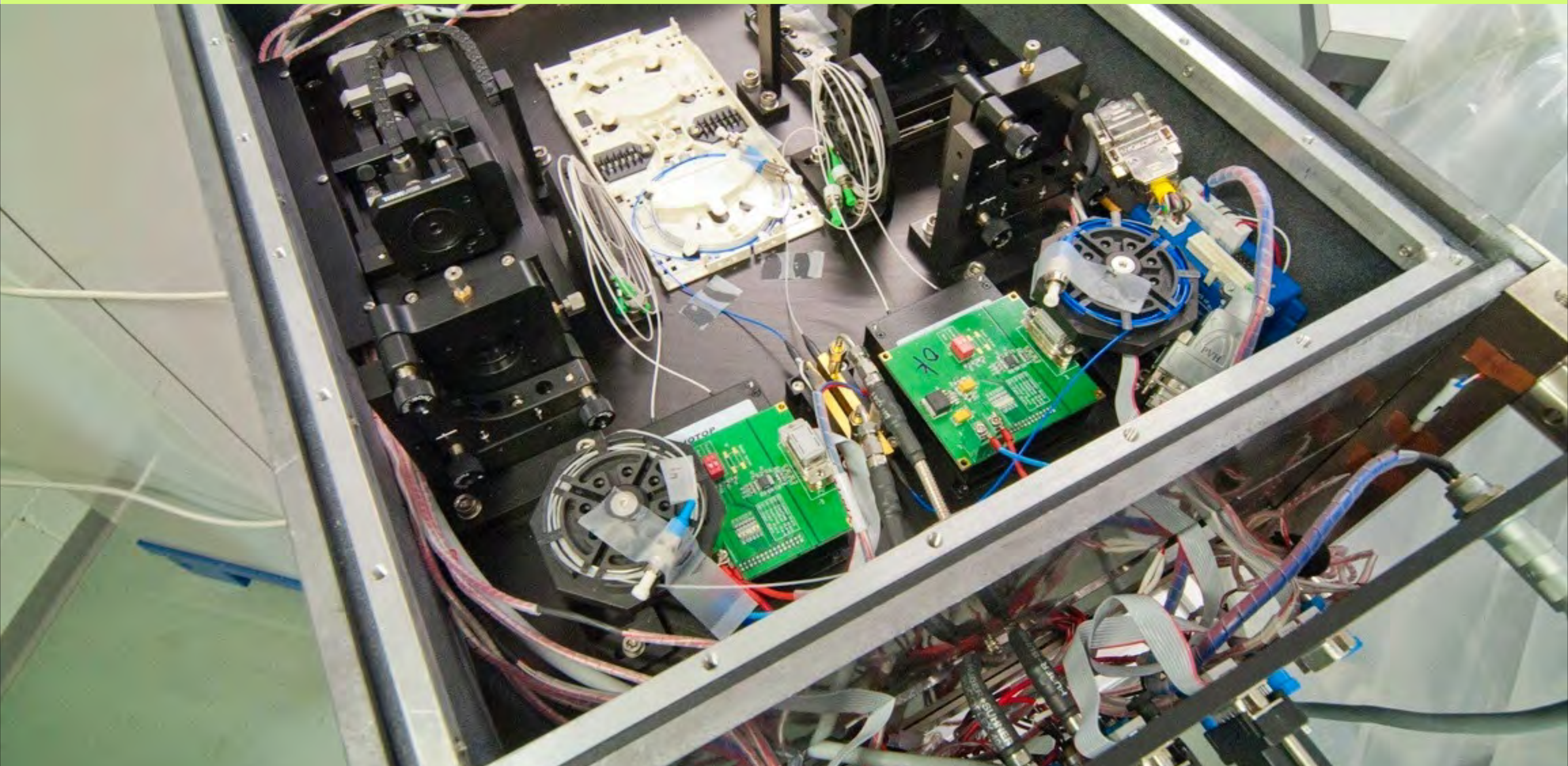
3 different pin positions ↔ 3 different Wire separations (8, 5 or 3.5 mm) ↔  
**3 different scan time (for a fixed wire velocity)**

# Wire Scanners

- > Wire scanners installed at all screen stations > 100 MeV
- > Measurements performed with horizontal wire:
  - > Charge measurement before and after wire
  - > Using beam synchronous data acquisition for encoder and charge (BPMs)
  - > Comparison to OTR measurements

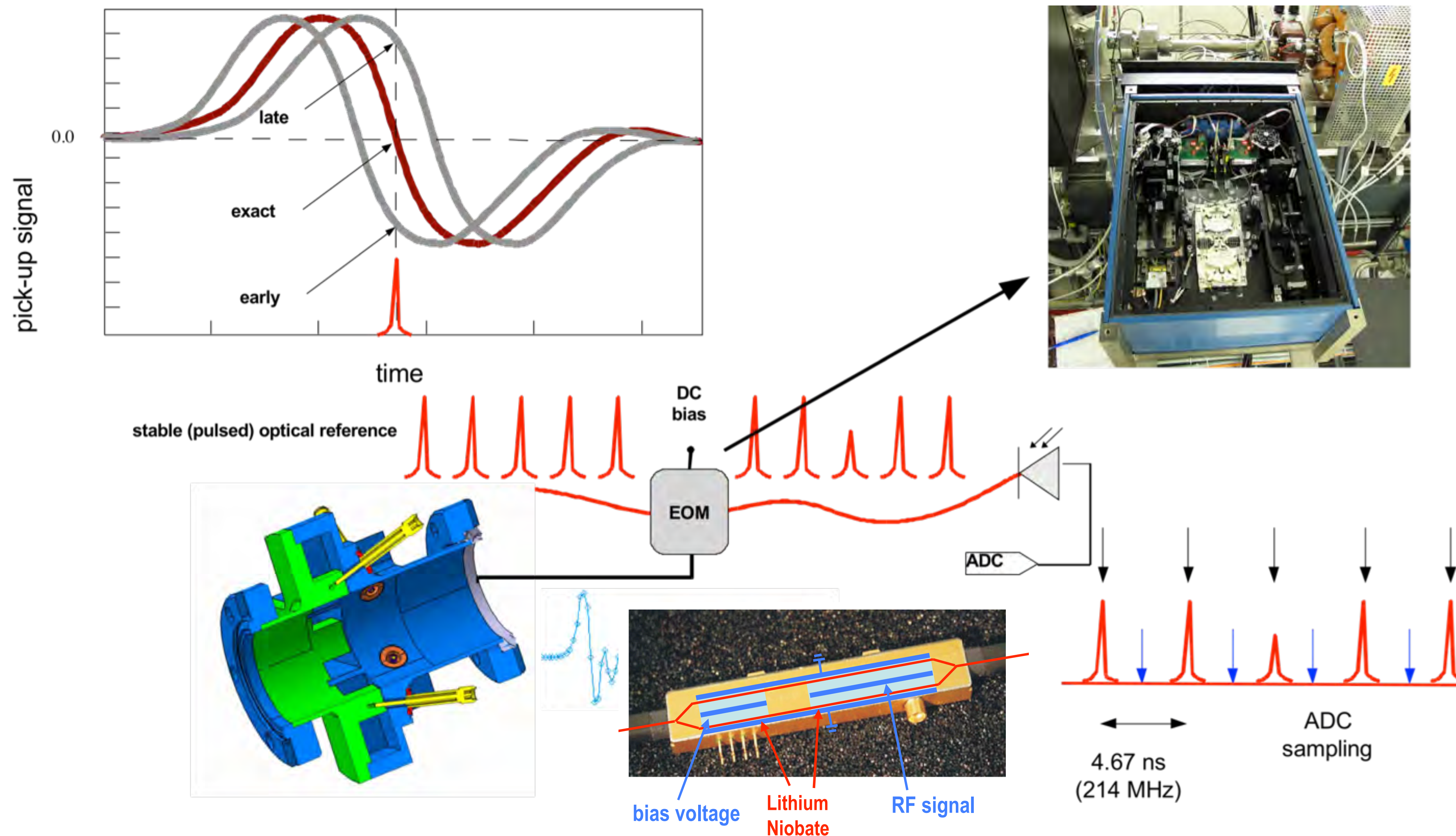


# Bunch Arrival Monitor



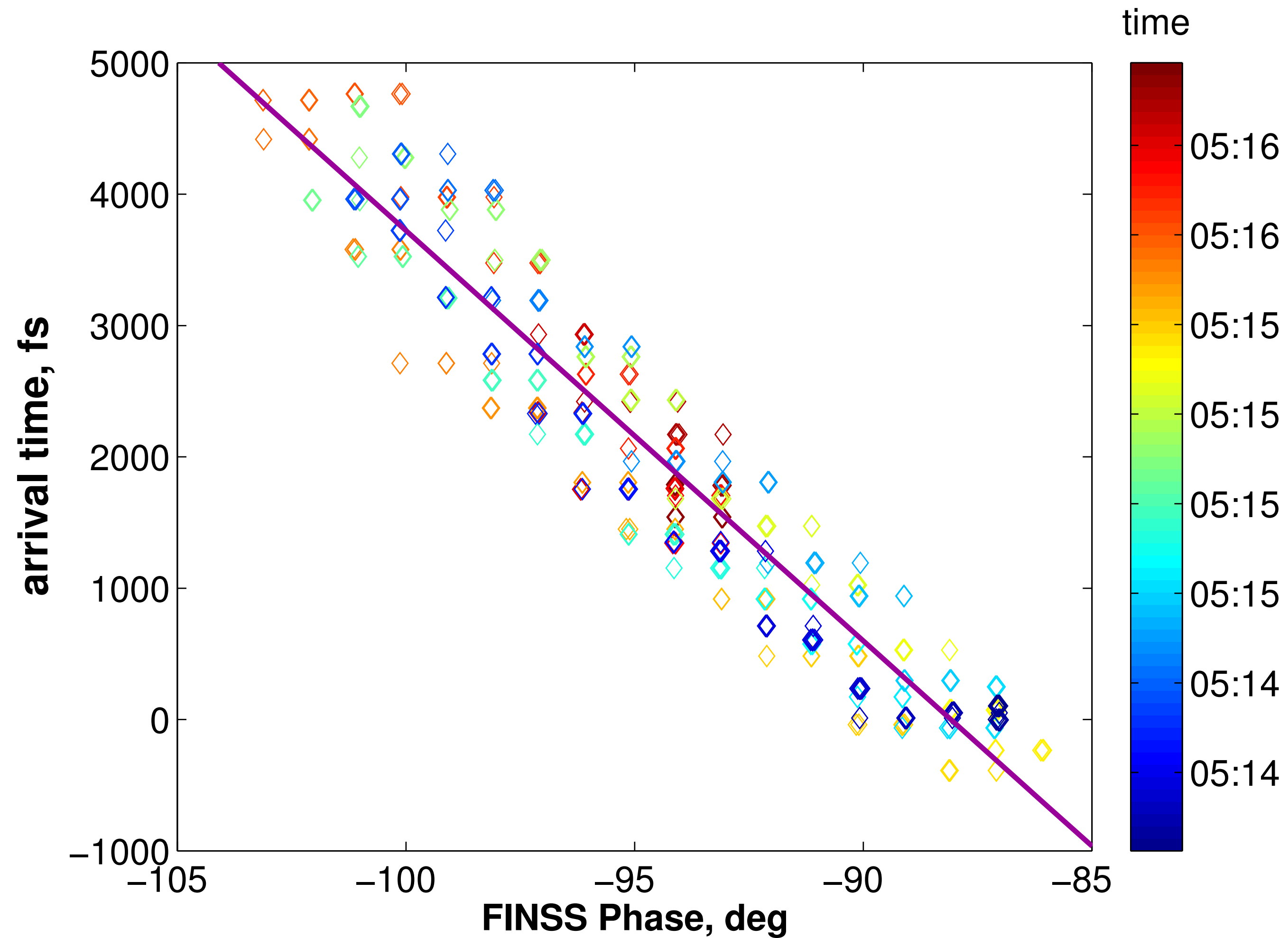
# Bunch Arrival Monitor

> Arrival time signal generated at pickup is transferred onto an electro-optical modulator

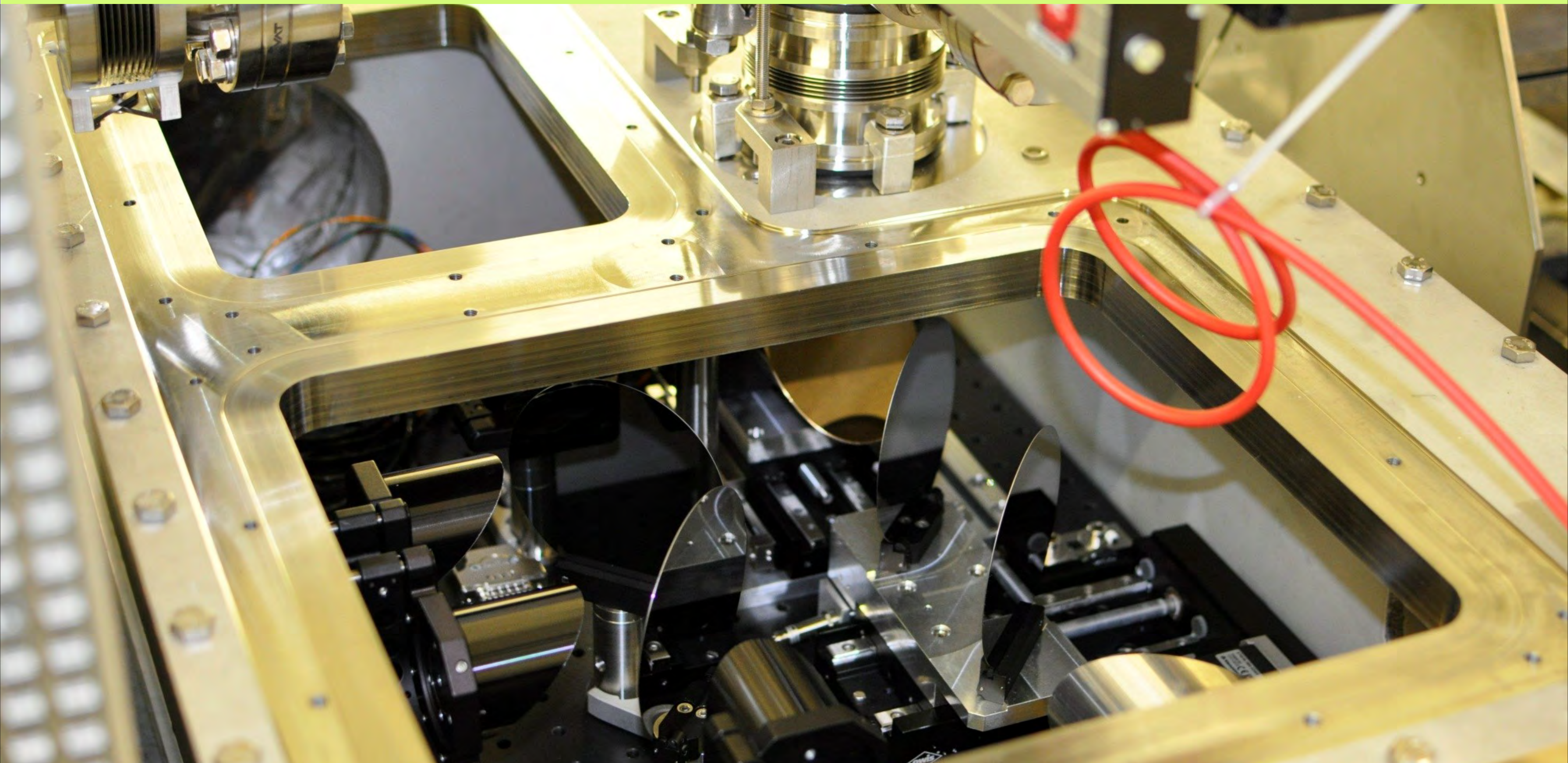


# Bunch Arrival Monitor

- > Dependence of arrival time on gun phase
- > Resolution of BAM: 18 fs rms

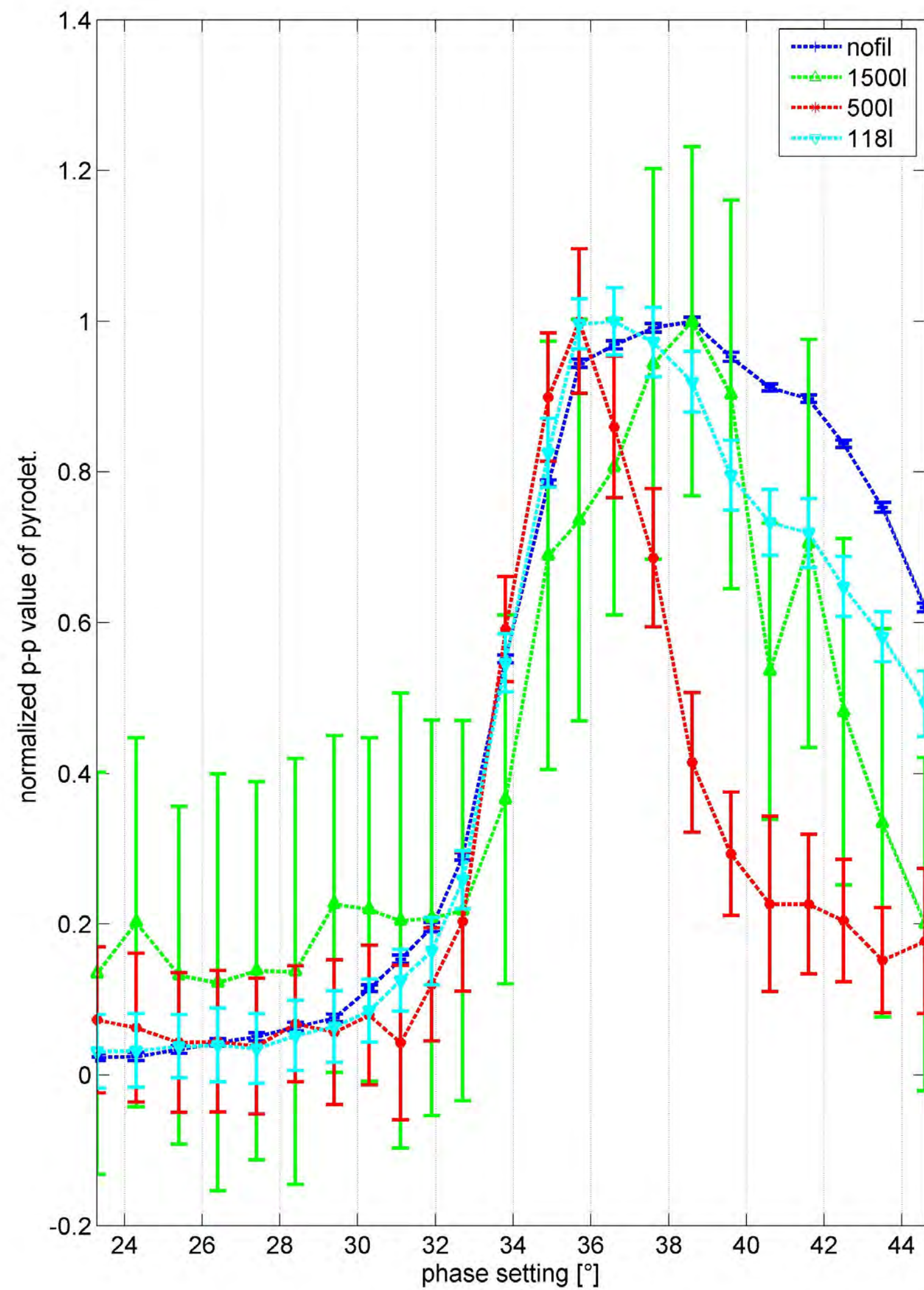


# Form Factor Monitor

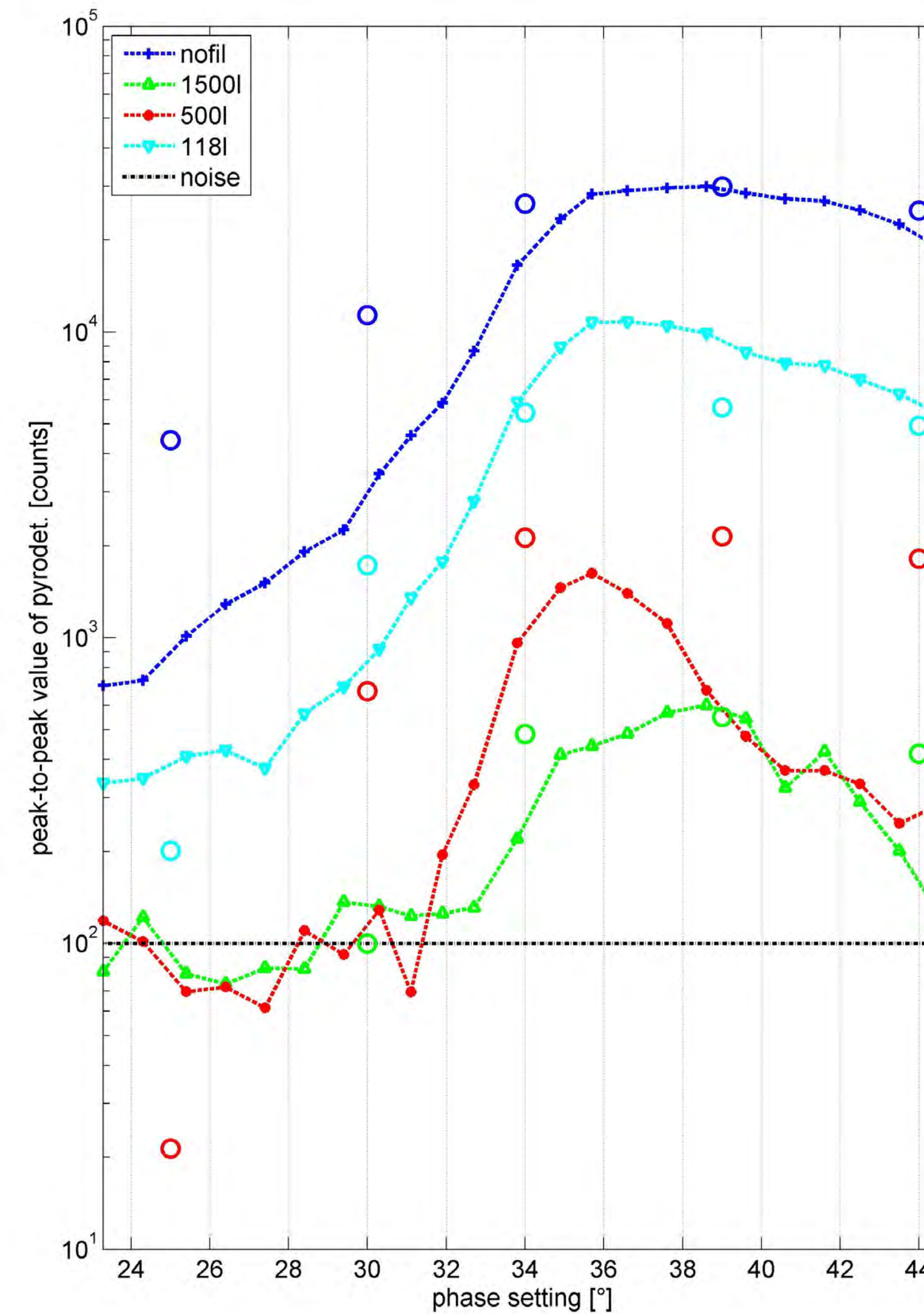


# Form Factor Monitor

## Normalized signals from pyros with different filters



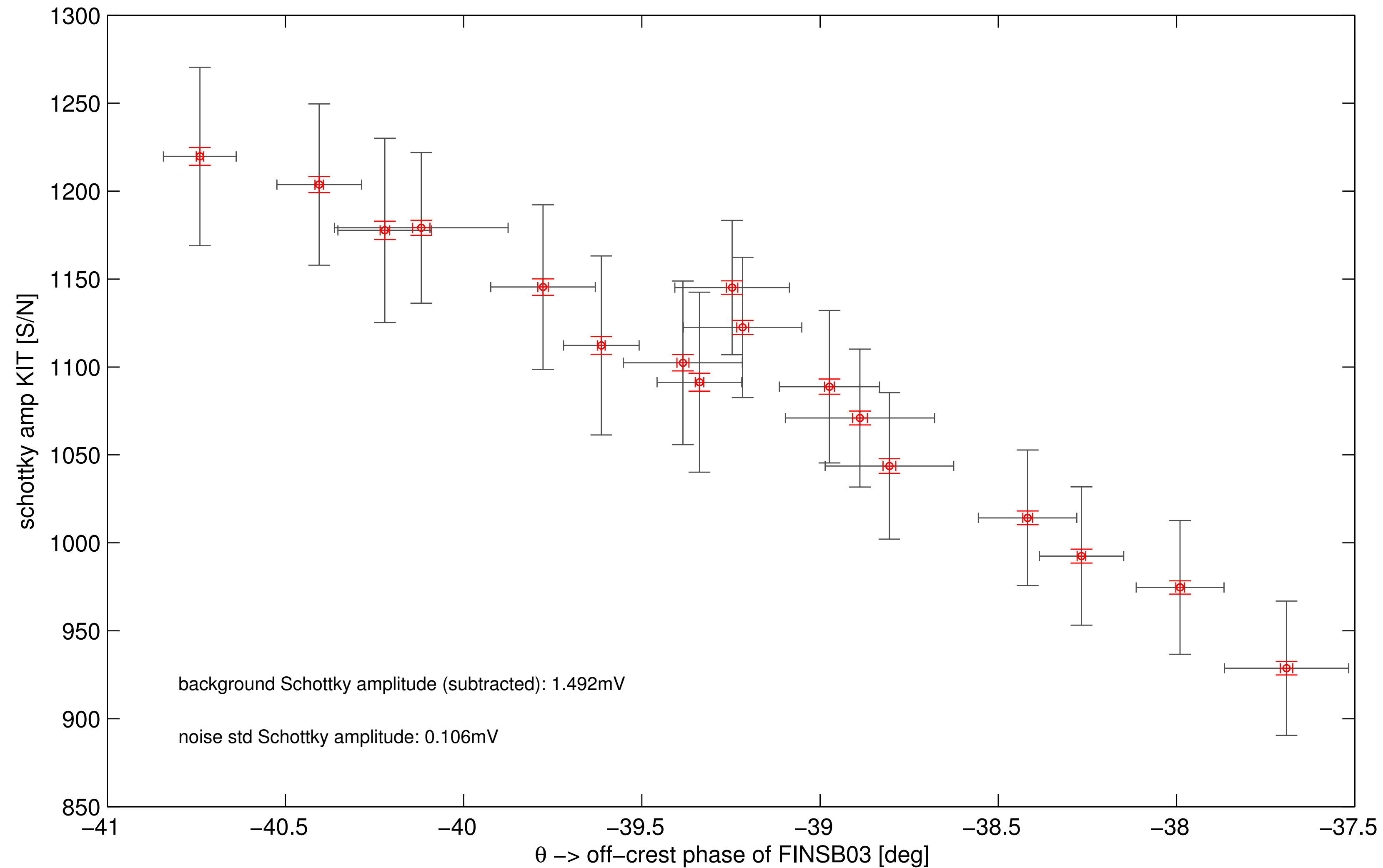
## Pyro signals compared to expected response



# Form Factor Monitor

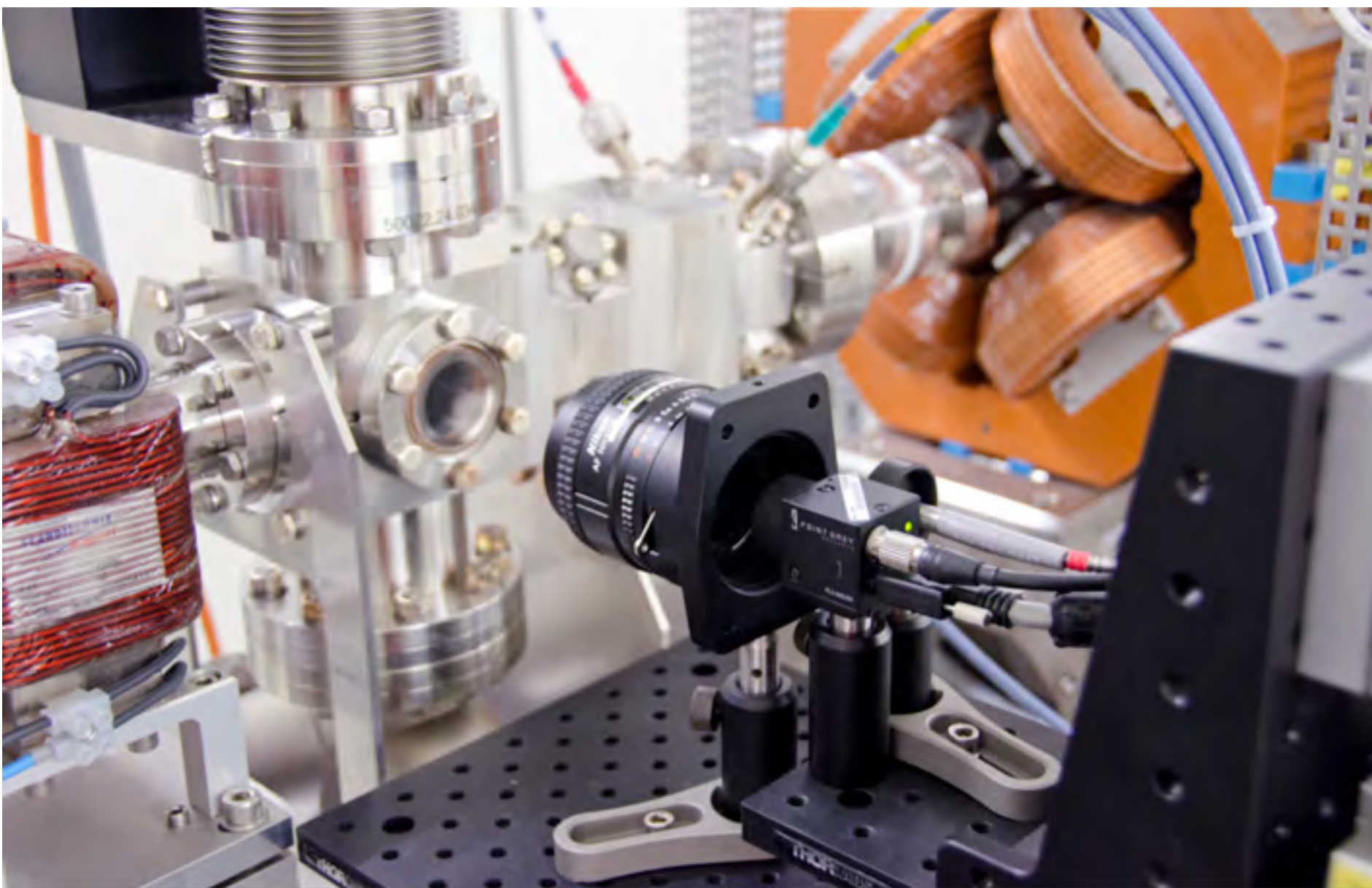
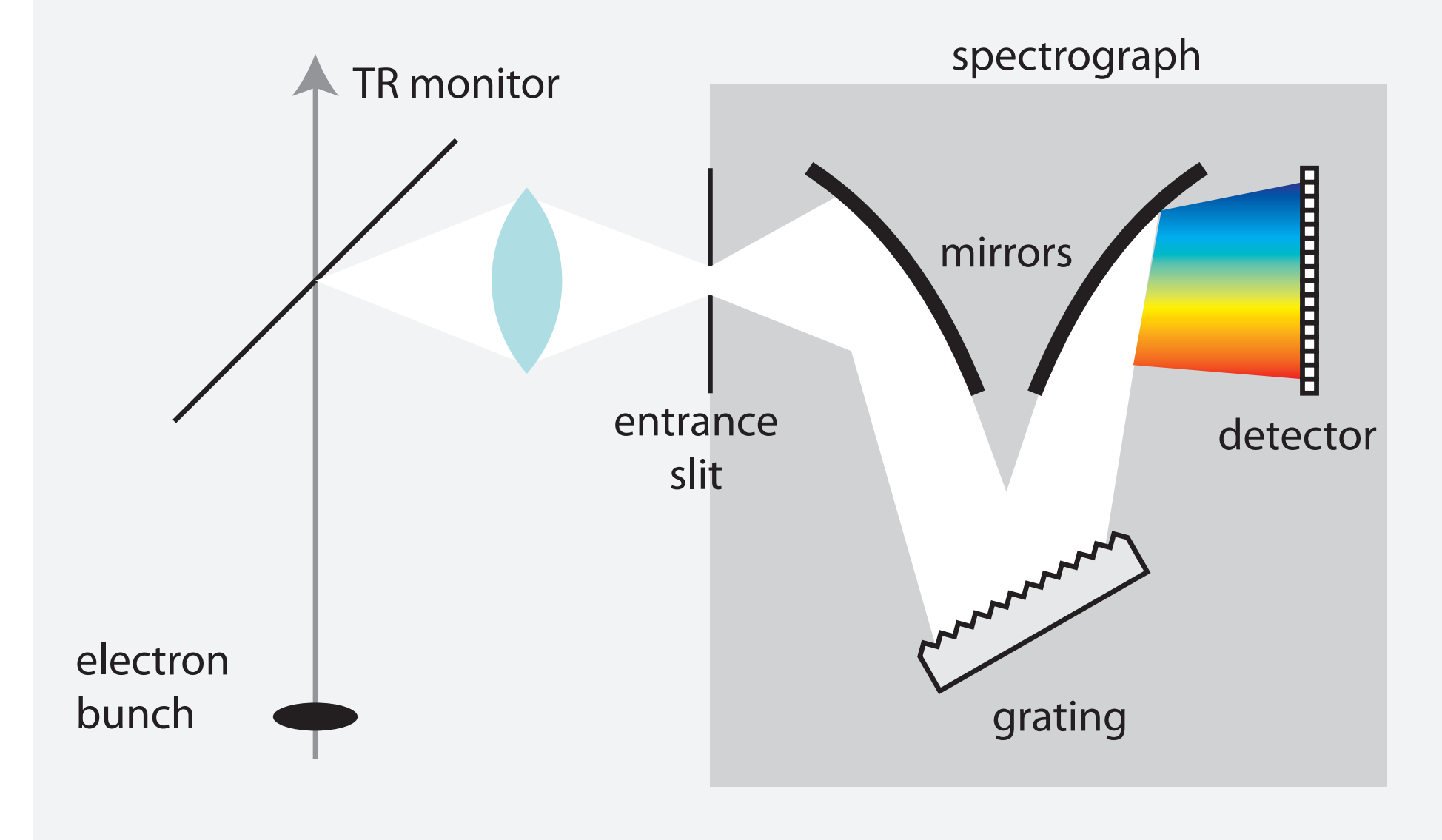
> New detector with improved signal-to-noise at 10 pC bunch charge

WEPC36

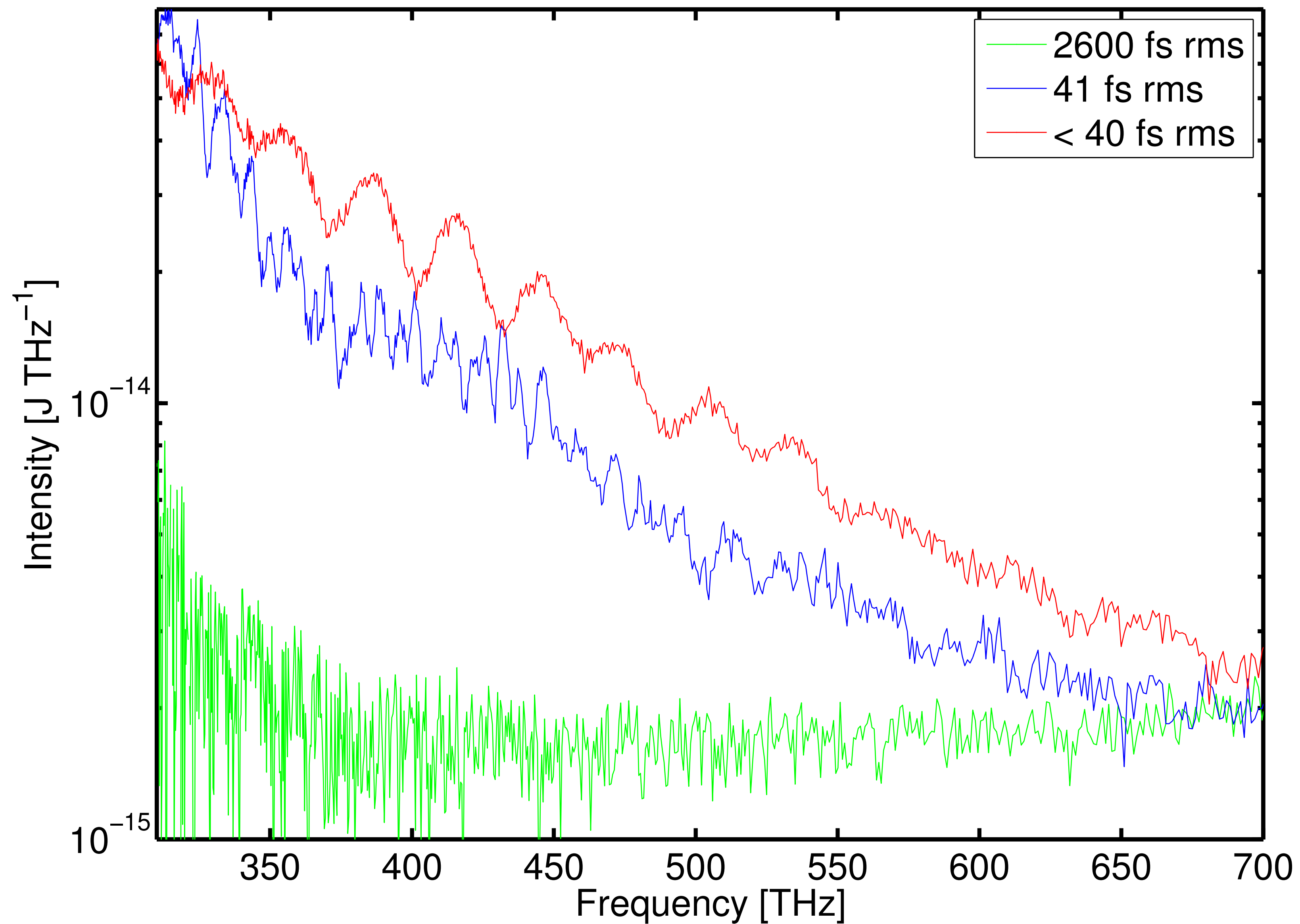


# Optical Spectrum of Transition Radiation

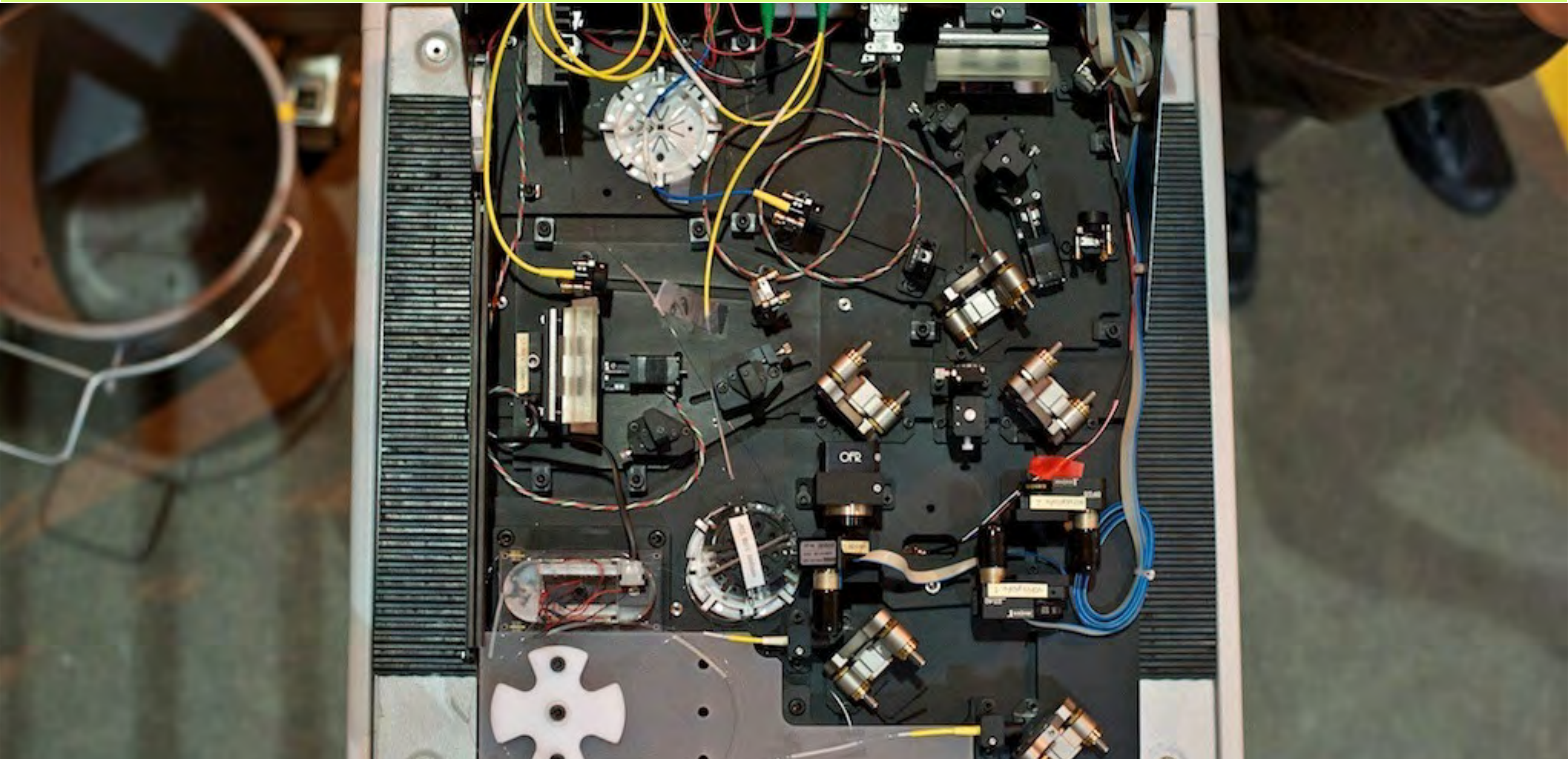
- > Experimental Setup in the SwissFEL Injector Test Facility
  - > Transition radiation from aluminum coated silicon screen
  - > Focusing with lens, now replaced by mirror
  - > Commercial spectrometer with wide spectral range from 316 to 1363 THz



# Optical Spectrum of Transition Radiation

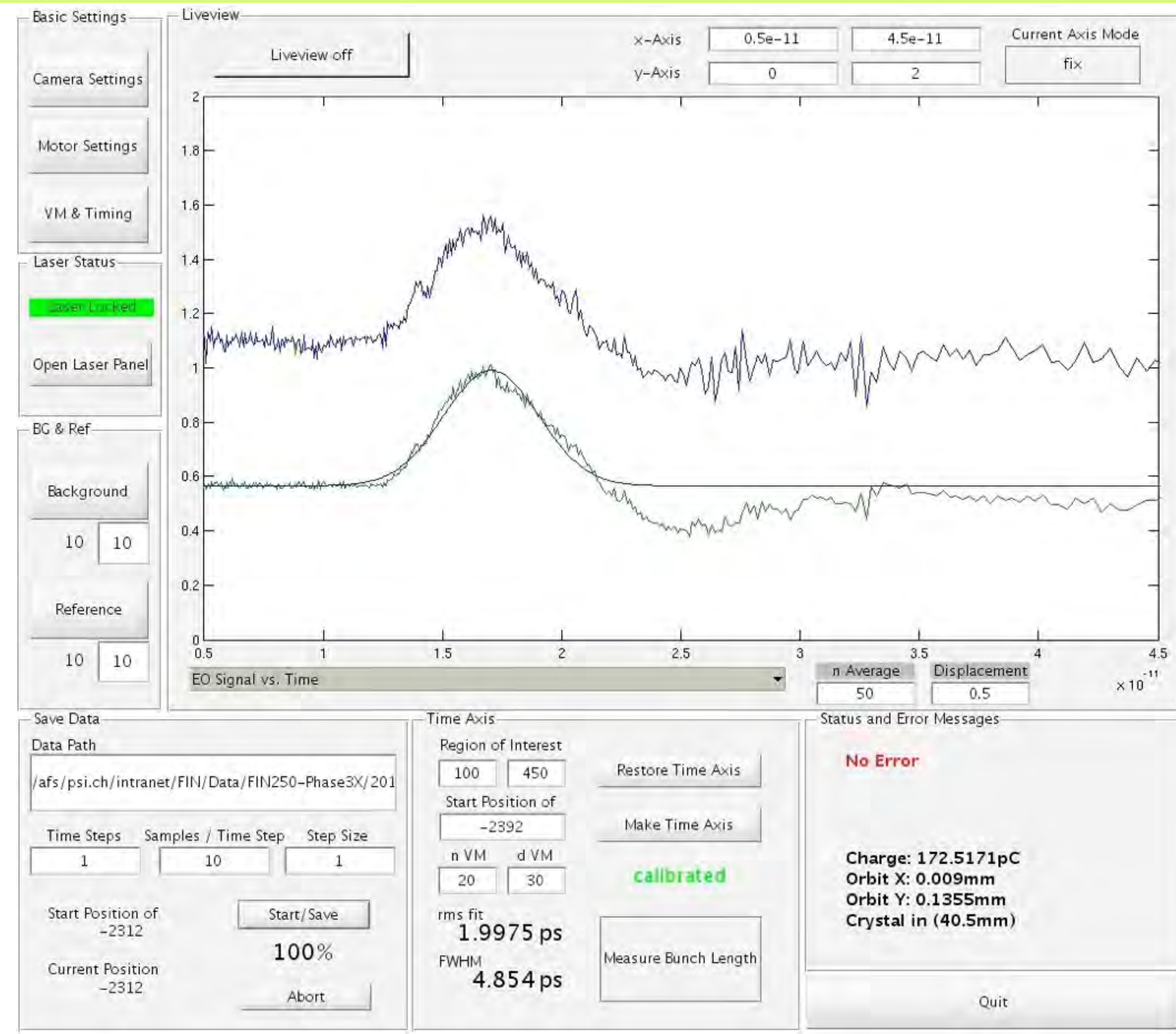


# Electro-Optical Monitor



# Electro-Optical Monitor

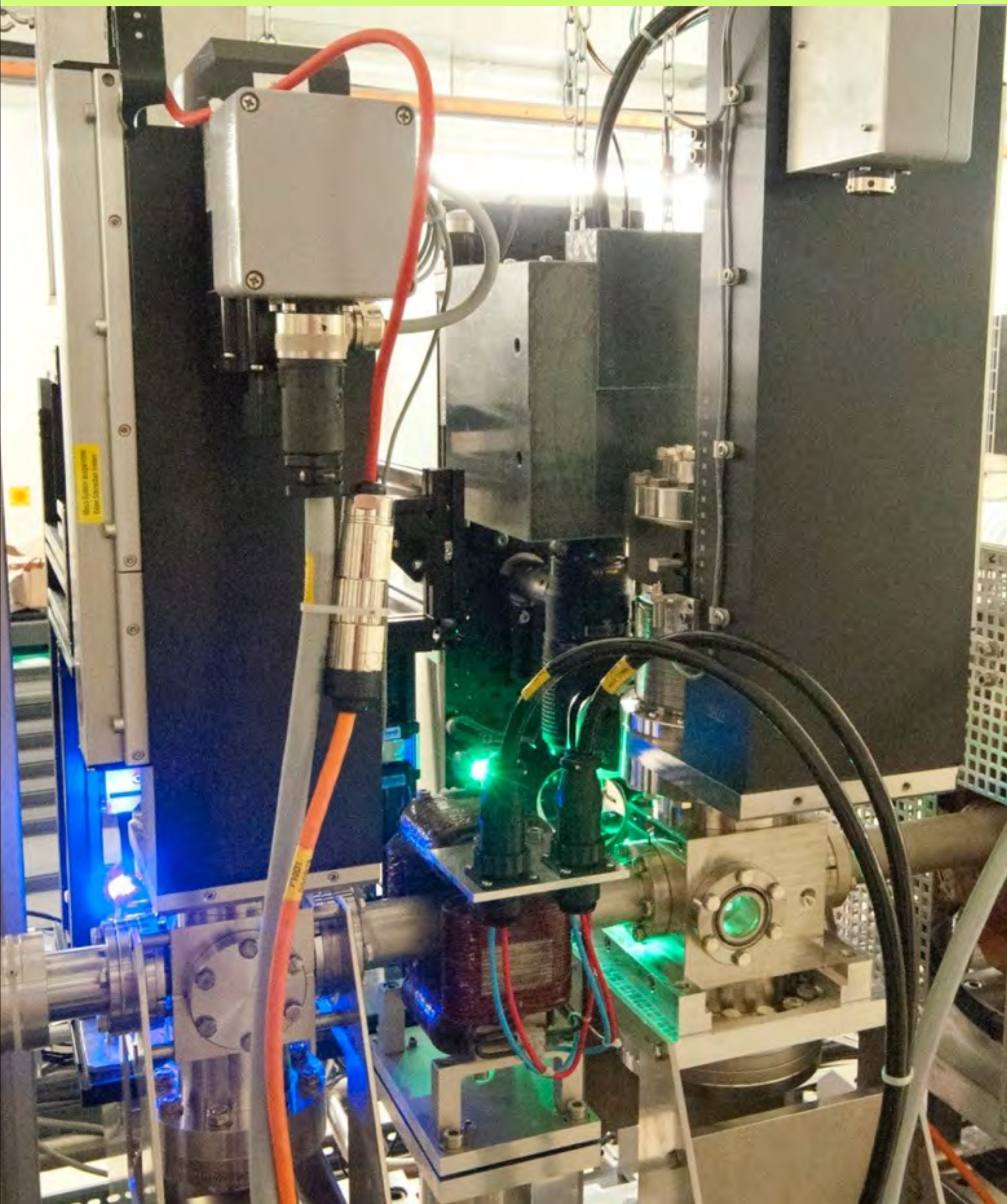
WEPC37



# Transverse Profile: Screen Monitor

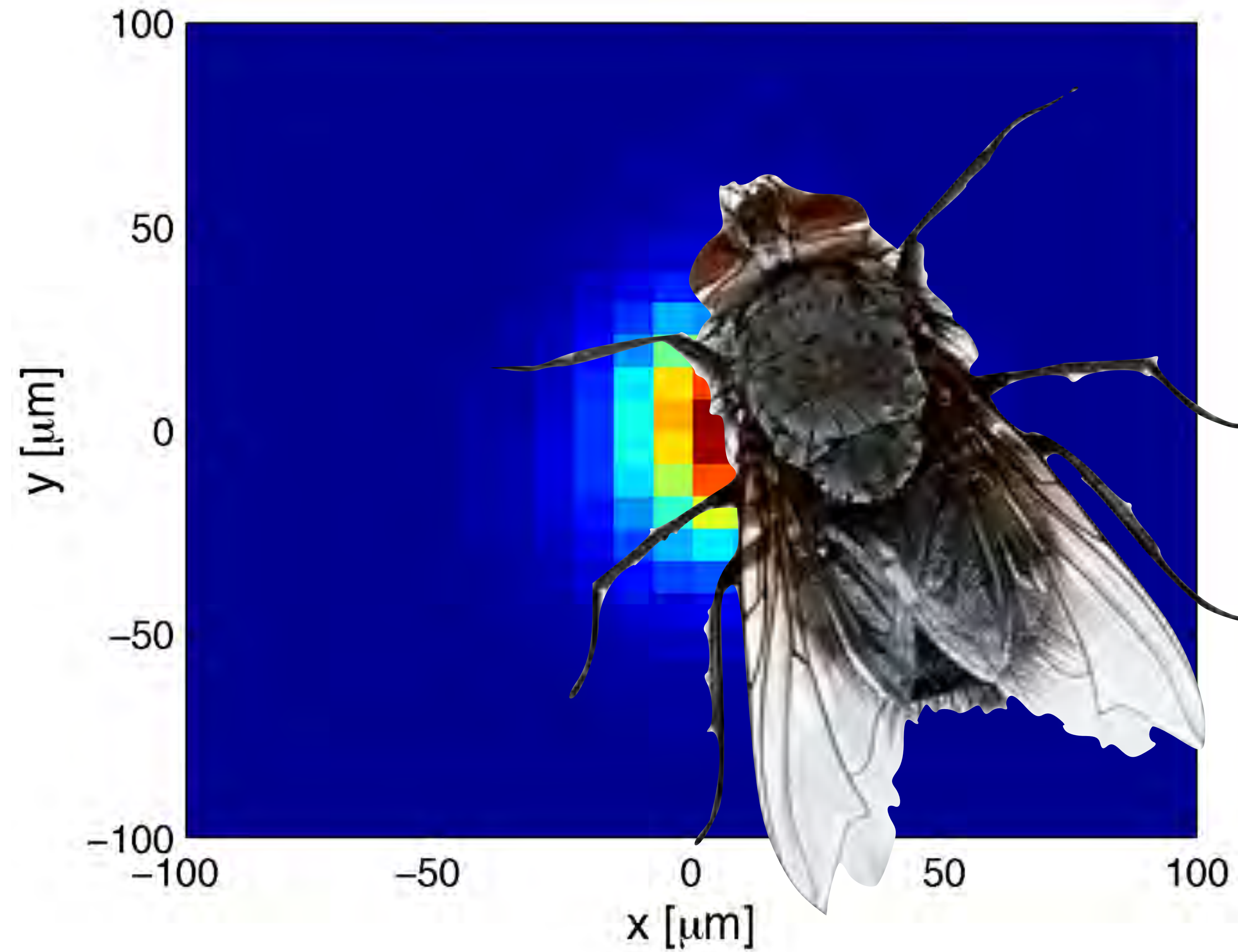


# Transverse Profile: Screen Monitor



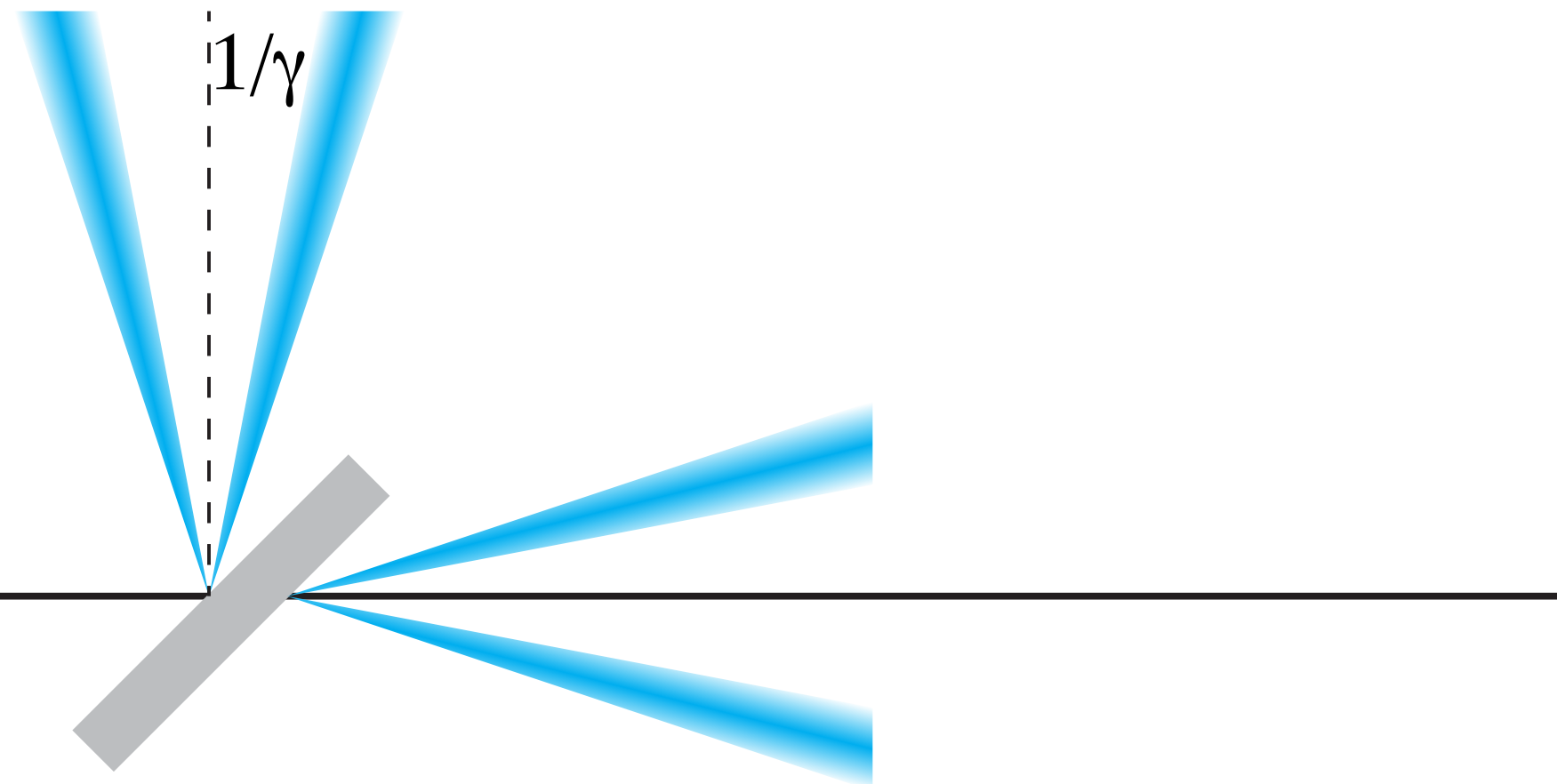
# Transverse Profile: Screen Monitor

- > Goal:  
Measurement  
of small  
beams  
(10  $\mu\text{m}$  rms)

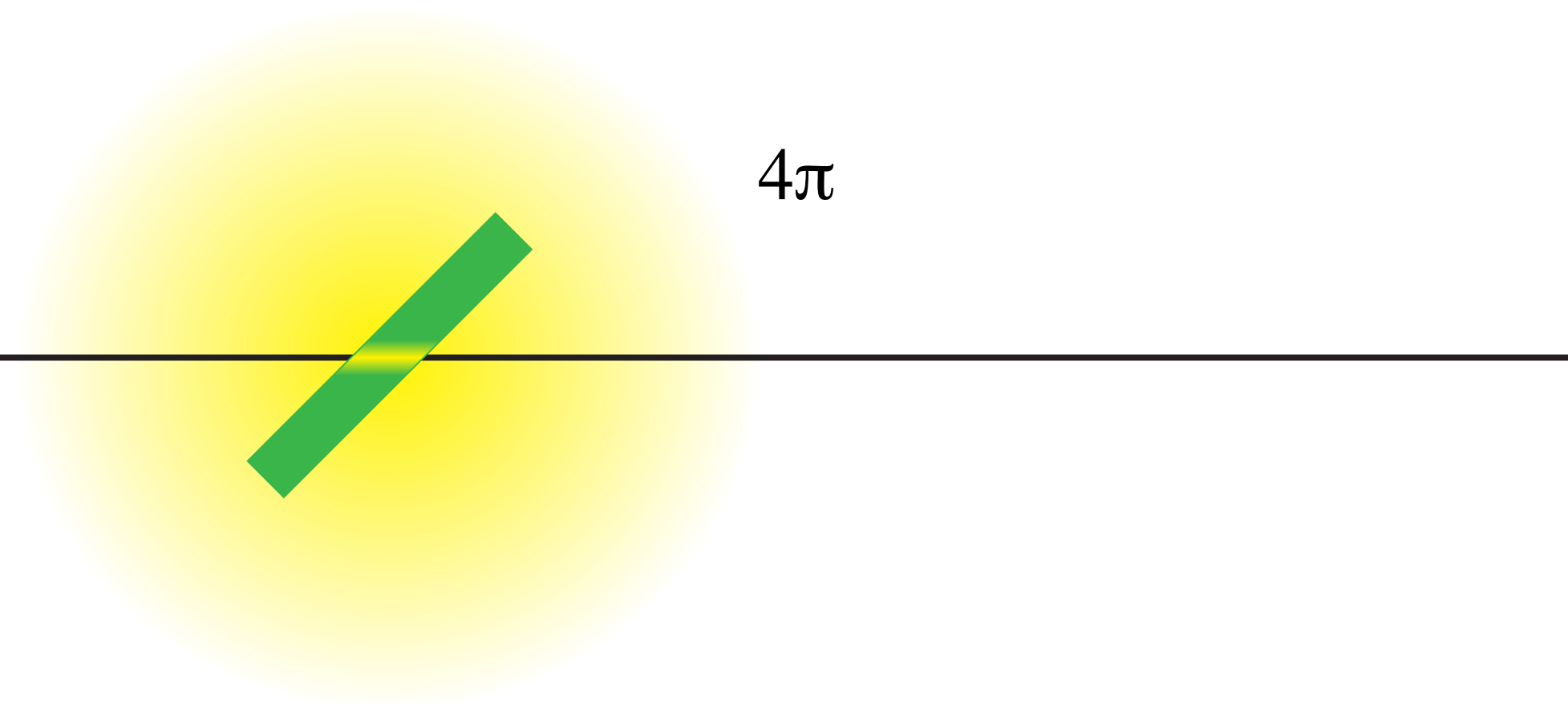


# 2-Dimensional Profile Monitors

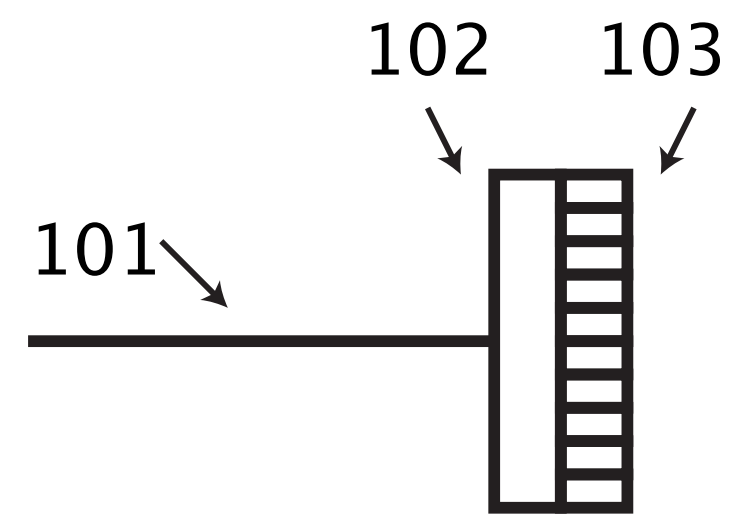
> Optical transition radiation (OTR)



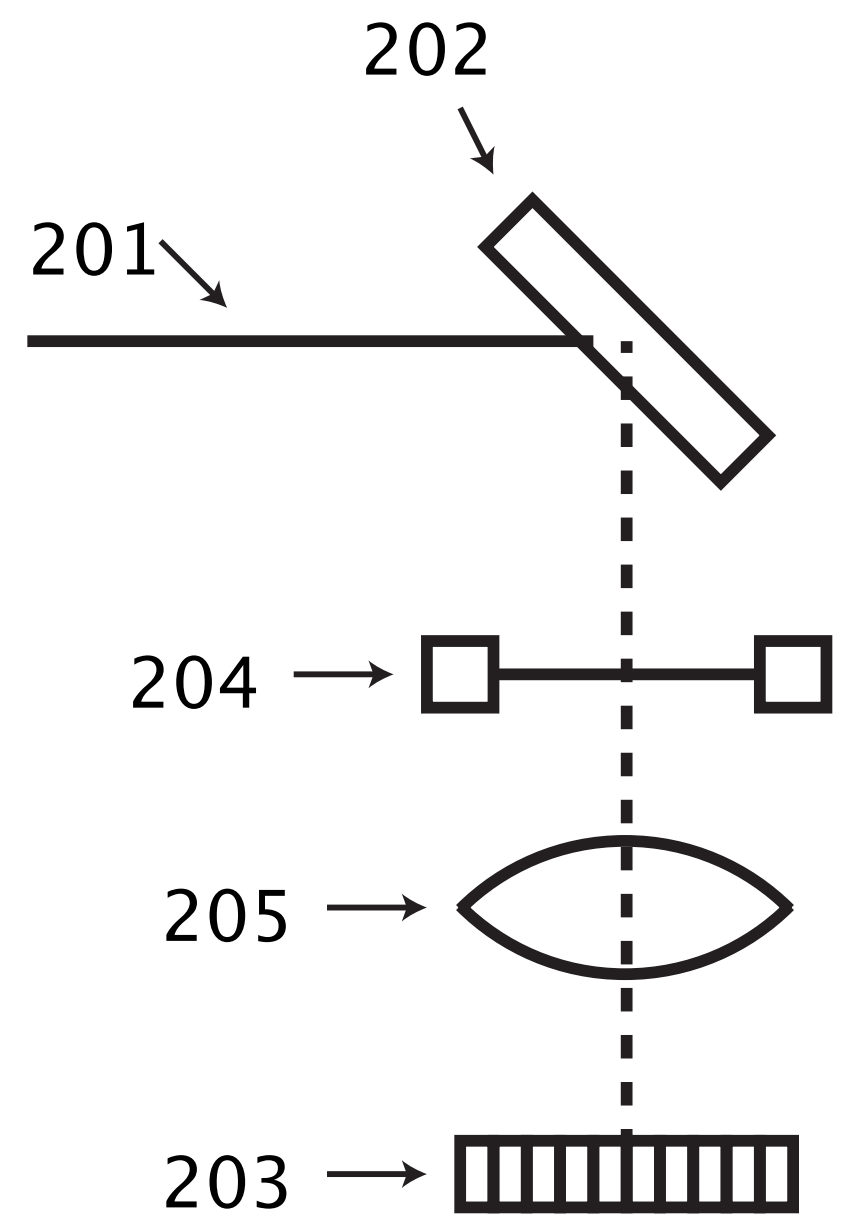
> Scintillation



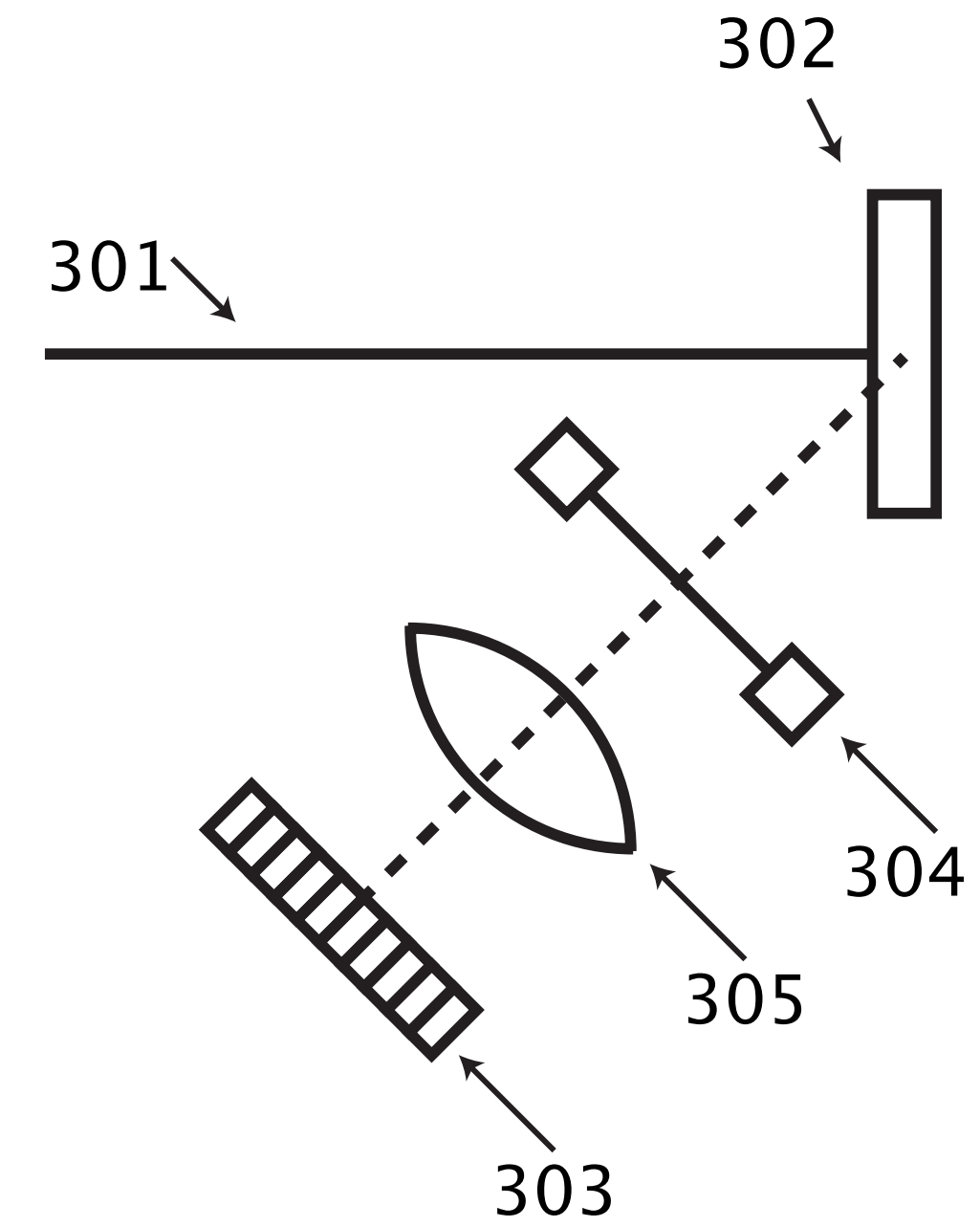
# Imaging Scintillators



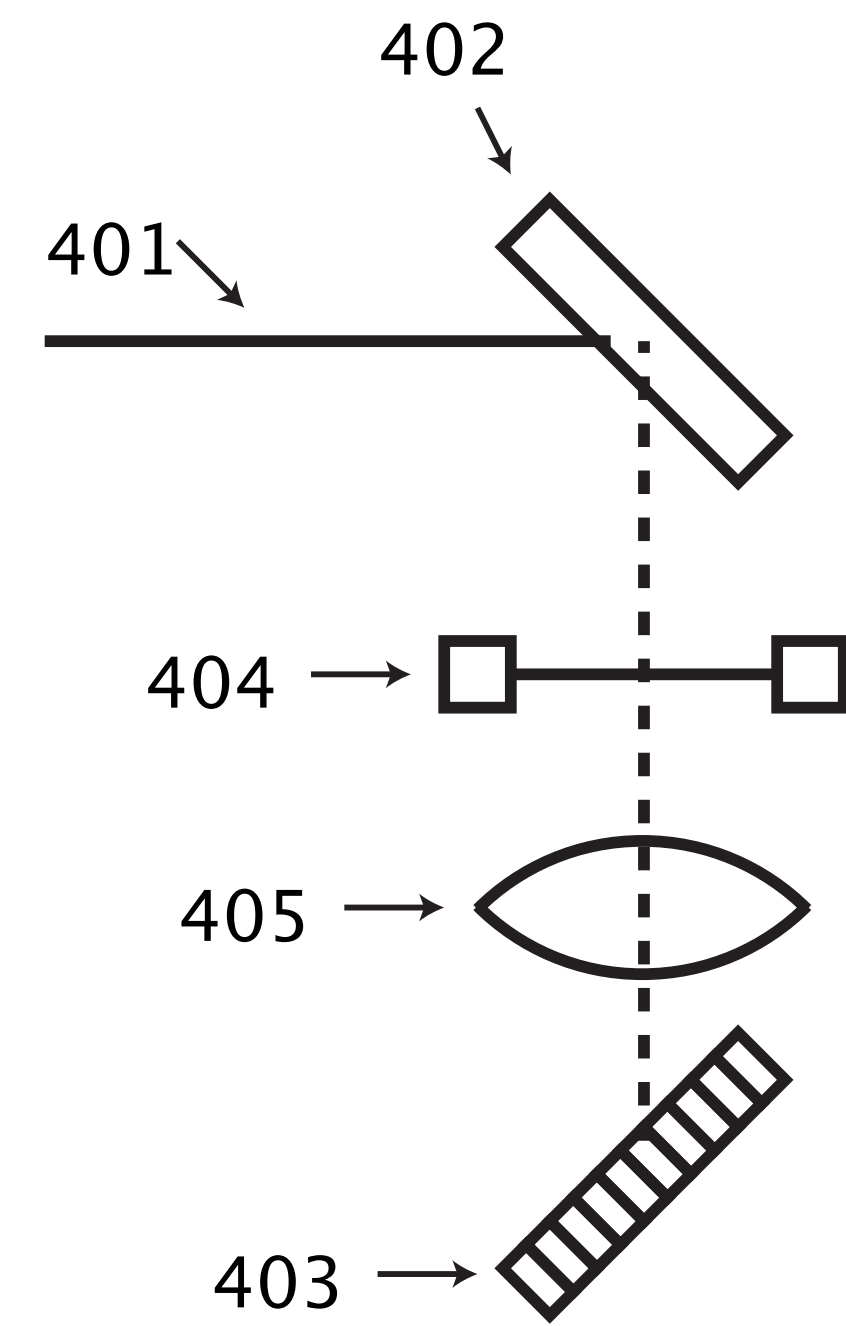
a)



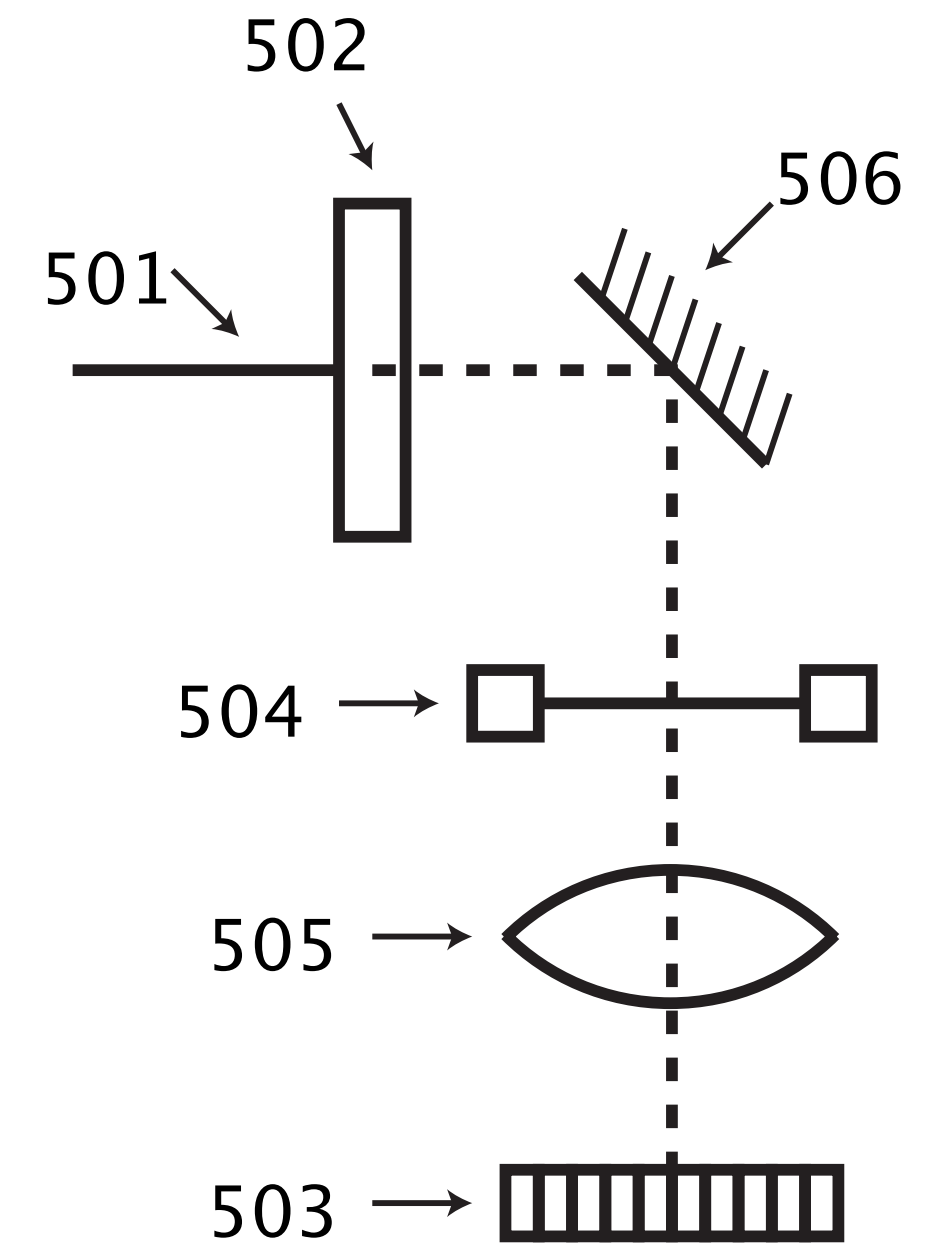
b)



c)

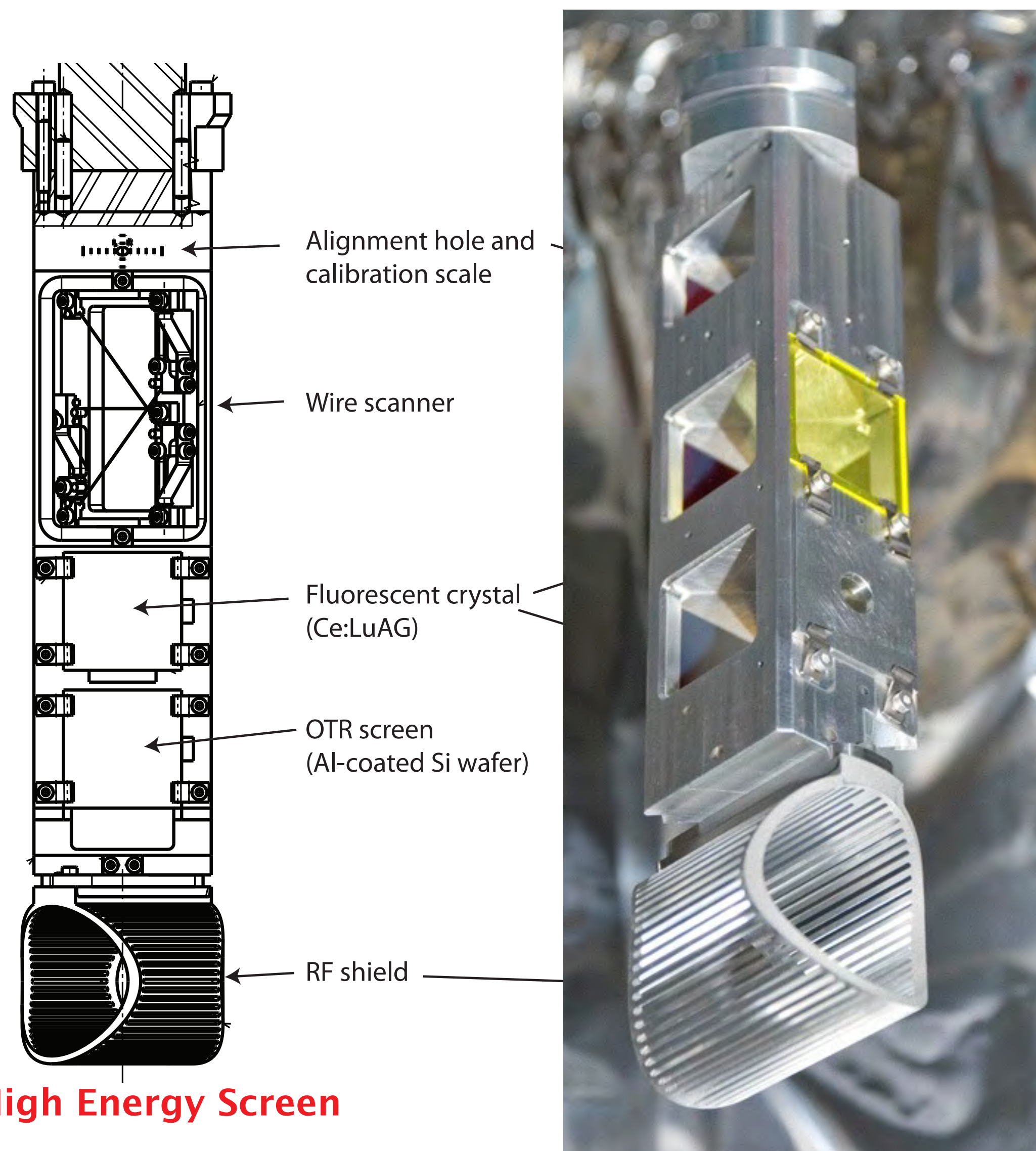


d)



e)

# Electron Beam Profile Monitors for the SwissFEL Injector Test Facility



## Installed scintillators

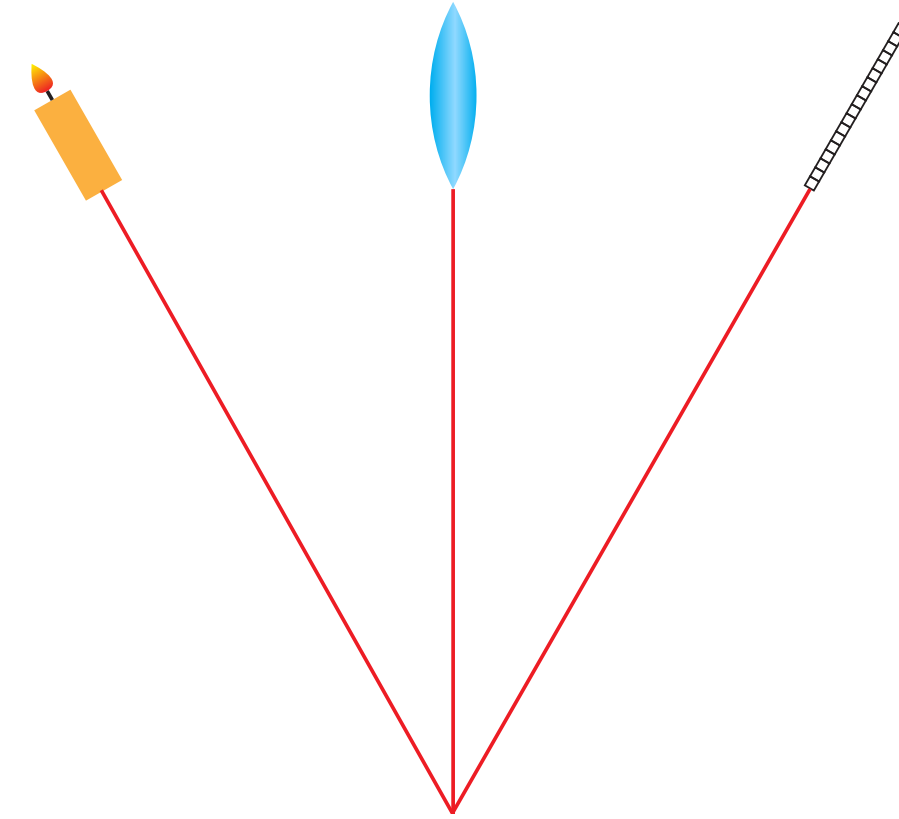
- Ce:YAG
  - 5  $\mu\text{m}$
  - 20  $\mu\text{m}$
  - 200  $\mu\text{m}$
- Ce:LuAG
  - 200  $\mu\text{m}$

# Design Considerations

## > Scheimpflug imaging principle — Theodor Scheimpflug (1865—1911)



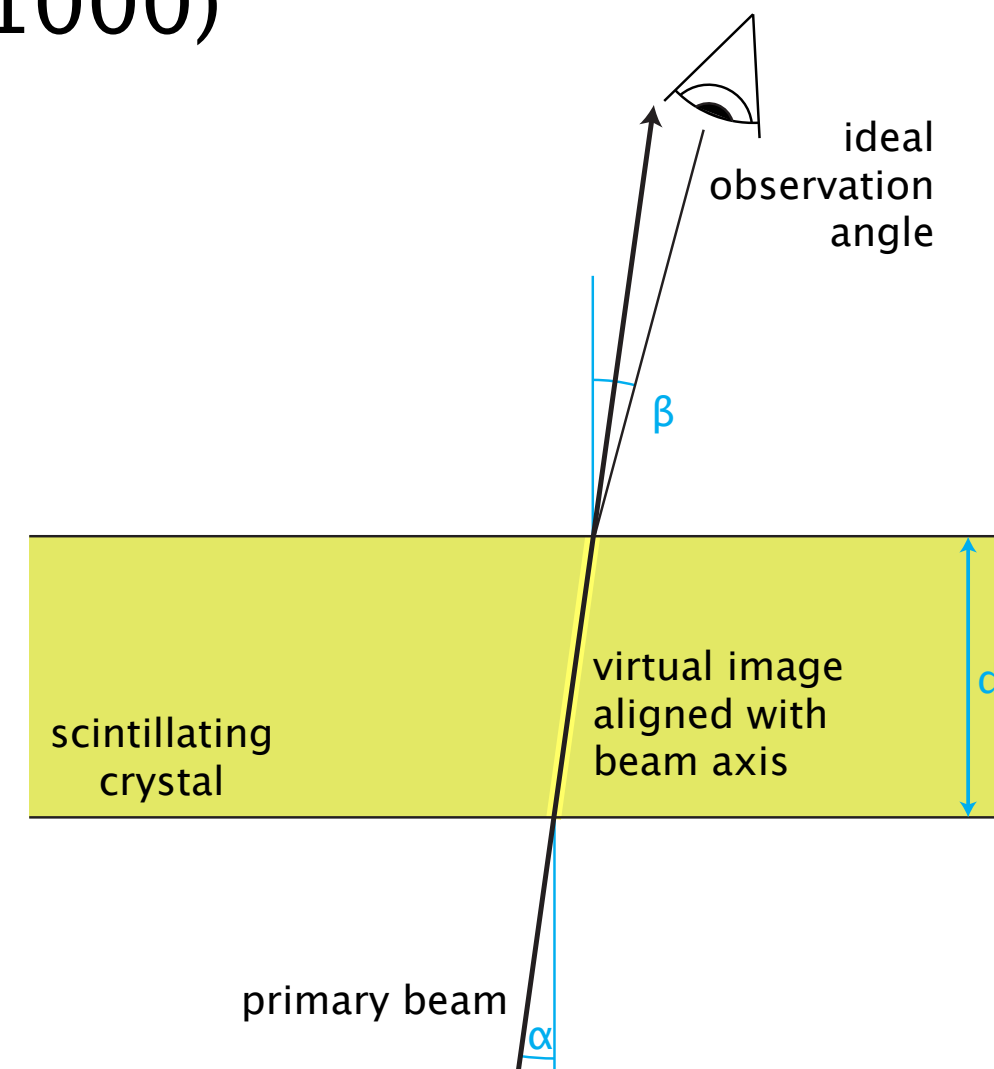
Fig. 1. Theodor Scheimpflug, May 1, 1888, in Pola, when he became a petty officer.



Observation of the Scheimpflug imaging principle allows to image the entire screen without depth-of-field issues.

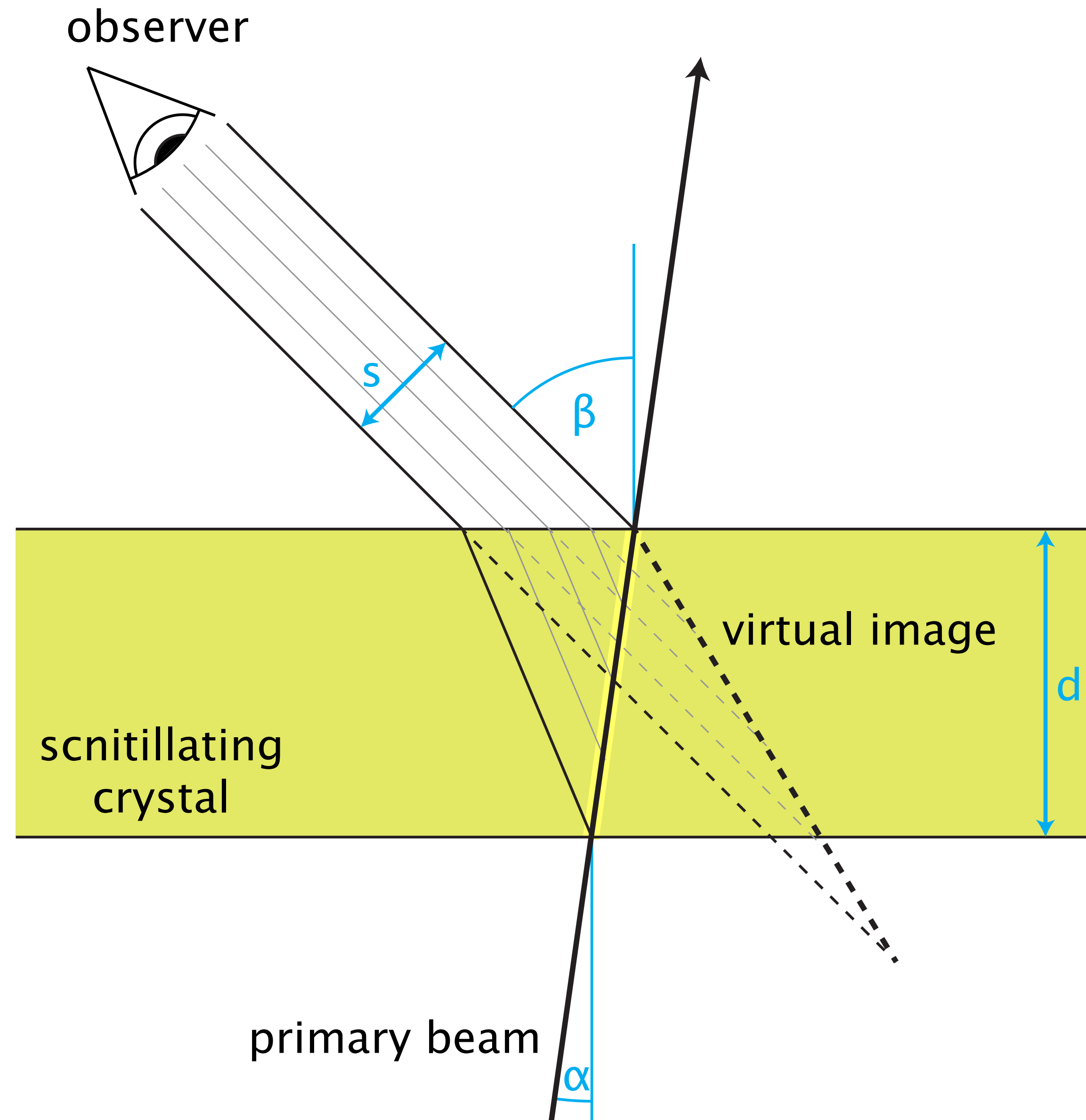
To avoid astigmatism, the lens is not tilted, but the detector is tilted. For a 1:1 imaging, we tilt the CMOS sensor by  $15^\circ$ .

## > Snell's law of refraction — Willebrord Snellius (1580—1626) Abu Sad al-Ala ibn Sahl (940—1000)

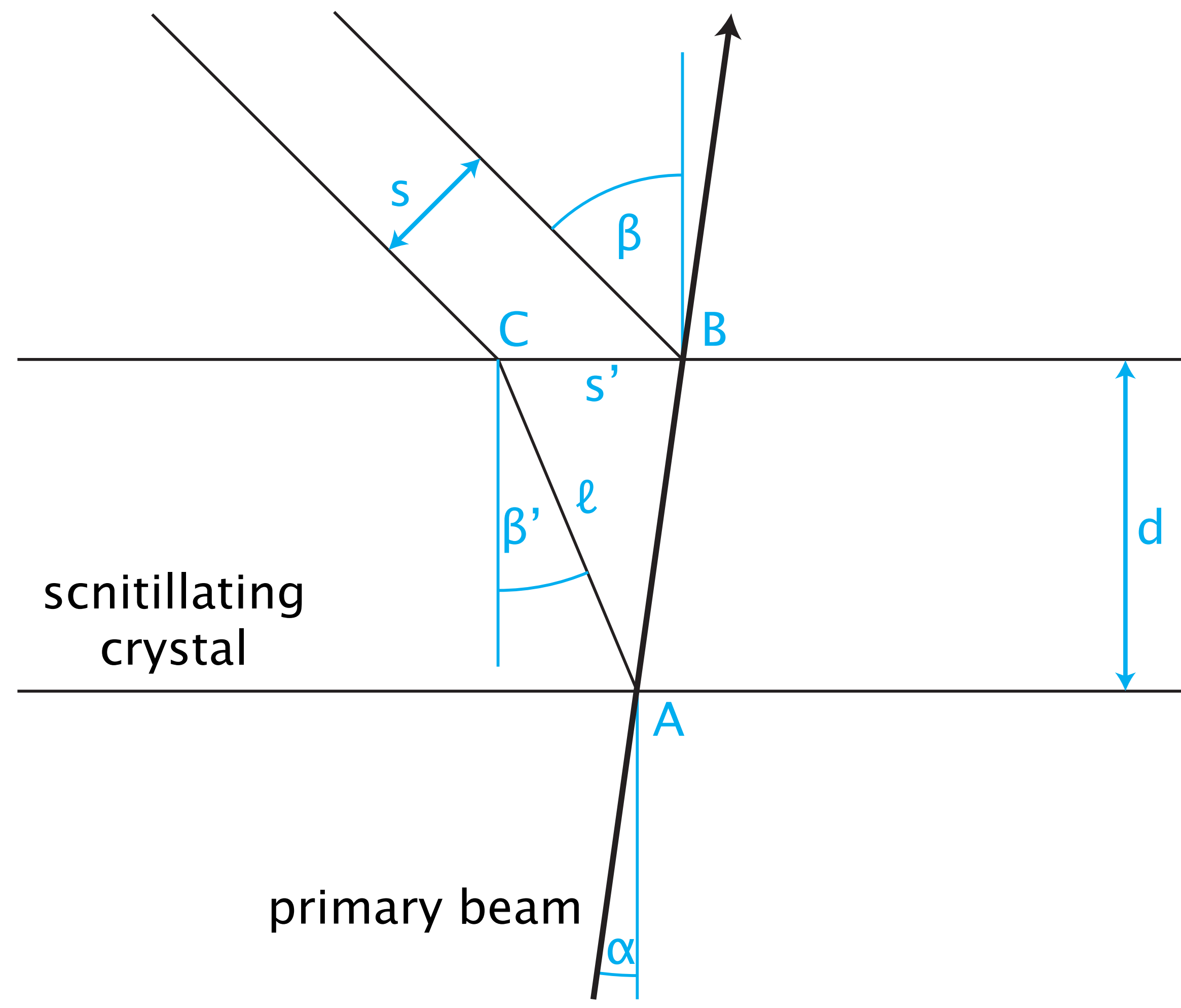


The YAG scintillator is observed at such an angle that Snell's law of refraction is observed. As a consequence, we can image beams that are smaller than the thickness of the scintillator.

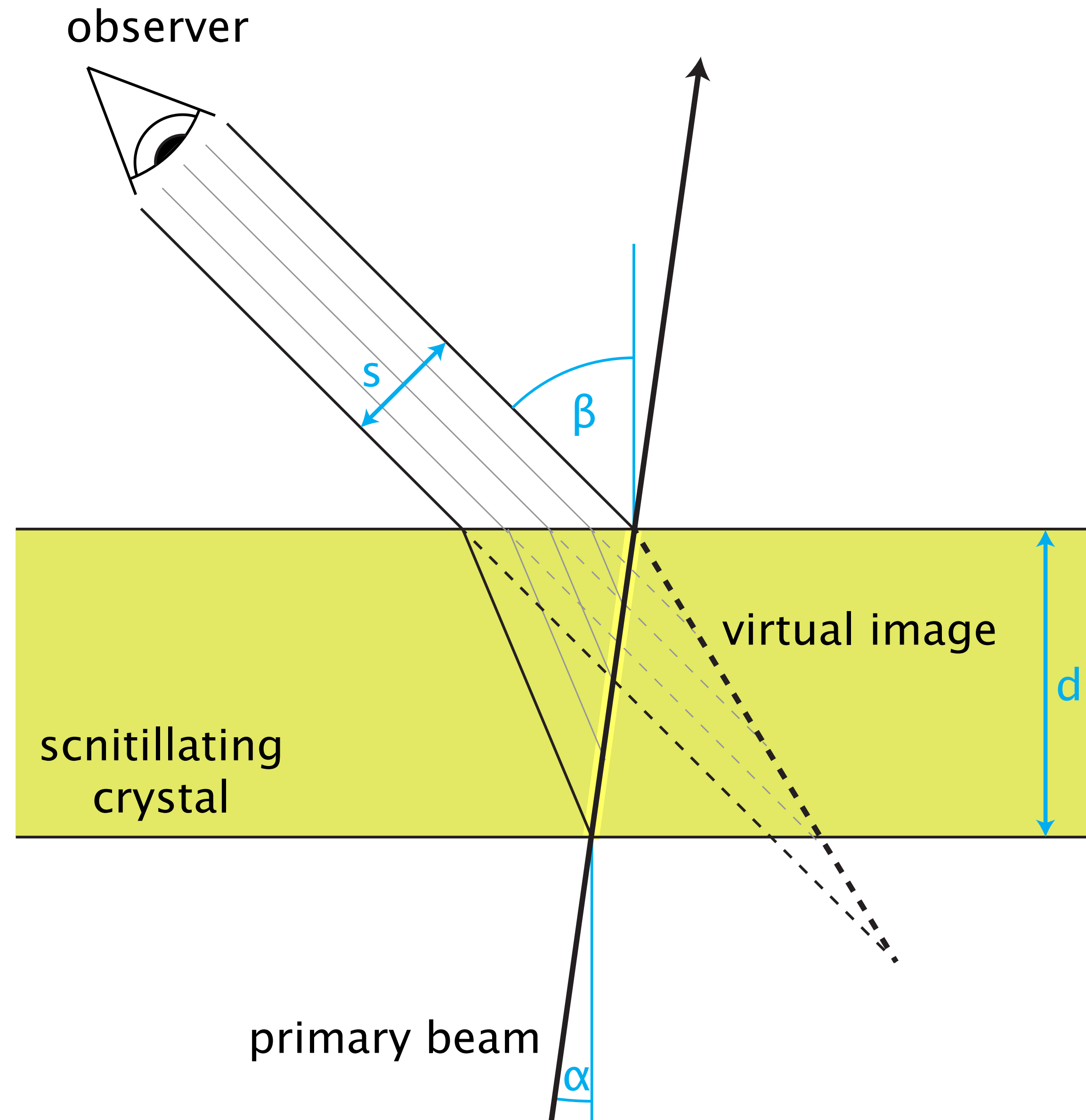
# Imaging Scintillating Crystals



# Imaging Scintillating Crystals

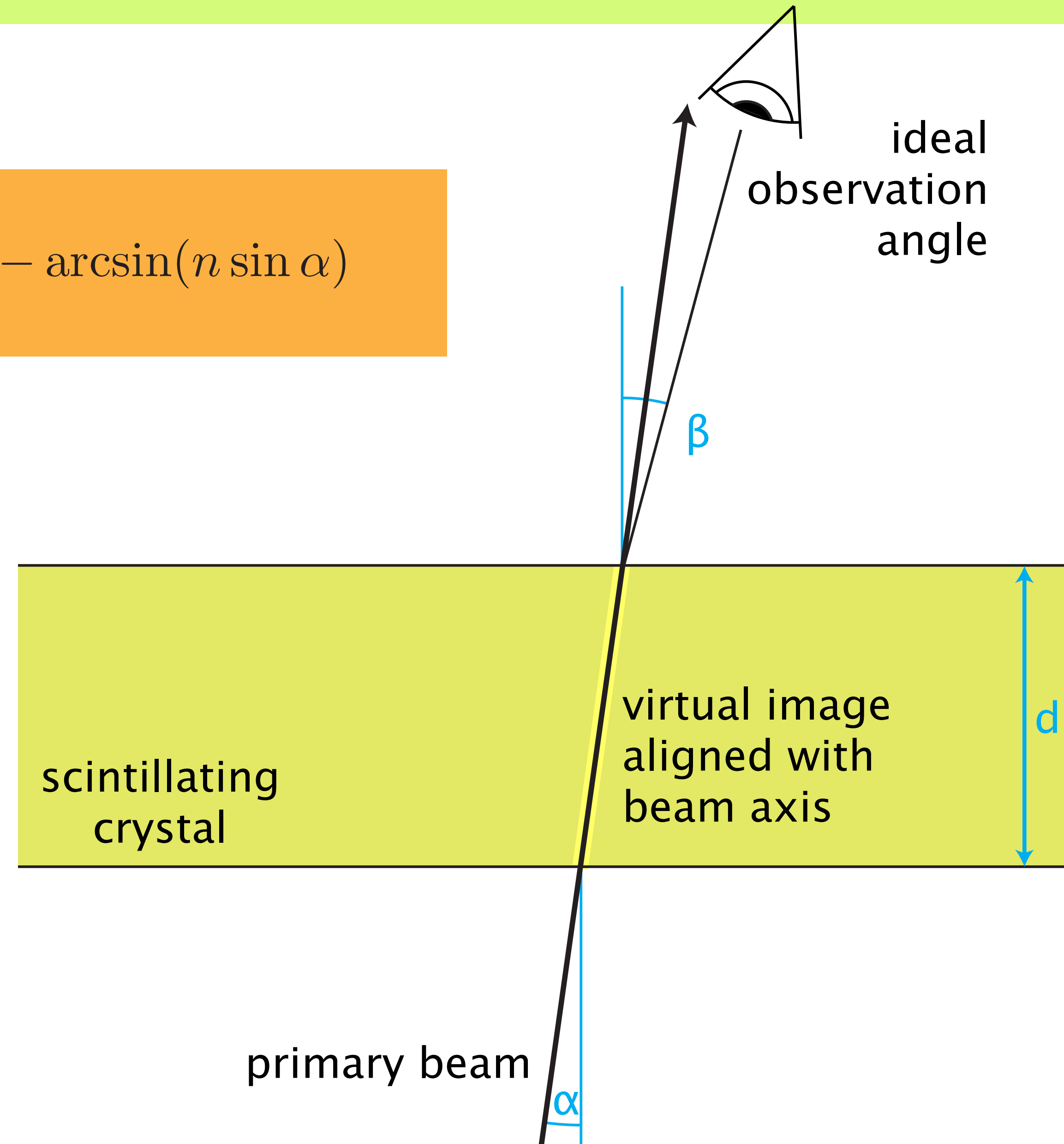


# Imaging Scintillating Crystals



# Imaging Scintillating Crystals

$$\beta_{\text{ideal}} = -\arcsin(n \sin \alpha)$$



# Trigonometry...

$$\frac{\sin \beta}{n} = \sin \beta'$$

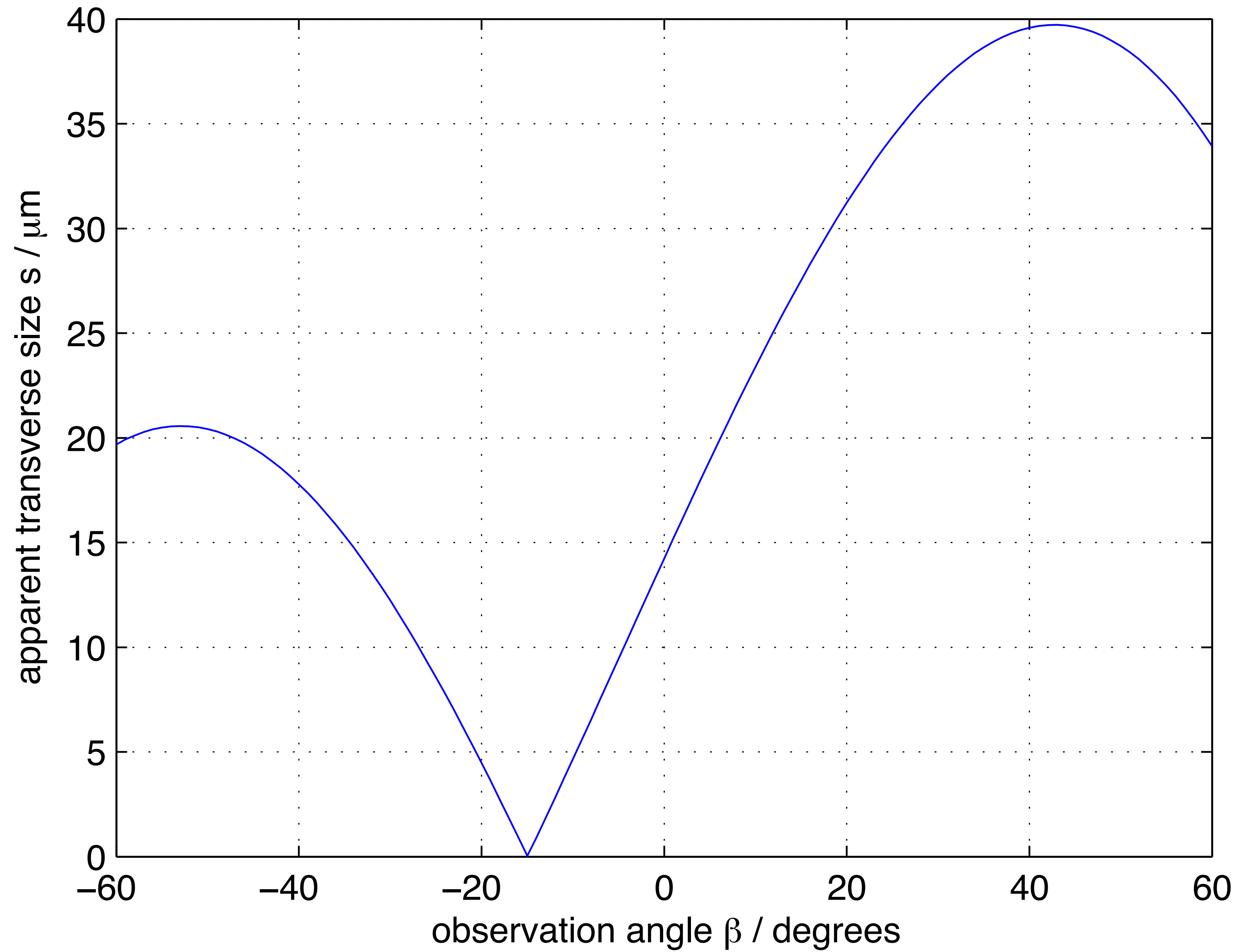
$$\ell := \overline{AB} = \frac{d}{\cos \beta'}$$

$$s' := \overline{BC} = \frac{s}{\cos \beta}$$

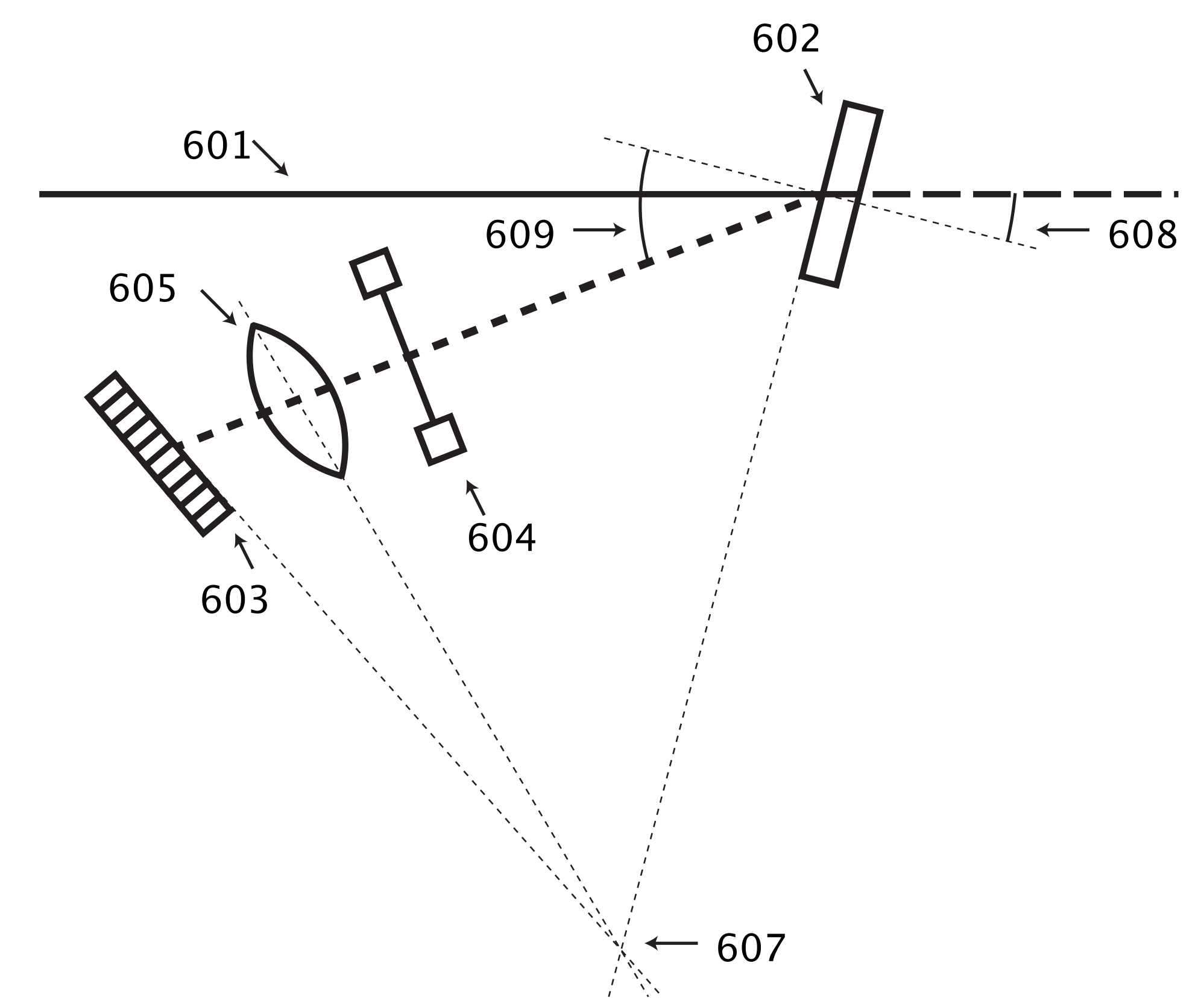
$$s'^2 = \ell^2 + \left(\frac{d}{\cos \alpha}\right)^2 - 2\ell \frac{d}{\cos \alpha} \cos(\alpha + \beta')$$

$$s = d \cos \beta \cdot \sqrt{\frac{1}{1 - \frac{\sin^2 \beta}{n^2}} + \frac{1}{\cos^2 \alpha} - 2 \frac{\cos \left( \arcsin \left( \frac{\sin \beta}{n} \right) + \alpha \right)}{\sqrt{1 - \frac{\sin^2 \beta}{n^2}} \cos \alpha}}$$

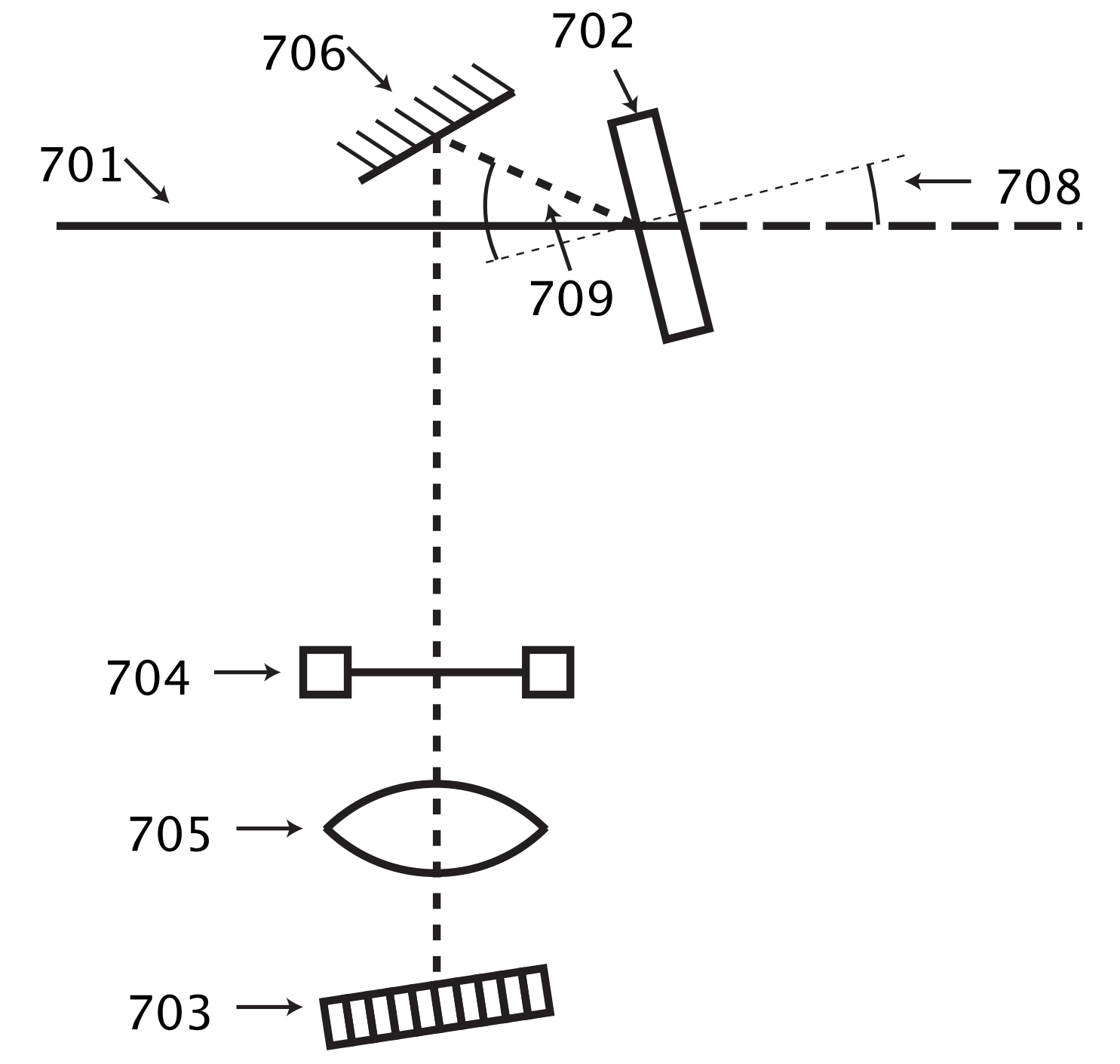
# Observed Beam Size



# Ideal Observation Angle



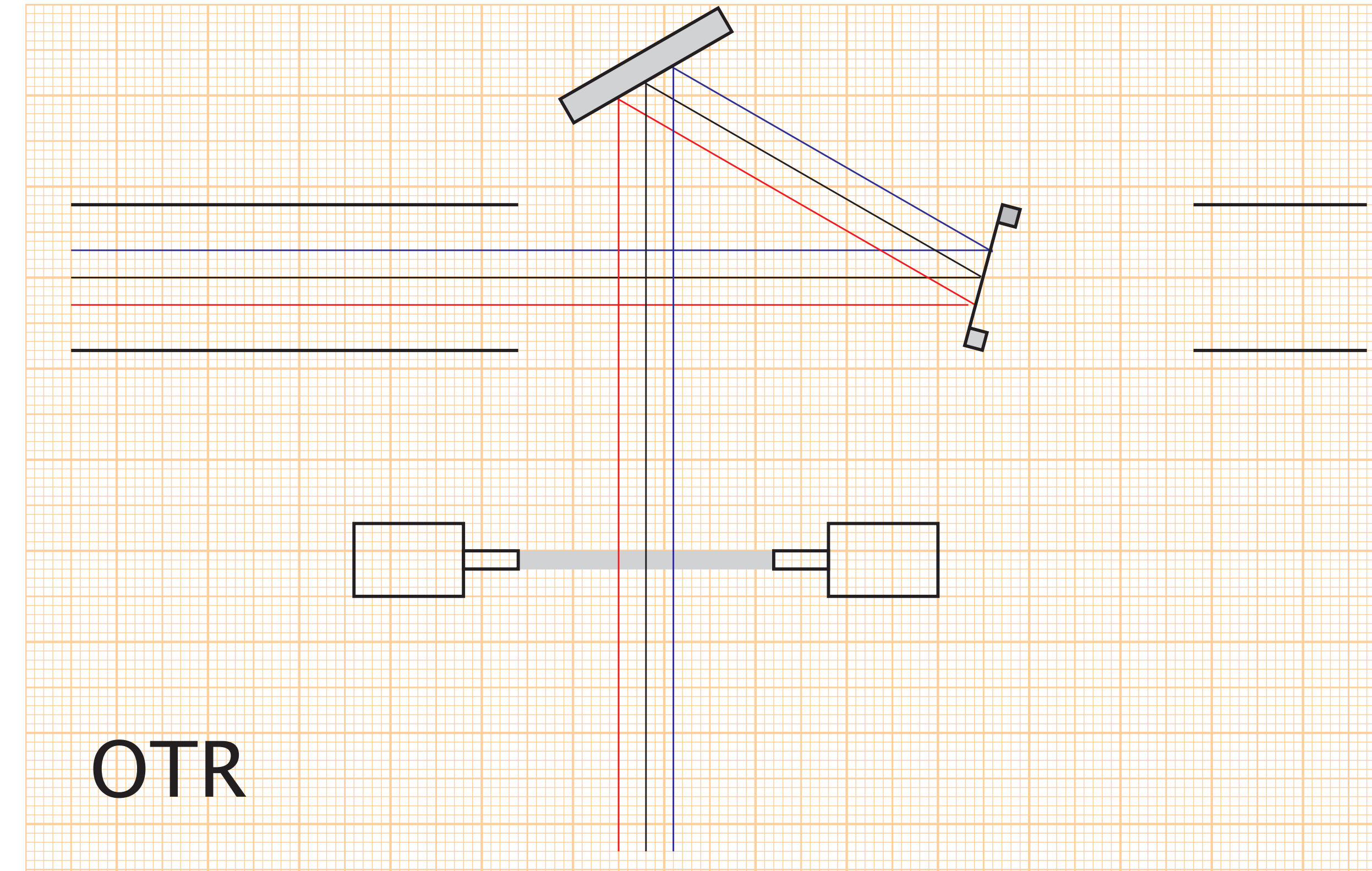
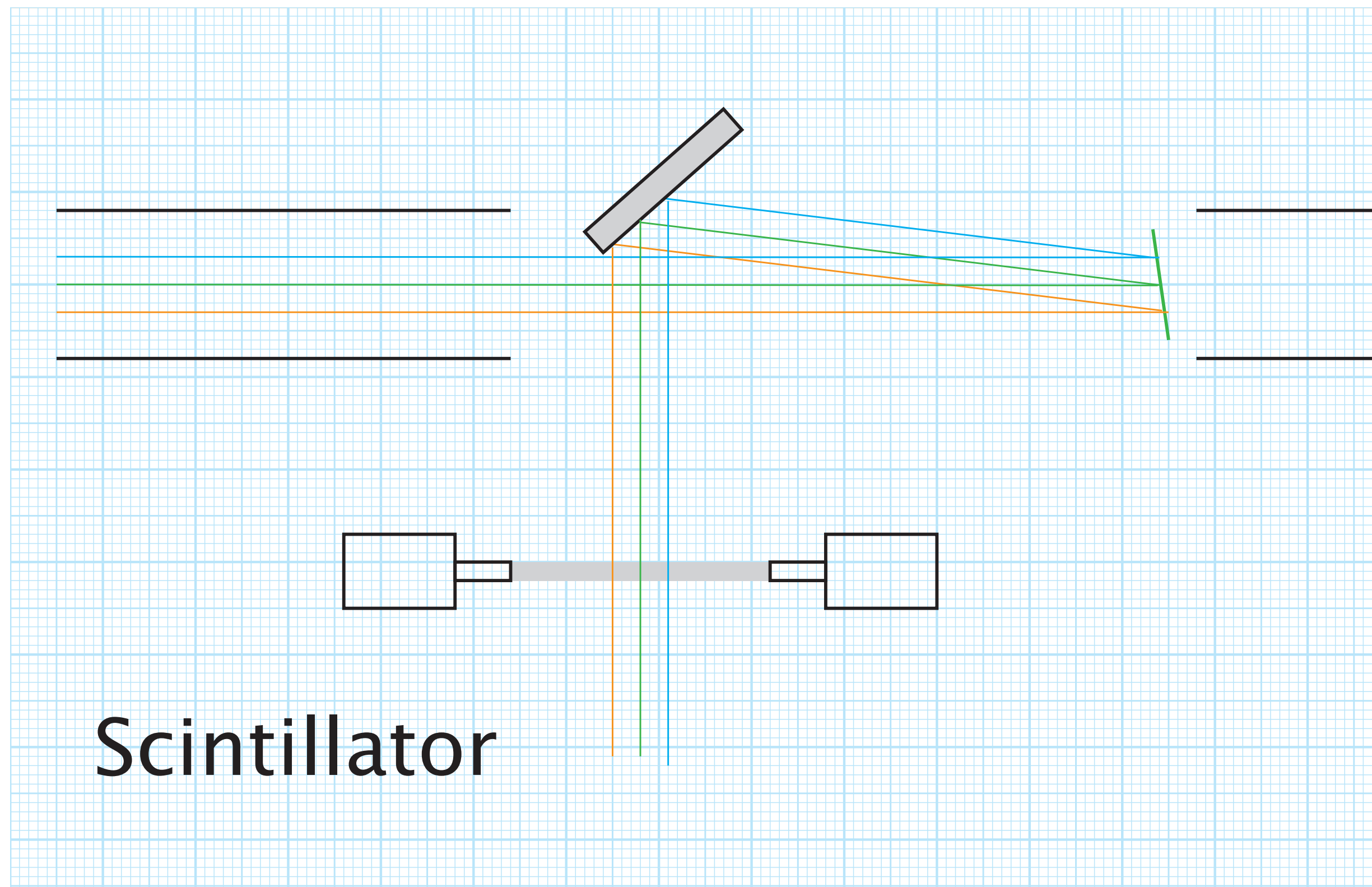
a)



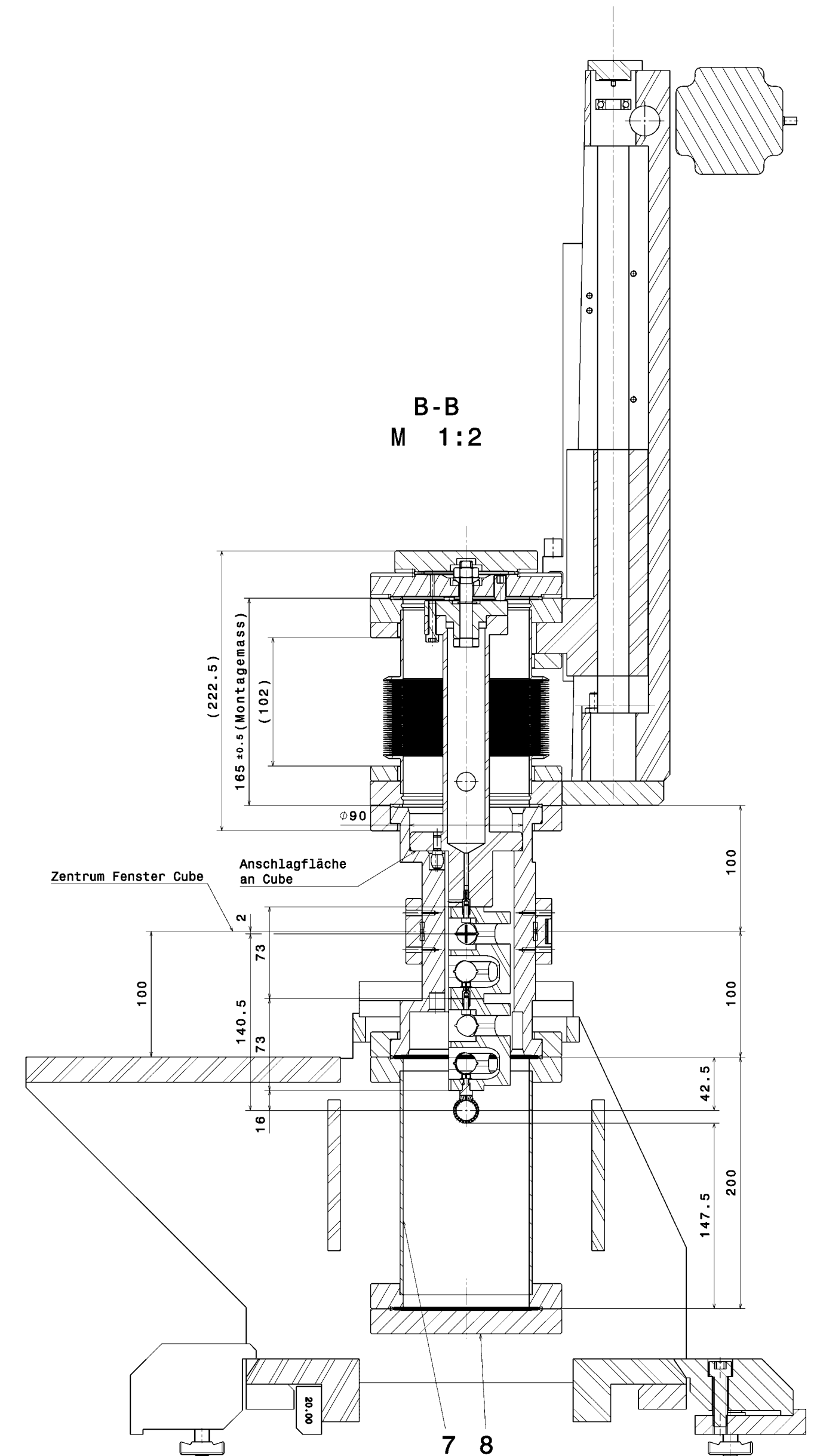
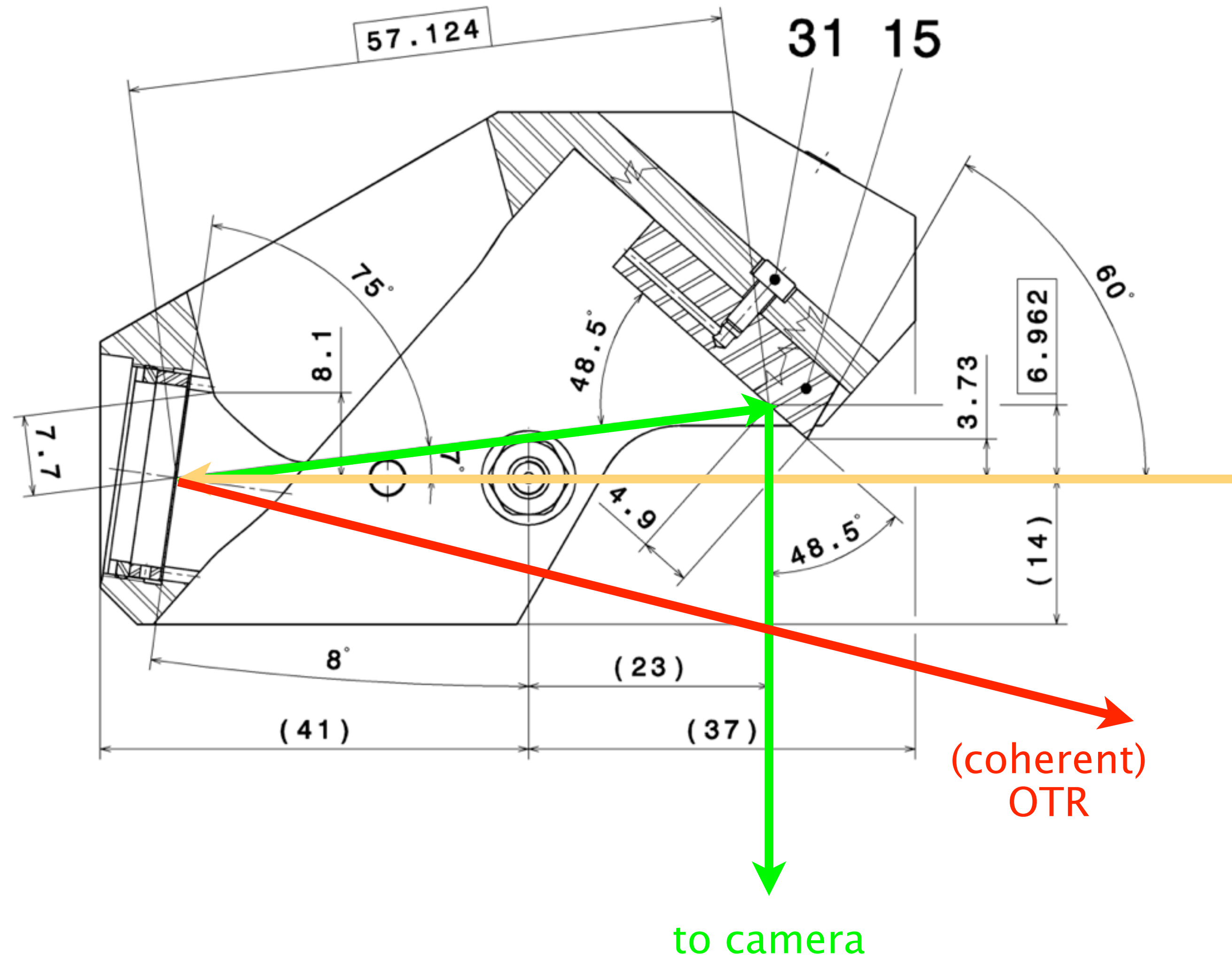
b)

# Measurement Principle

- > Combination of two monitors:
  - > Scintillating crystal
  - > Optical transition radiation



# Implementation



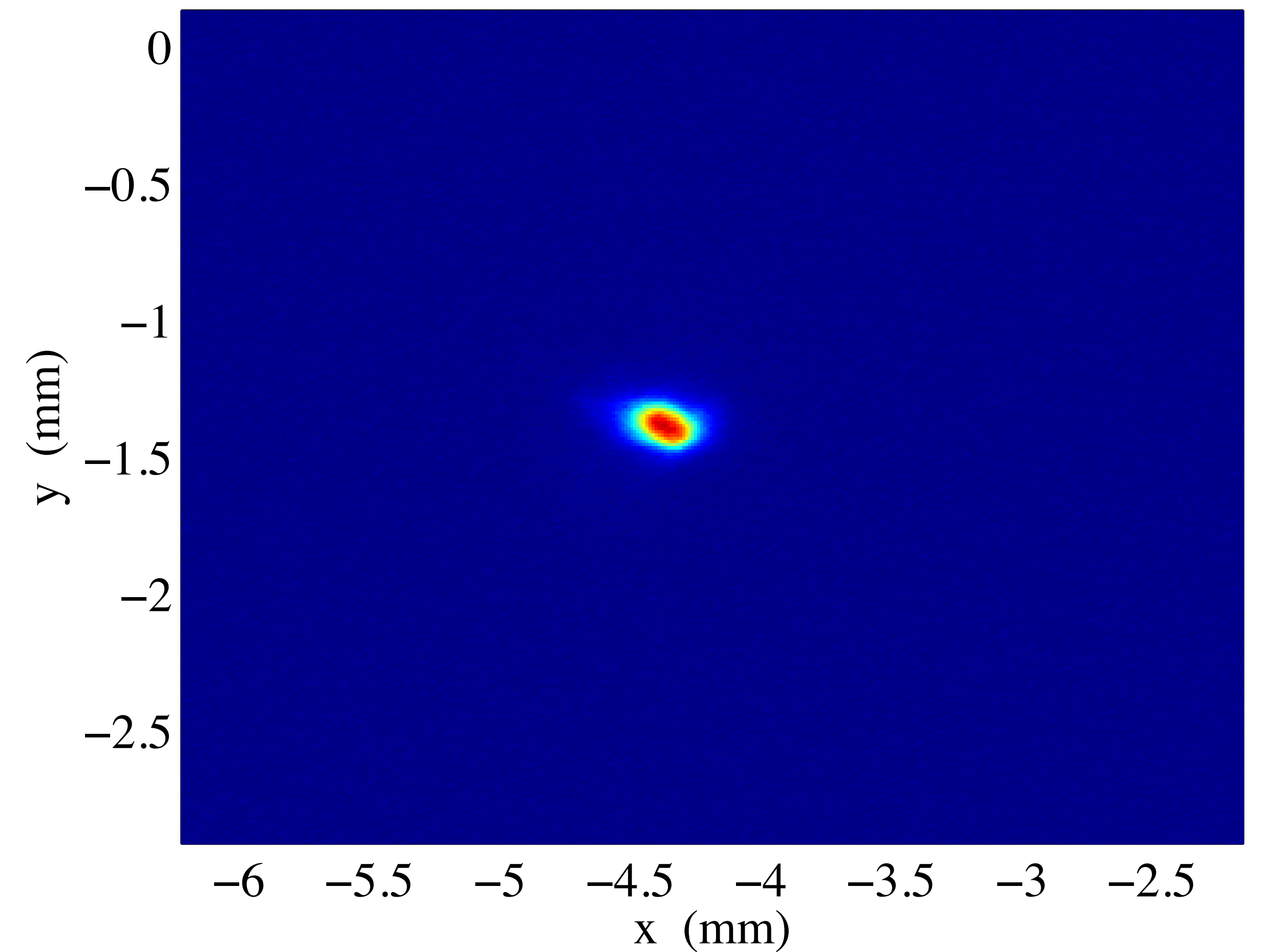
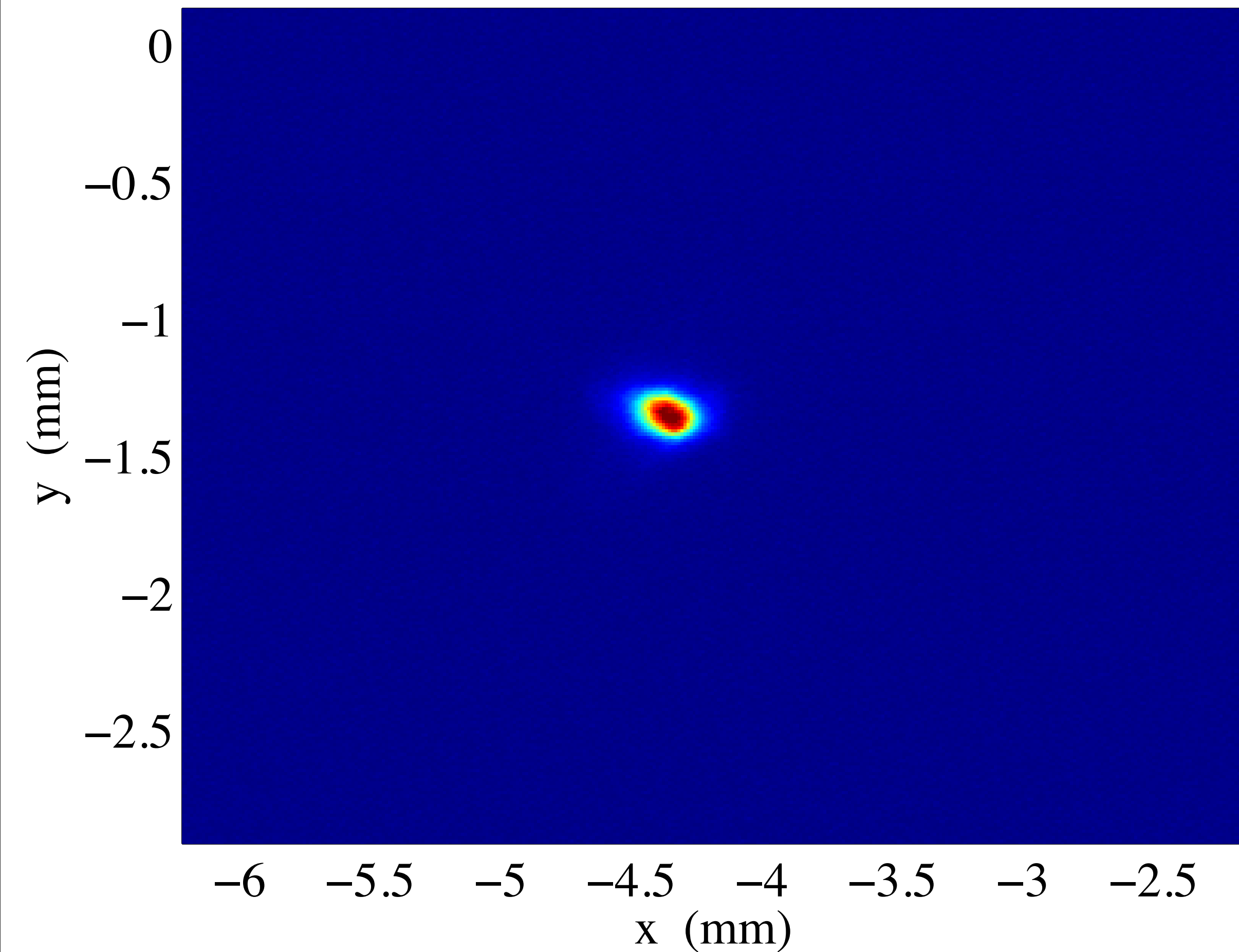
# Suppression of Coherent Optical Transition Radiation

> Laser heater ON

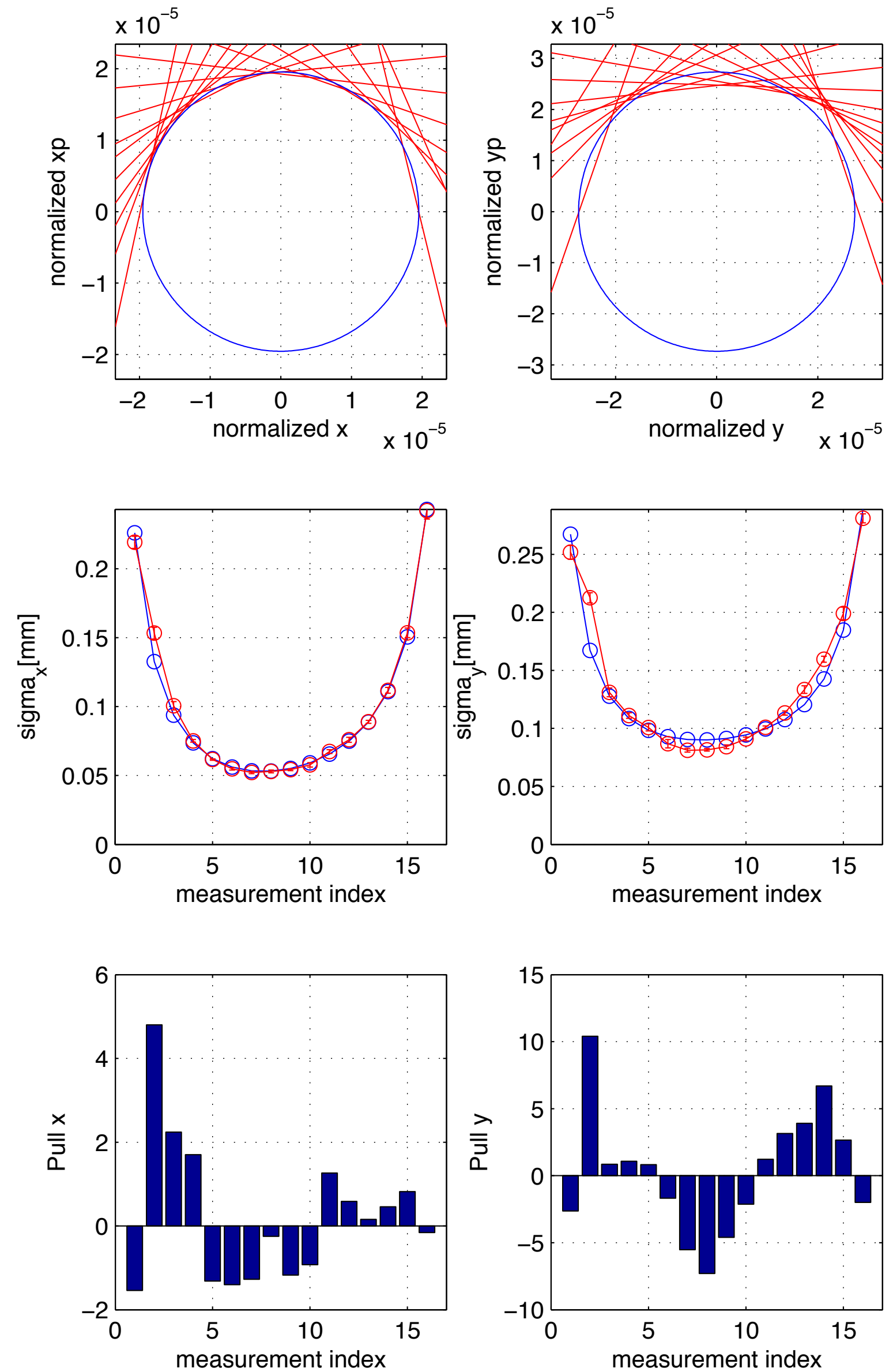
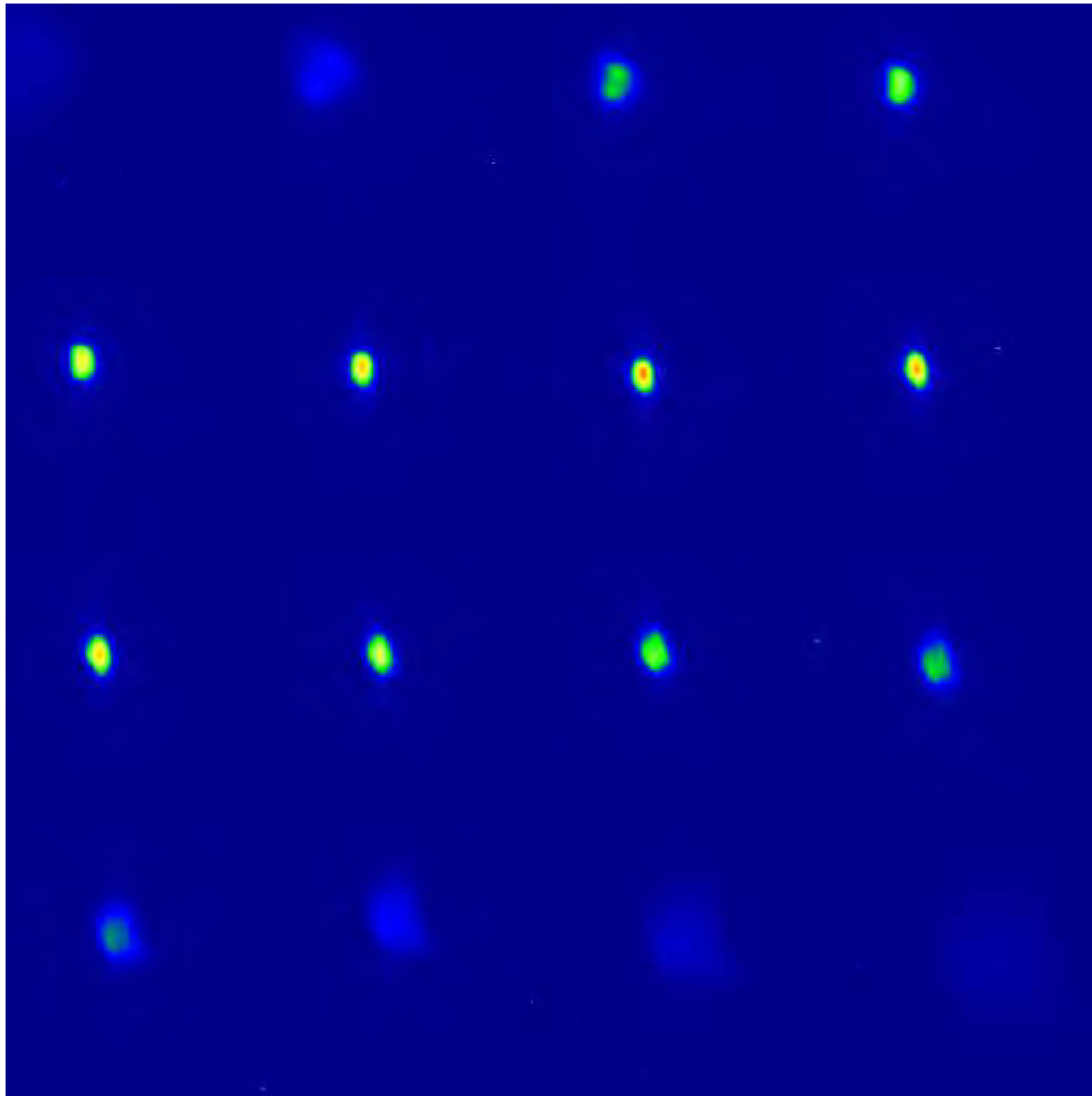
> Laser heater OFF

Profile Monitor YAGS:LTU1:743 04-Dec-2013 18:46:44

Profile Monitor YAGS:LTU1:743 04-Dec-2013 18:47:36



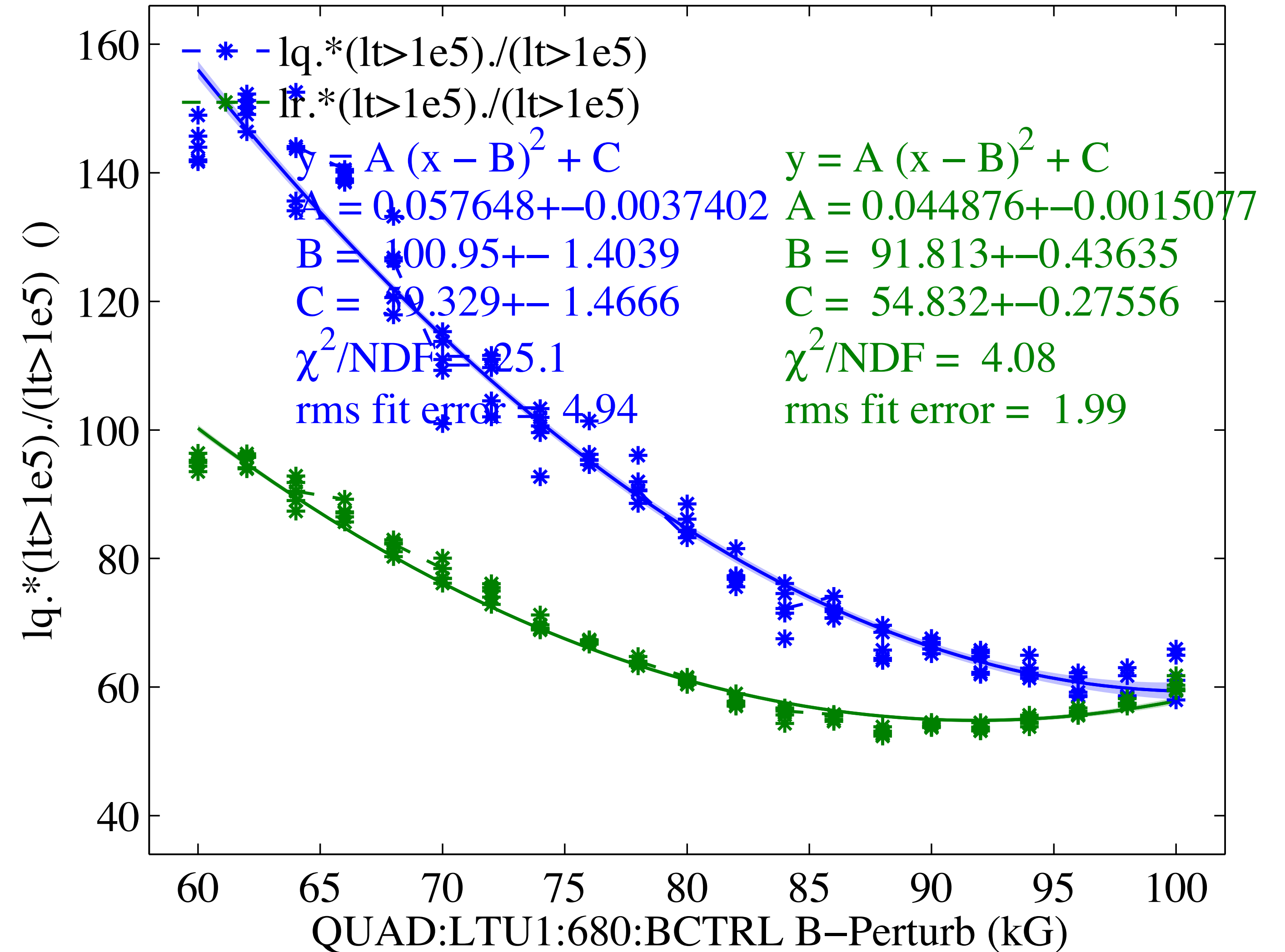
# Transverse Profiles: Quadrupole Scan



# Quadrupole Scan

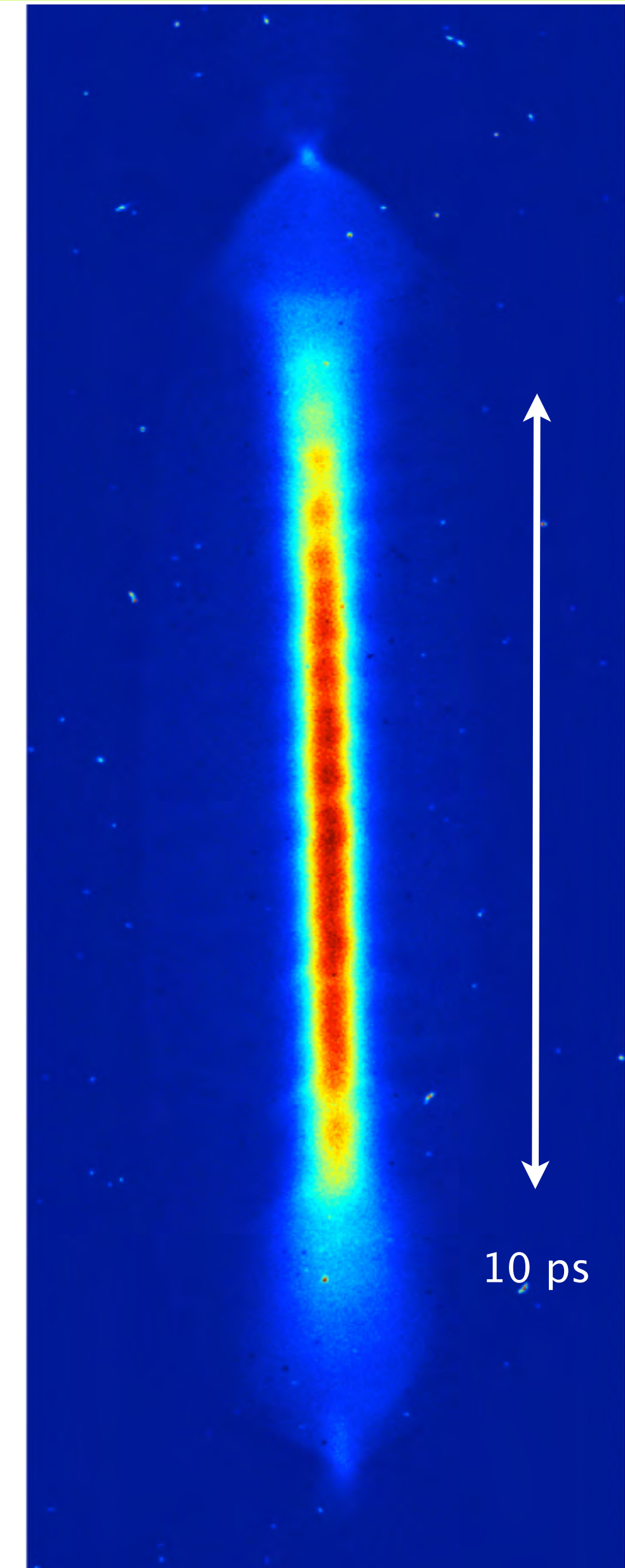
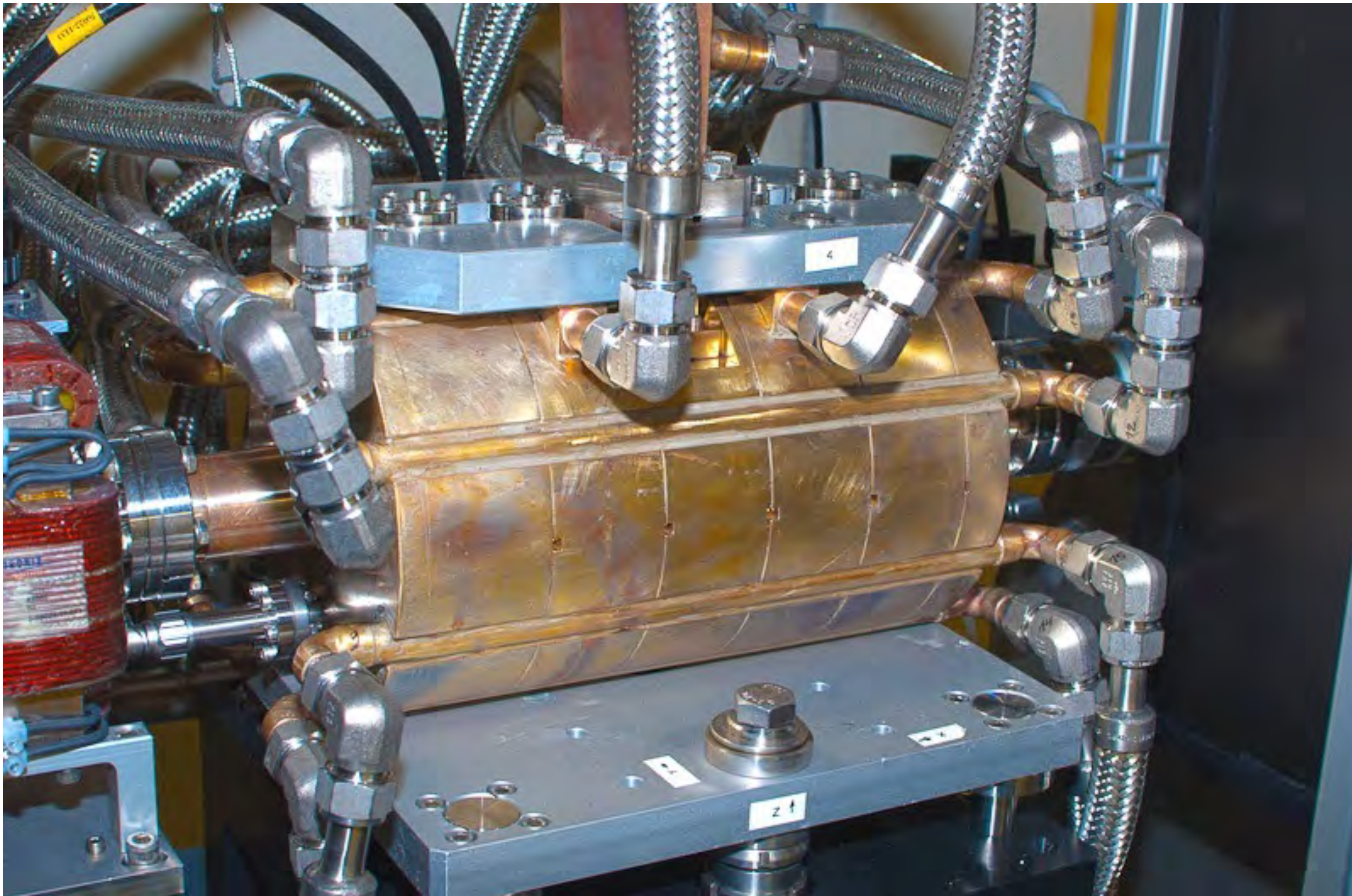
- > Scan single quadrupole
- > Beam size (horizontal and vertical) as a function of quadrupole field gradient

OPAL and All 04-Dec-2013 18:35:10



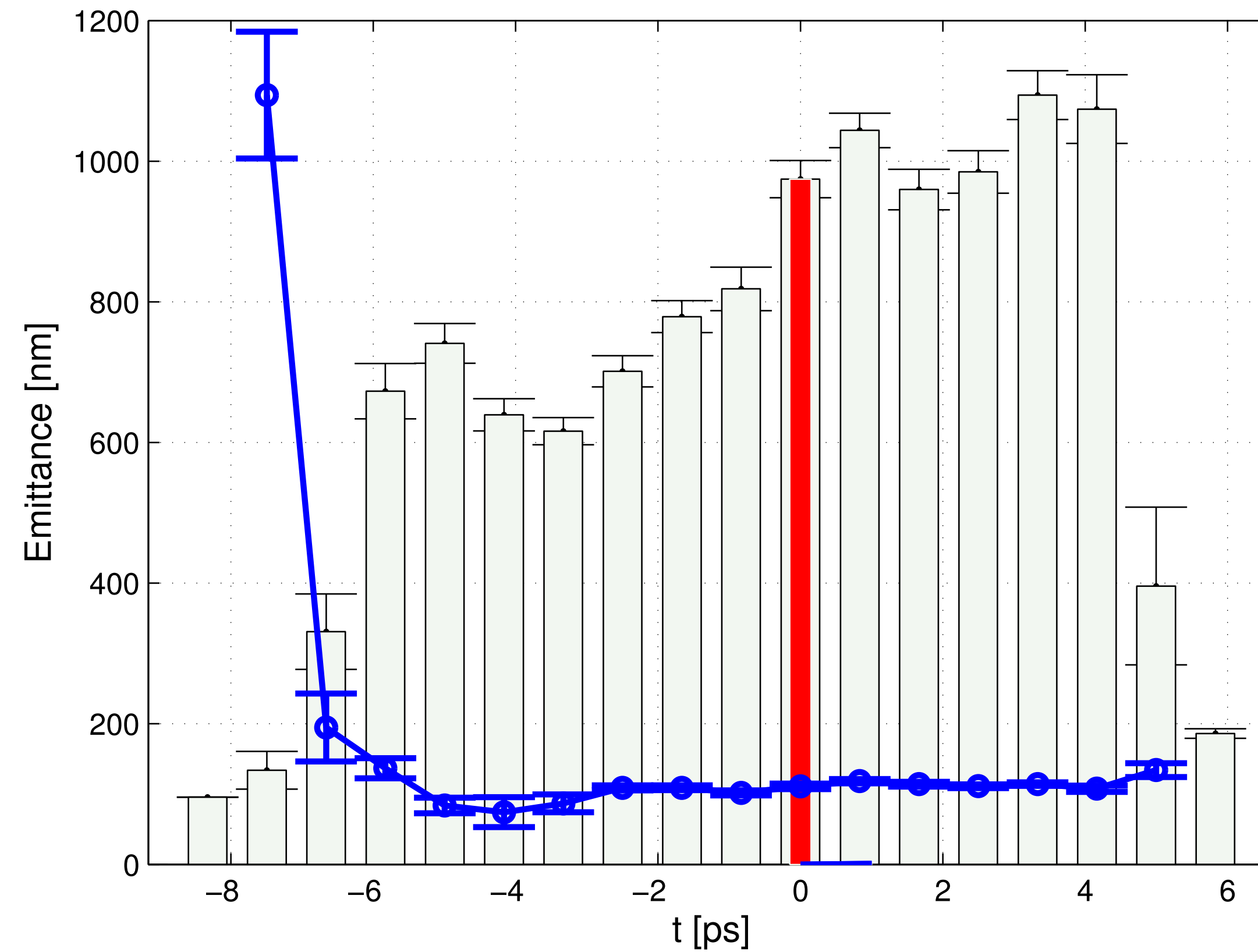
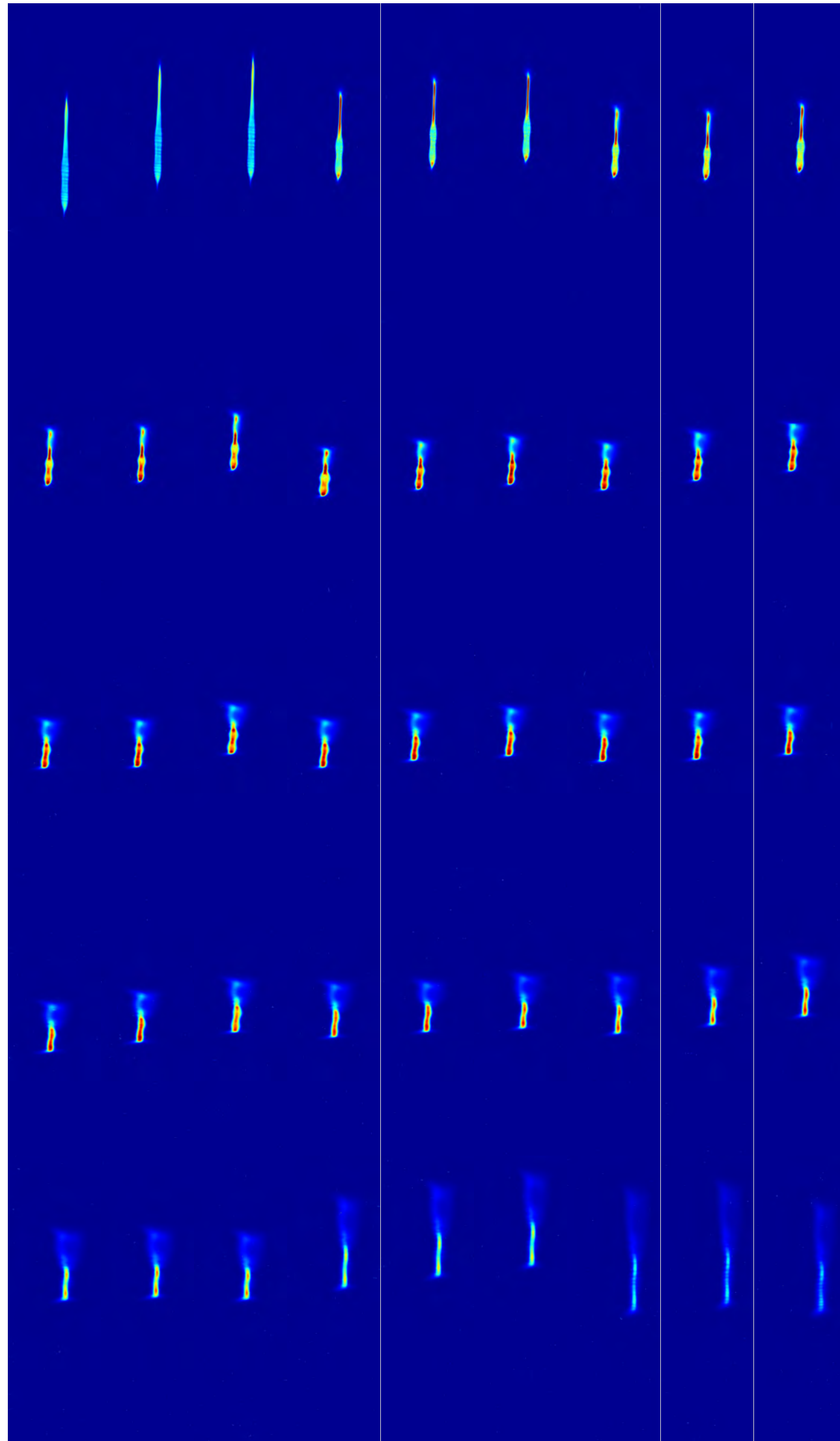
# Direct Streaking of the Electron Beam

- > Requires integrated transverse field of several MV
- > Use transverse deflecting RF structure, powered by klystron
- > Two-dimensional measurements possible



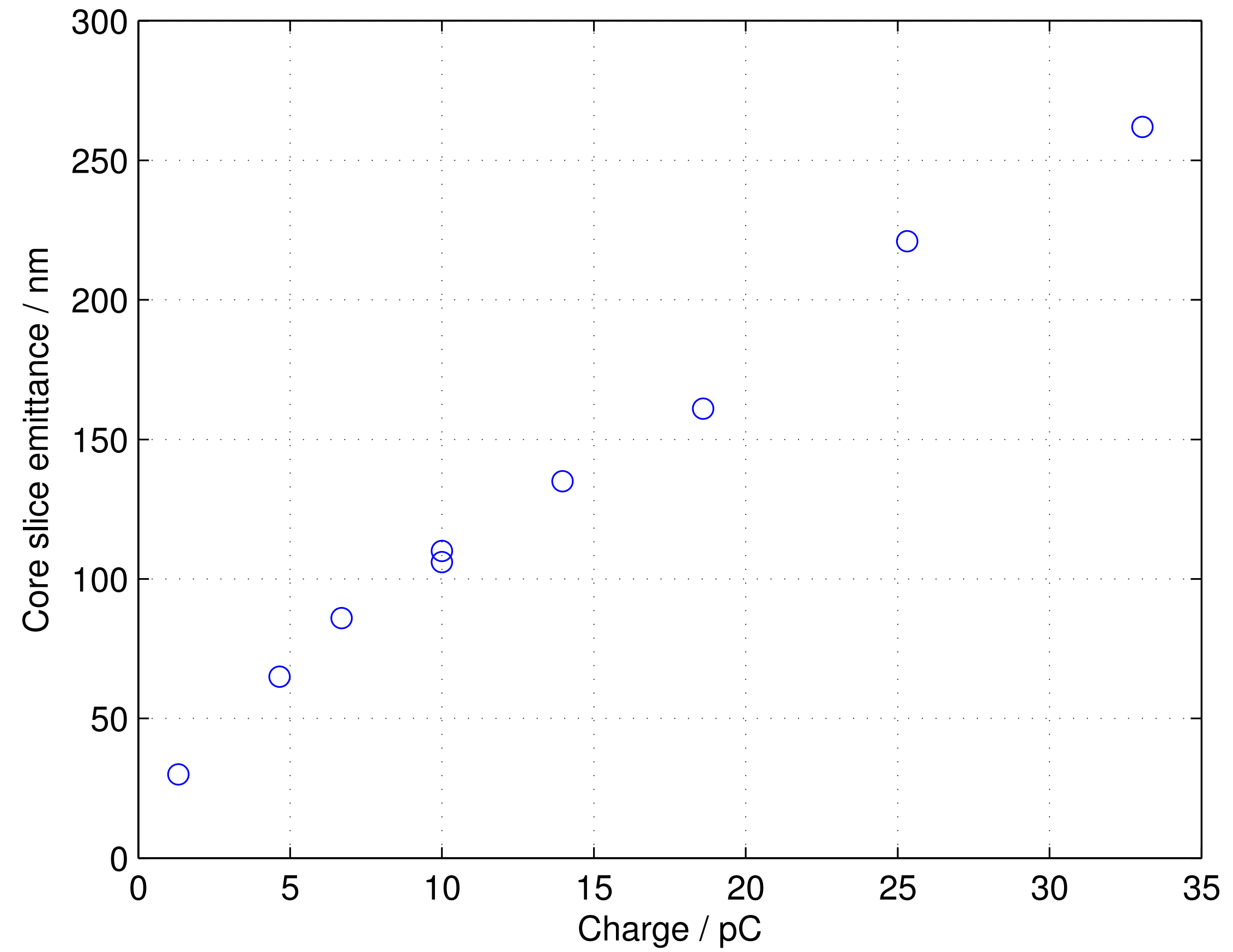
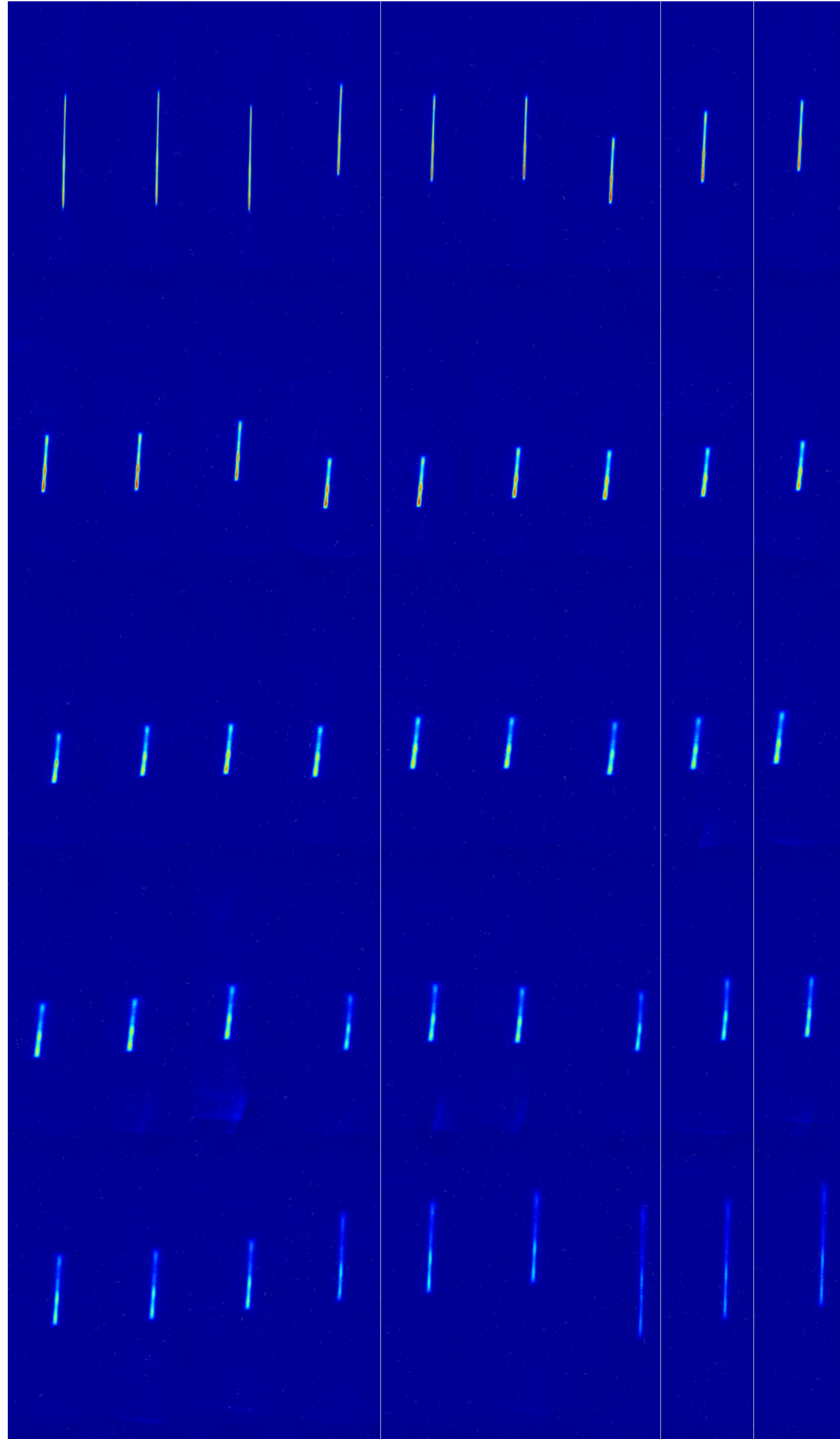
# 3-Dimensional Measurements

> Reconstruction from a series of 2-d measurements: Slice emittance



# 3-Dimensional Measurements

> Slice emittance measurement of a 1.3 pC beam



# Electron Beam Instrumentation for SwissFEL

Rasmus Ischebeck, for the SwissFEL Team

> Thank you for help, slides, graphics, photos and plots provided by:

- > Vladimir Arsov
  - > Franz-Josef Decker
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  - > Paul Emma
  - > Antonio Falone
  - > Franziska Frei
  - > Joe Frisch
  - > Ishkhan Gorgisyan
  - > Yevgeniy Ivanisenko
  - > Boris Keil
  - > Gene Kraft
  - > Patrick Krejcik
  - > Florian Löhl
  - > Gian Luca Orlandi
  - > Marco Pedrozzi
  - > Peter Peier
  - > Eduard Prat
  - > Volker Schlott
  - > Bennie Smit
  - > Howard Smith
  - > Markus Stadler
- ... and all PSI and SLAC operators